

***Short Course On
Phase-Locked Loops and Their Applications
Day 5, AM Lecture***

Advanced PLL Examples (Part I)

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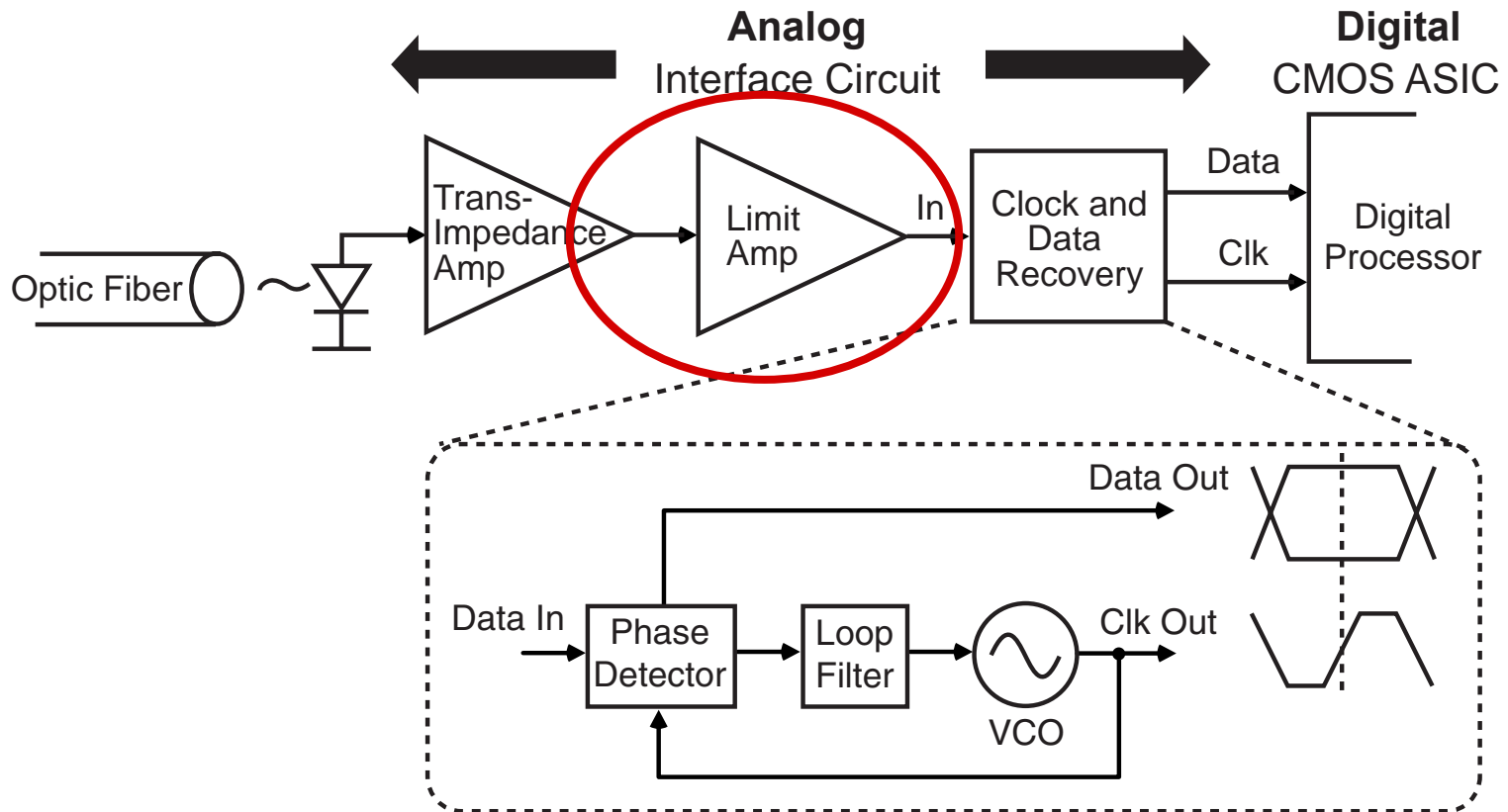
Outline

- **Fast offset compensation for CDR limit amps**
- **Fractional-N based DLL**
- **Low-jitter multiplying DLL**
- **Sub-harmonic injection-locked oscillator**

***A 3.125 Gb/s Limit Amplifier in CMOS with 42 dB
Gain and
1 μ s Offset Compensation***

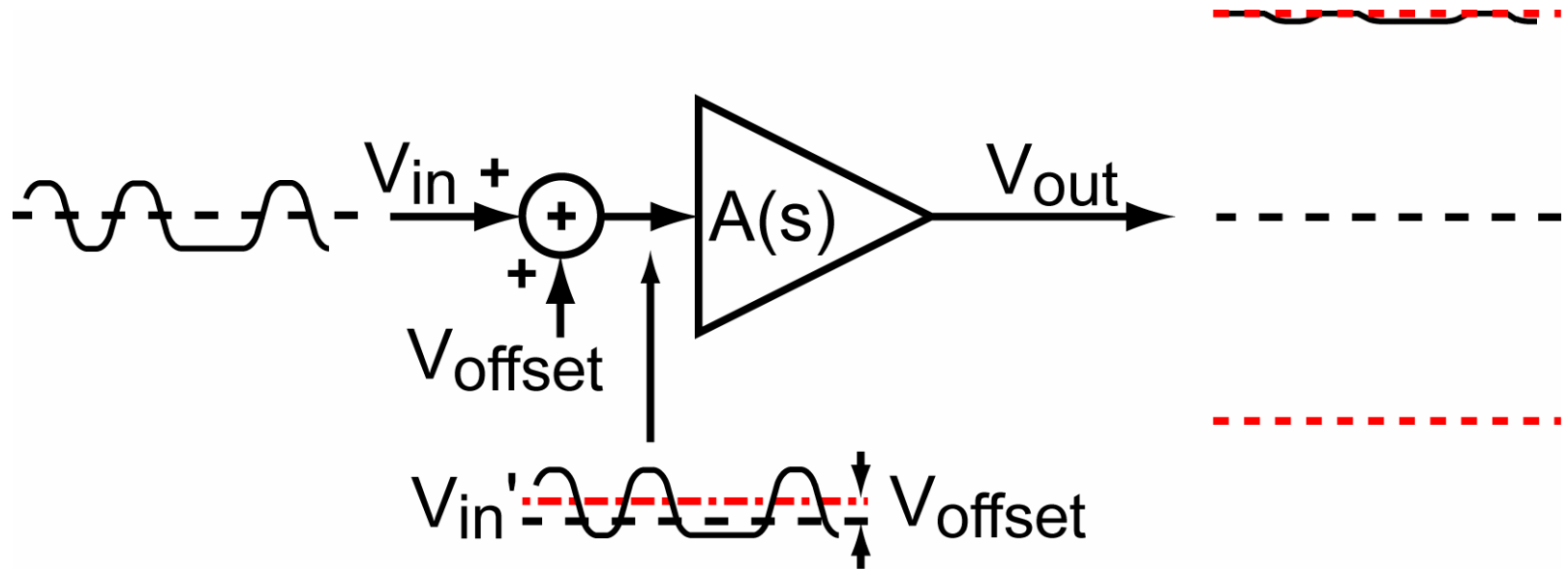
**Ethan A. Crain, Michael H. Perrott
Massachusetts Institute of Technology**

A Fast Acquisition Limit Amp



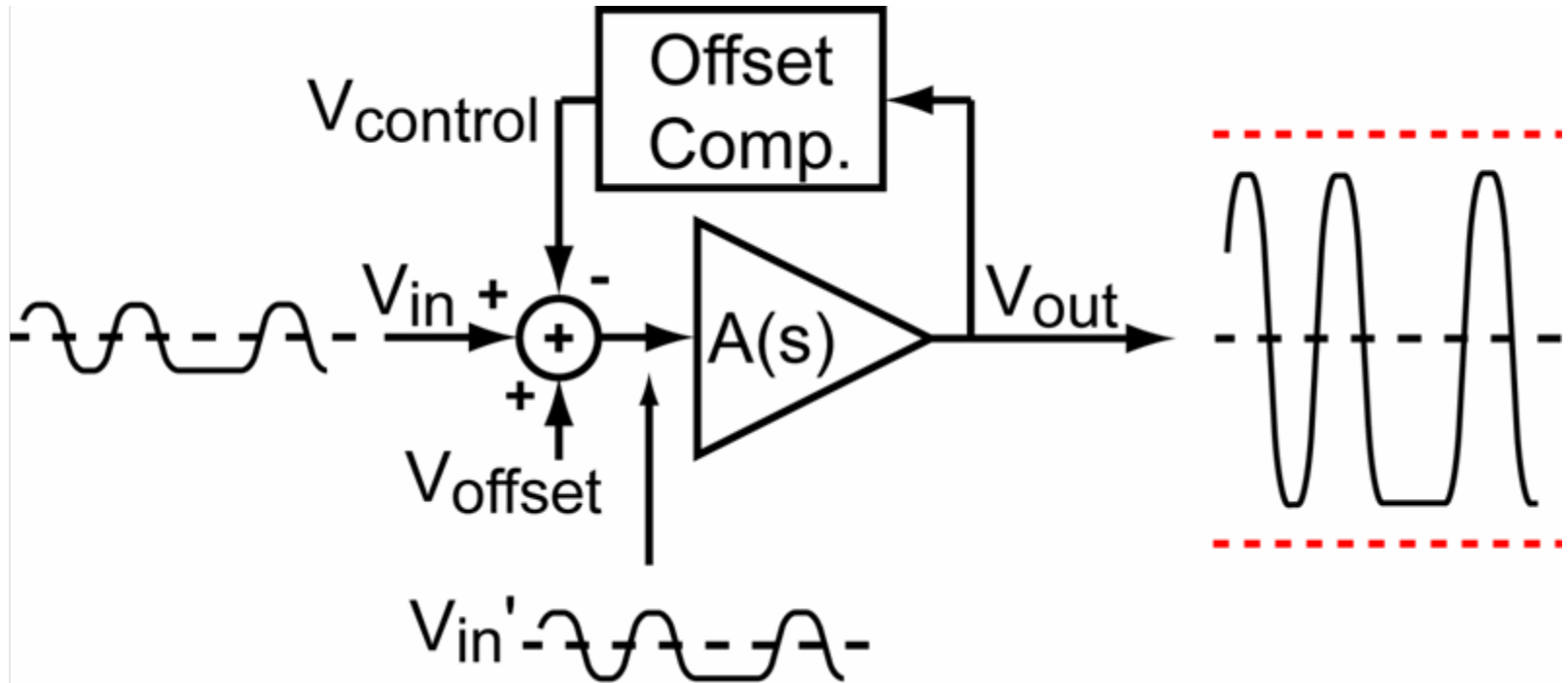
- Acquisition time of CDR is limited by slow response of limit amp offset correction loop (typically milliseconds)
- Goal: improve speed of offset correction

Motivation for Offset Compensation



Without offset compensation the output of high gain amplifiers can saturate due to offset voltage alone

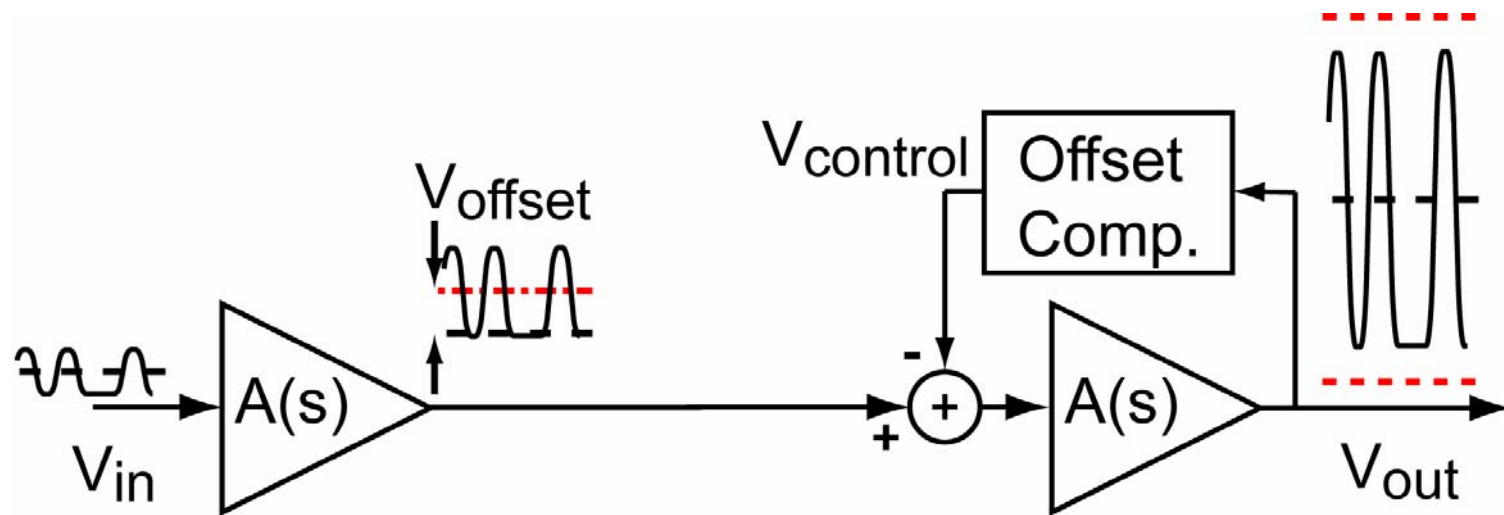
Motivation for Offset Compensation



Offset compensation is required for high gain amplifiers to prevent the output from saturating due to offset

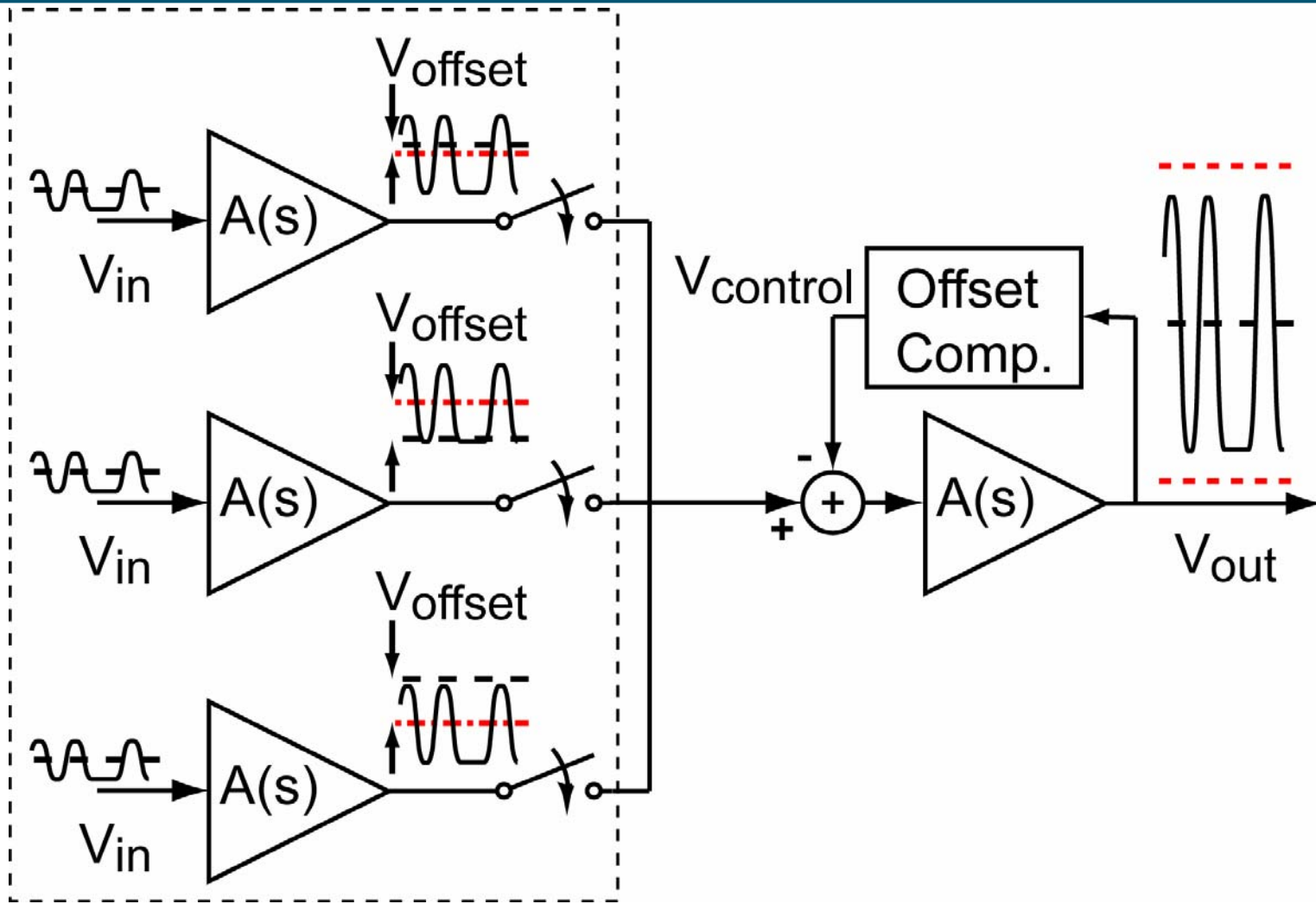
Classical offset compensation methods suffer from long compensation times

Why long settling times matter



Compensation only happens once in one-to-one links
Typical offset compensation time $\approx 1ms$

Why long settling times matter

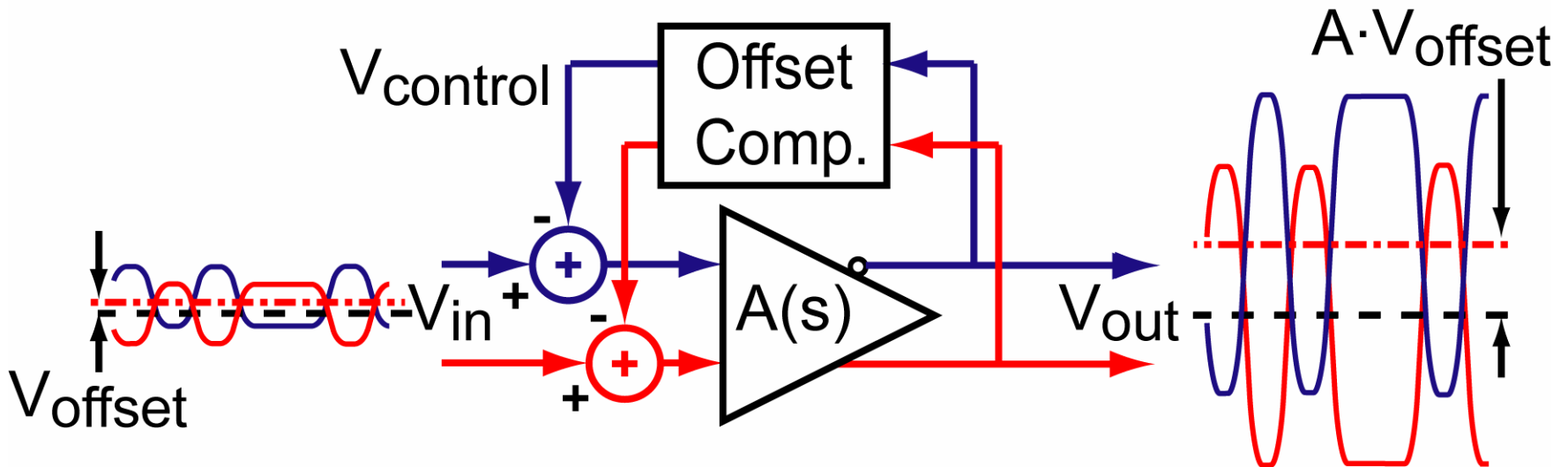


The compensation time determines how quickly we can switch between channels

Outline

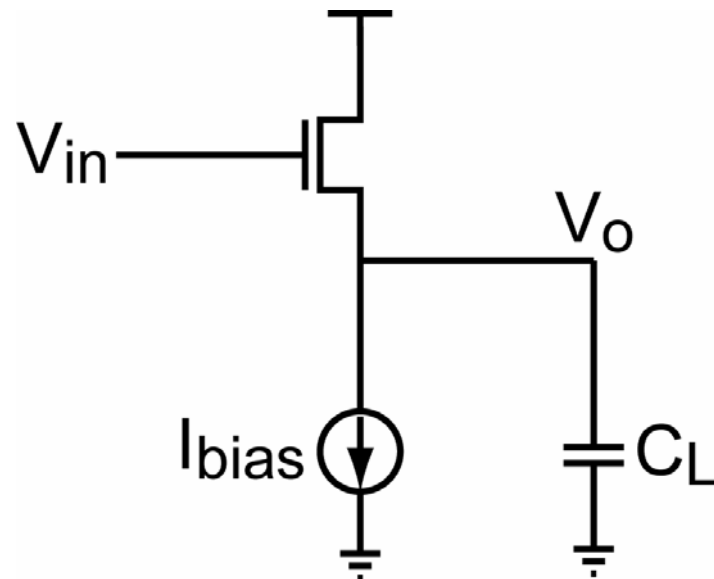
- ⇒ Proposed method
- ⇒ Peak detector design
- ⇒ System Details
- ⇒ Measured results
- ⇒ Conclusions

Proposed Method – Key Assumptions



- Assume that the data path is differential and the two data paths have approximately equal gains
- Assume that we are processing NRZ data
- The output-referred offset is equal to the difference in output common-mode levels

Traditional Peak Detector

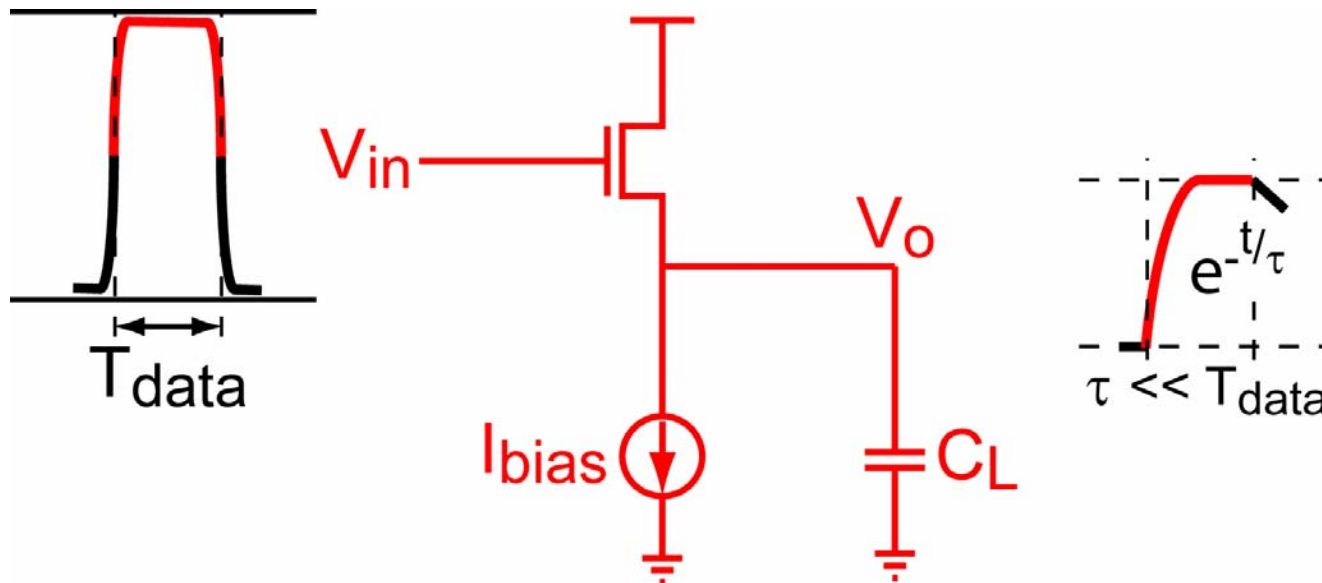


Consider operation of traditional CMOS peak detector

Operation During Track Phase

$$\frac{1}{\tau} \propto \frac{\sqrt{I_{bias}}}{C_L}$$

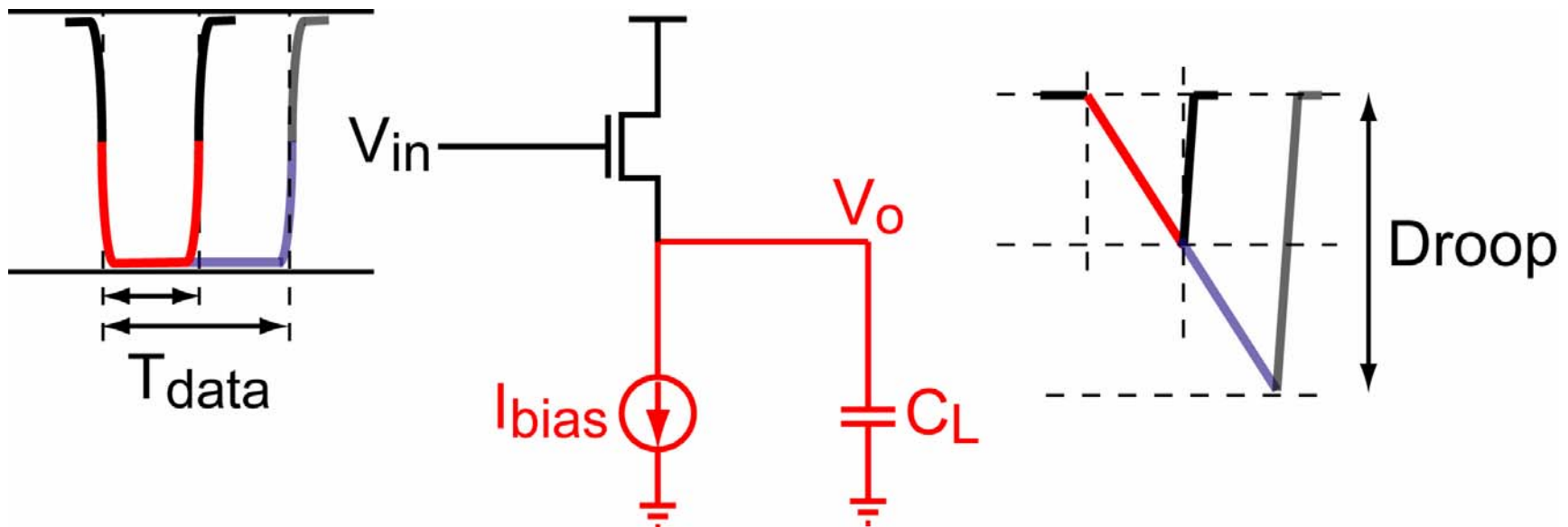
$$\text{Slew Rate} \propto \frac{I_{bias}}{C_L}$$



Fast Offset Compensation \rightarrow Large I_{bias}

Operation During Hold Phase

$$\text{Droop} = I_{bias} \cdot \frac{T_{data}}{C_L}$$



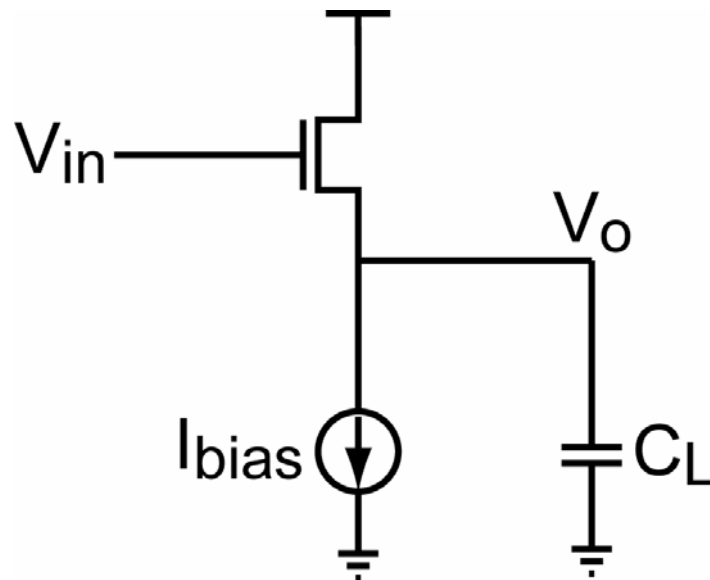
Droop proportional to both I_{bias} and T_{data}

Data dependent droop \rightarrow Jitter (ISI)

Small Jitter \rightarrow Small I_{bias}

Trade-Off for Traditional Peak Detector

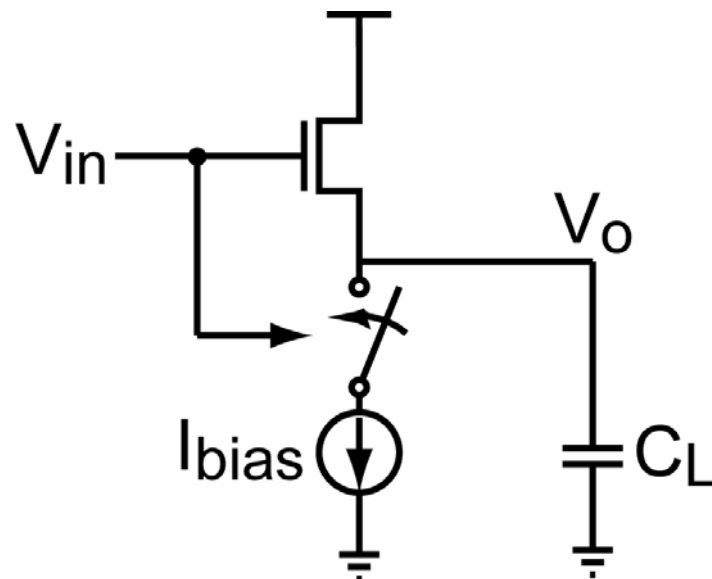
Trade-off between *settling time* and *jitter performance* due to Inter-Symbol Interference!



Fast Settling \rightarrow *Large* I_{bias} Low Jitter \rightarrow *Small* I_{bias}

Can we modify the design to improve the trade-off?

Proposed Solution

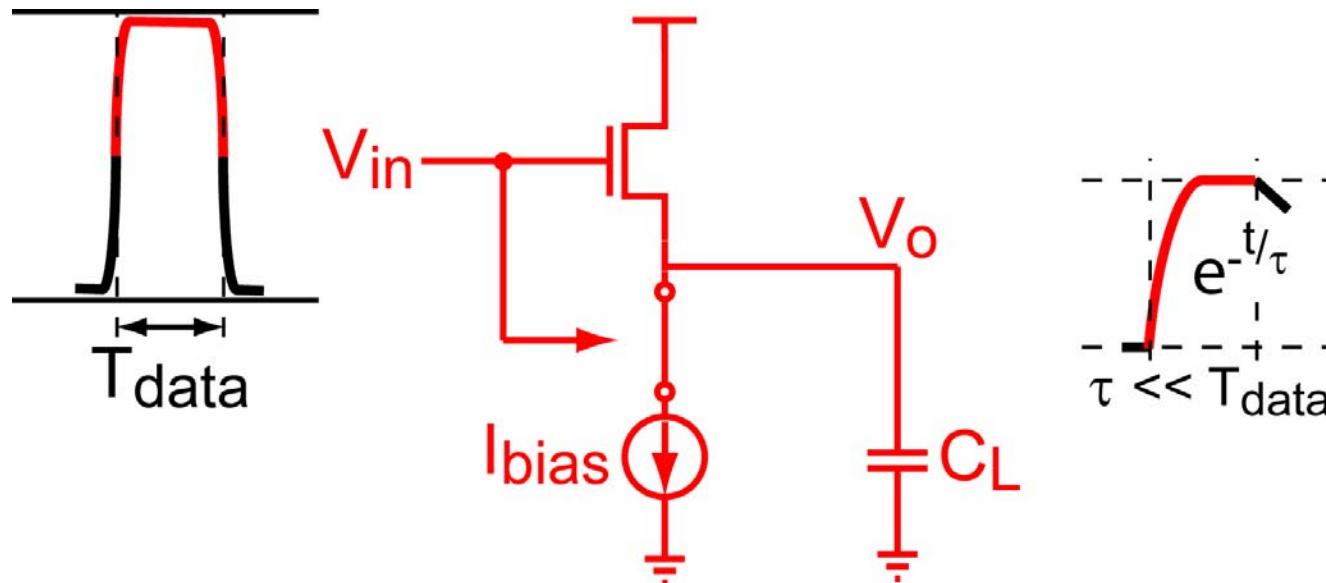


Add switch device that is controlled by the input

Proposed Solution – Track Phase

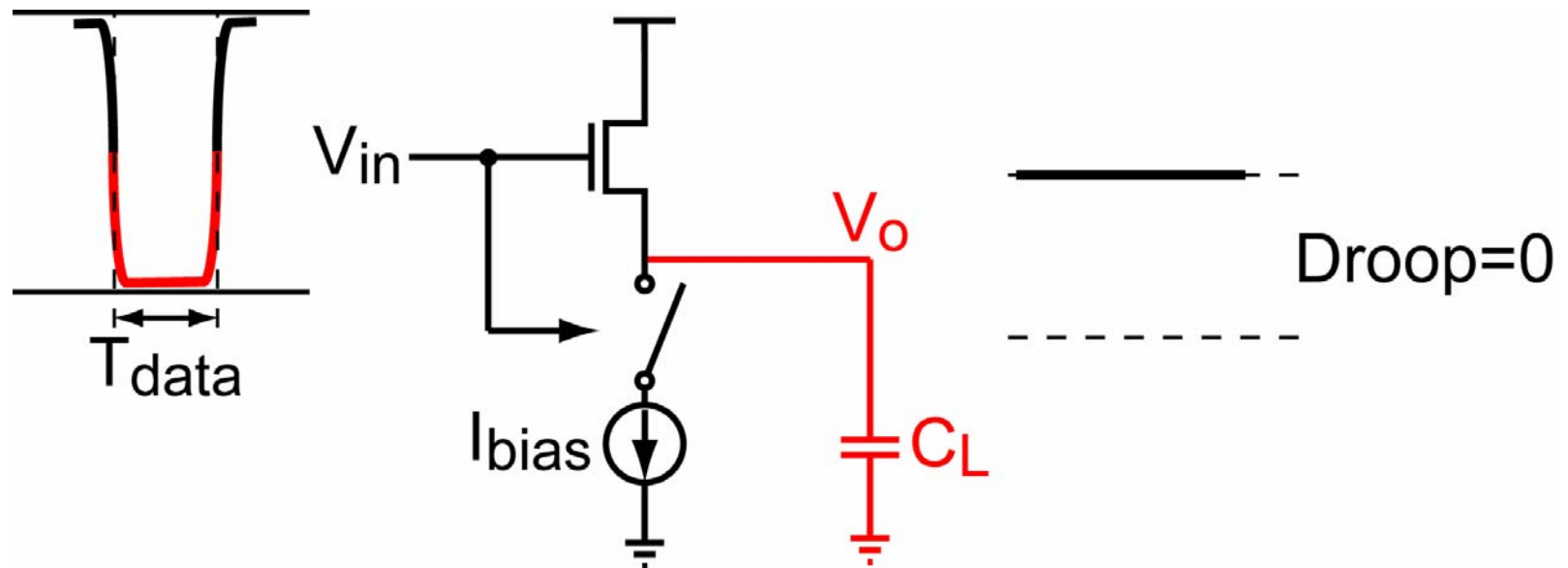
$$\frac{1}{\tau} \propto \frac{\sqrt{I_{bias}}}{C_L}$$

$$\text{Slew Rate} \propto \frac{I_{bias}}{C_L}$$



Same operation as original peak detector circuit

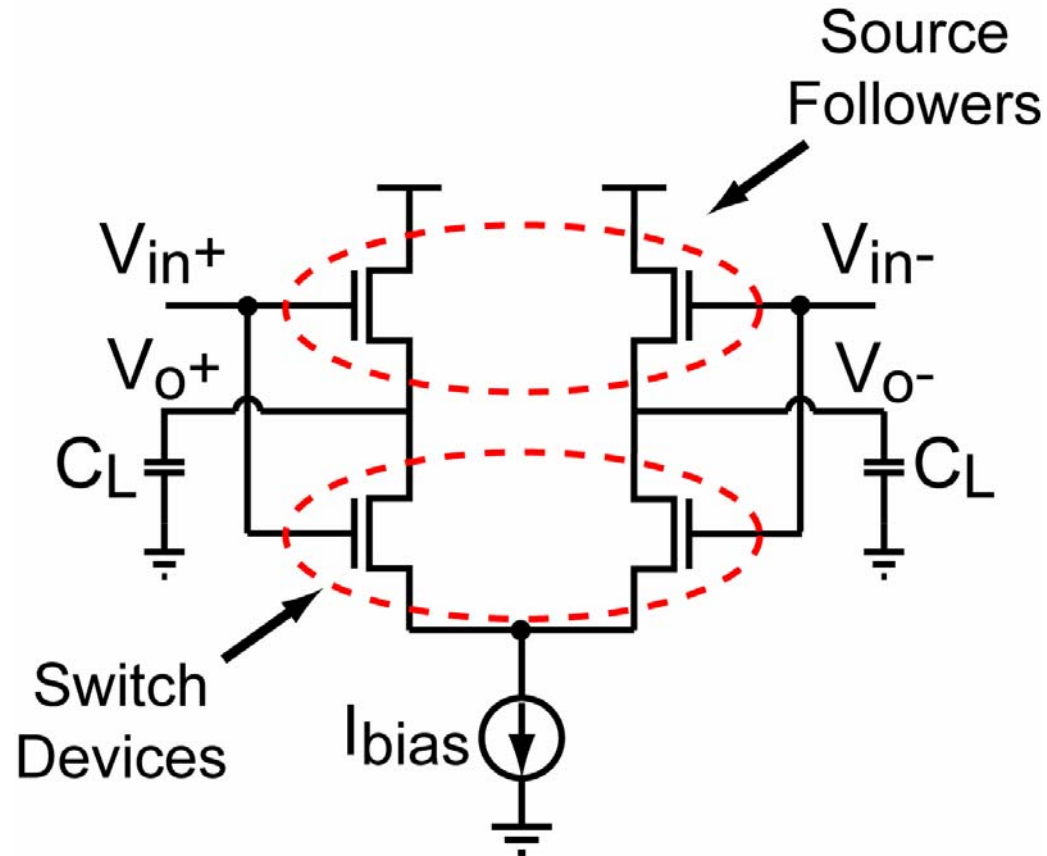
Proposed Solution – Hold Phase



Droop is ideally independent of both I_{bias} and T_{data}

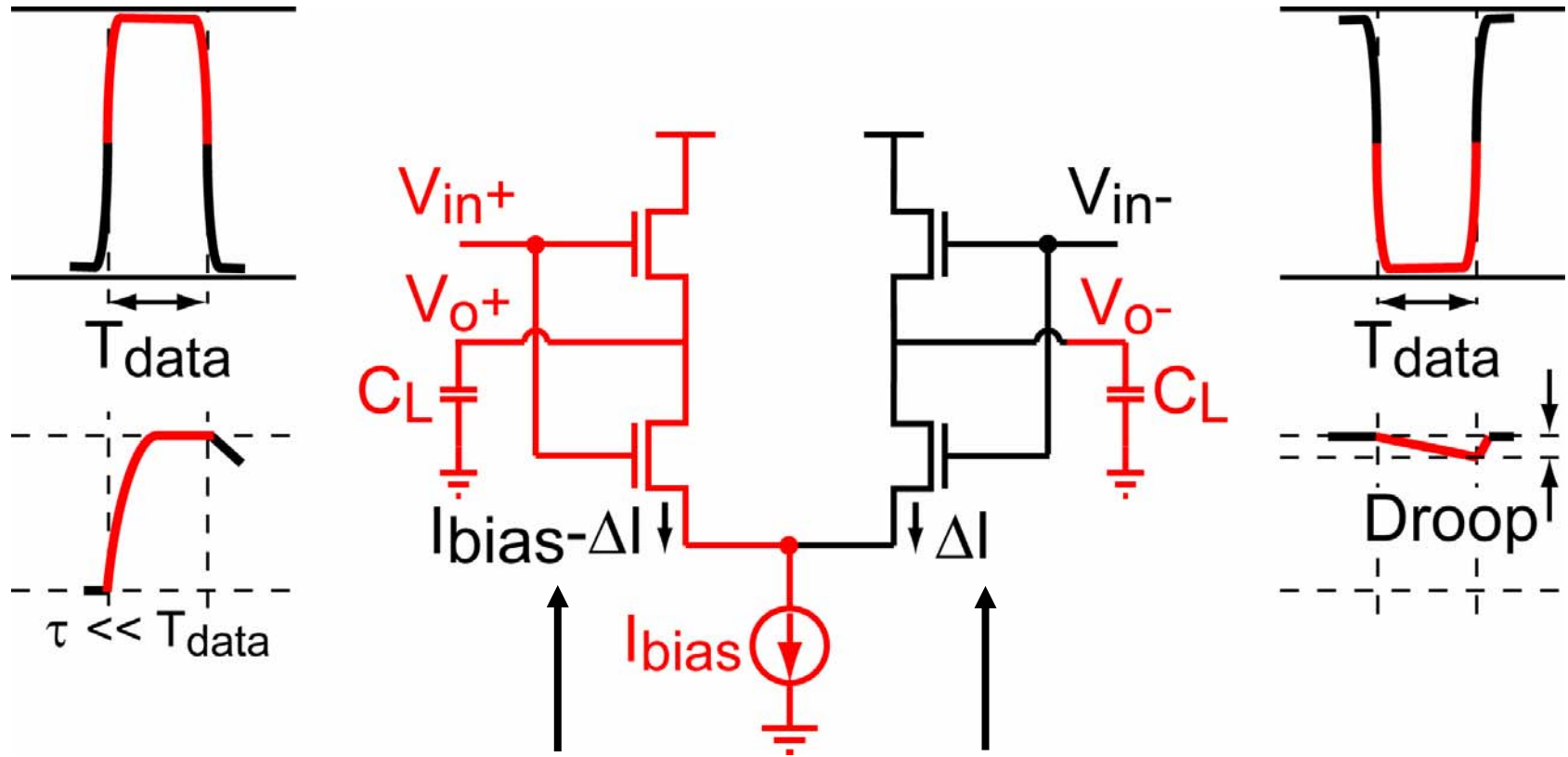
Can achieve small jitter with a large I_{bias}

Proposed Solution – Differential Design



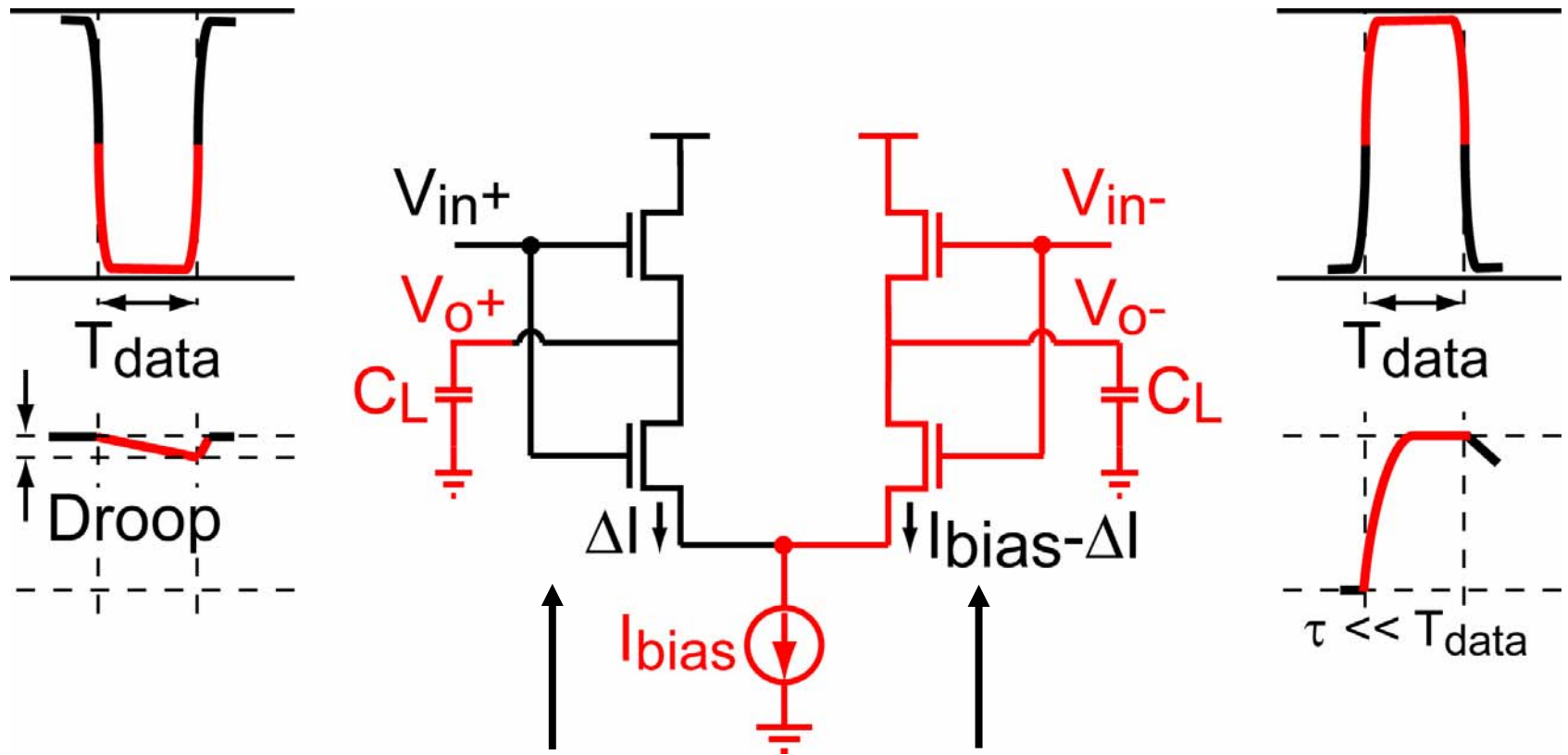
Use inputs to switch I_{bias} between the two source-follower circuits

Proposed Solution – Operation



Incomplete switching causes non-zero droop

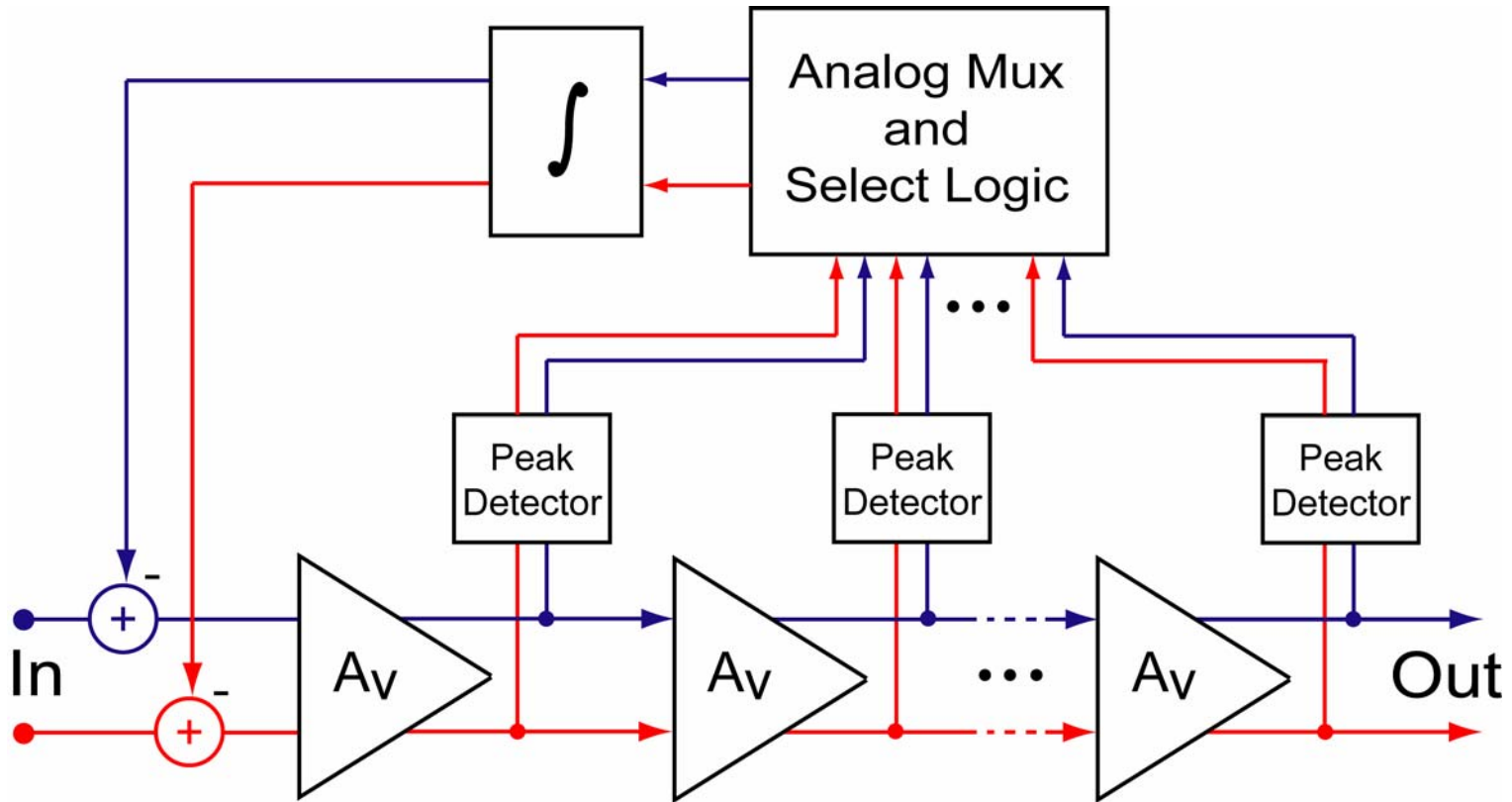
Proposed Solution – Operation



Incomplete switching causes non-zero droop

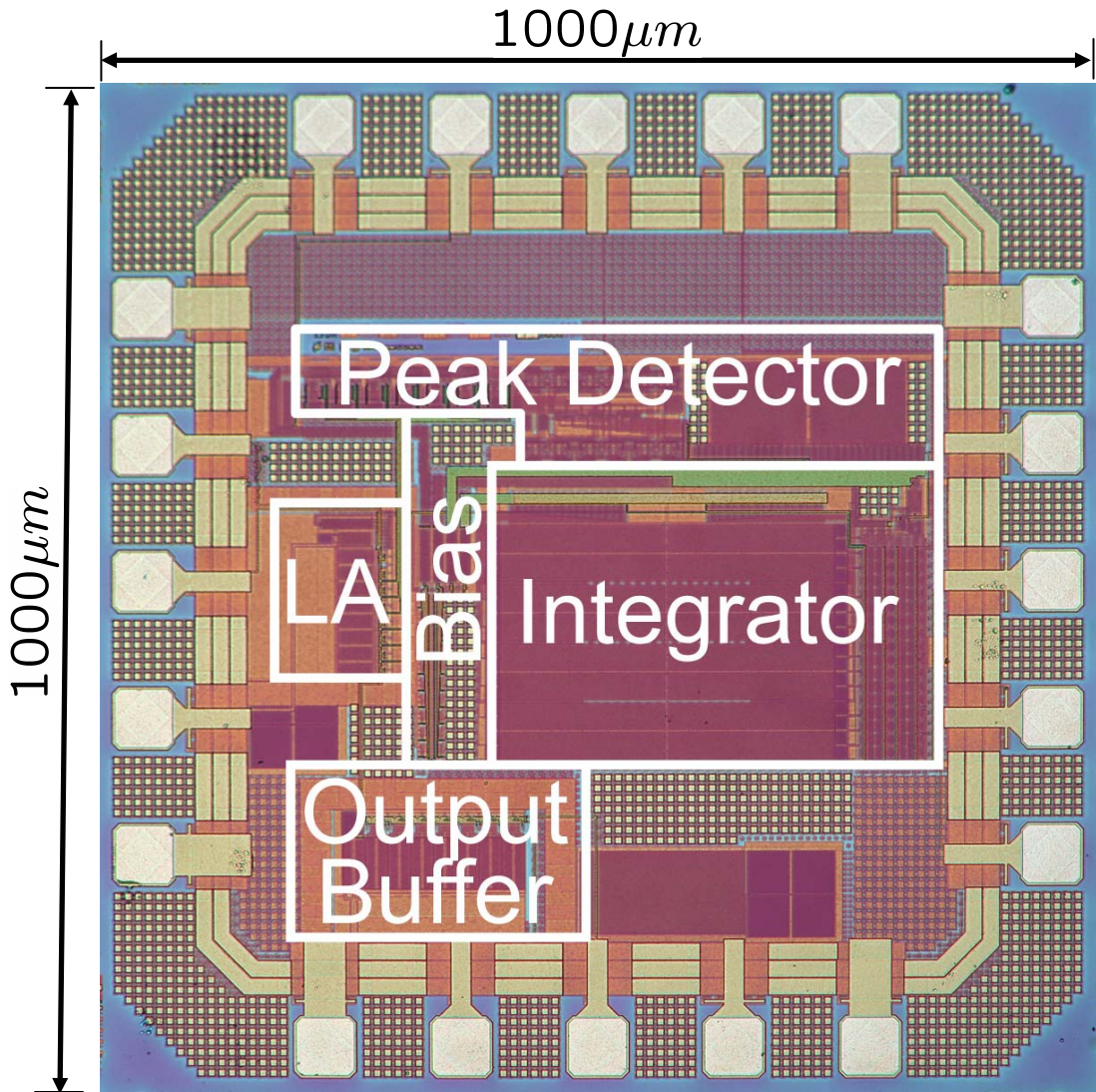
Simultaneously achieve fast offset compensation and low droop

Multi-Tap Compensation



- Dynamic multi-tap control loops are required
- Peak detector at each amplifier output
- All loops have matched gain

Test System – Die Micrograph



Fabricated in National Semiconductor's
0.18 μm CMOS process

- 3.125Gb/s limit-amp.
42dB gain
5GHz BW
- Compensation
time $< 1\mu\text{s}$
- Meet OC48 jitter specs.
 $< 4\text{ps}_{RMS}$ @ 2.5Gb/s
- Total area: 1mm^2
- Active area: 0.5mm^2
- Supply Voltage: 1.8V
- Total Power: 338mW
- Power of LA & Offset
Compensation: 113mW

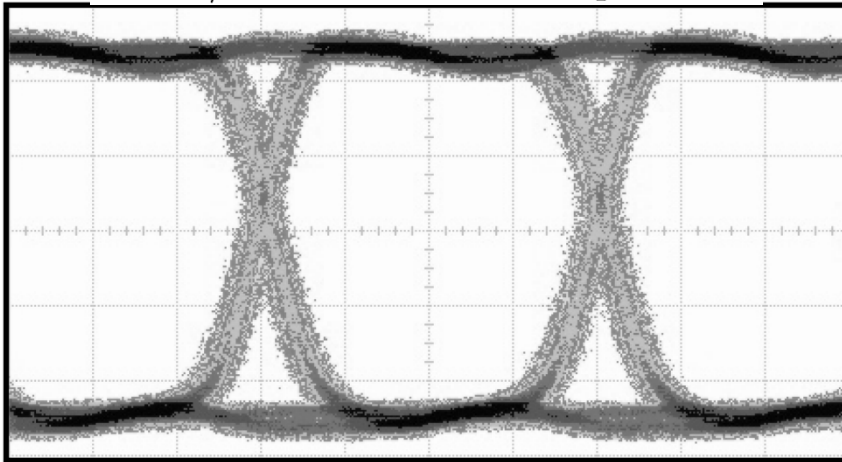
Test System – Measured Results

Eye diagrams with $2.5mV_{pp}$ PRBS $2^{31} - 1$ input

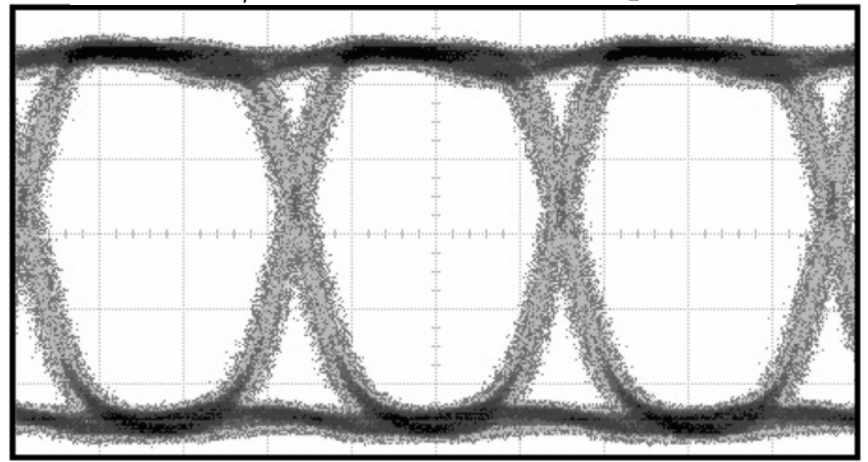
Offset Compensation Settling time $\approx 1\mu s$

$2.5Gb/s \rightarrow Jitter = 3.71ps$ RMS

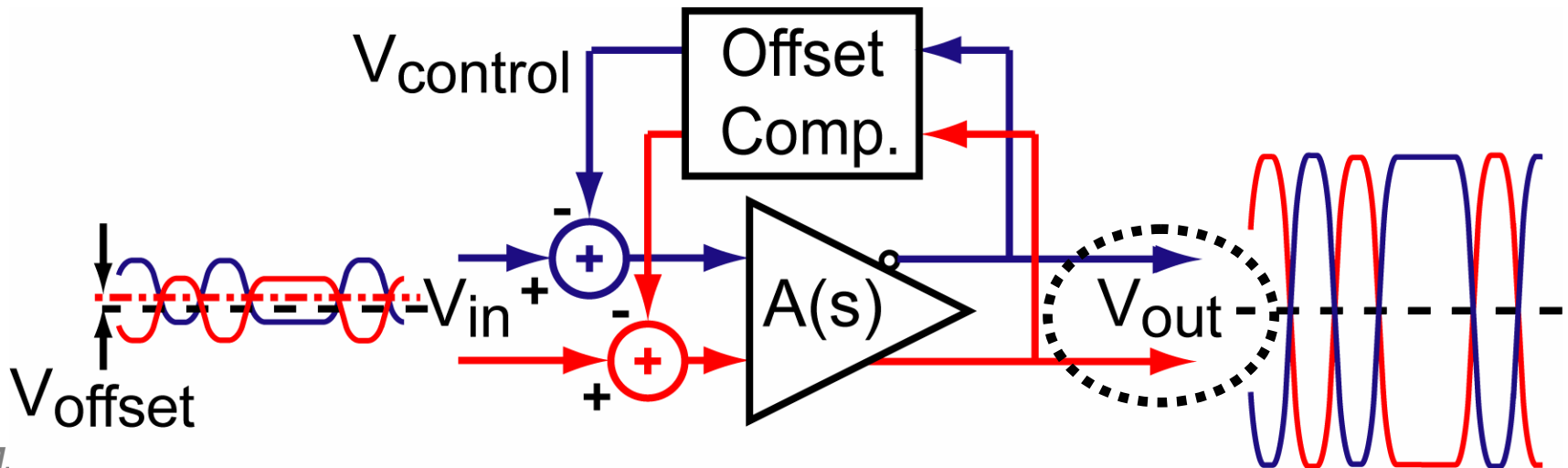
$3.125Gb/s \rightarrow Jitter = 5.90ps$ RMS



Horizontal Scale: 100ps/div Vertical Scale: 50mV/div



Horizontal Scale: 100ps/div Vertical Scale: 50mV/div

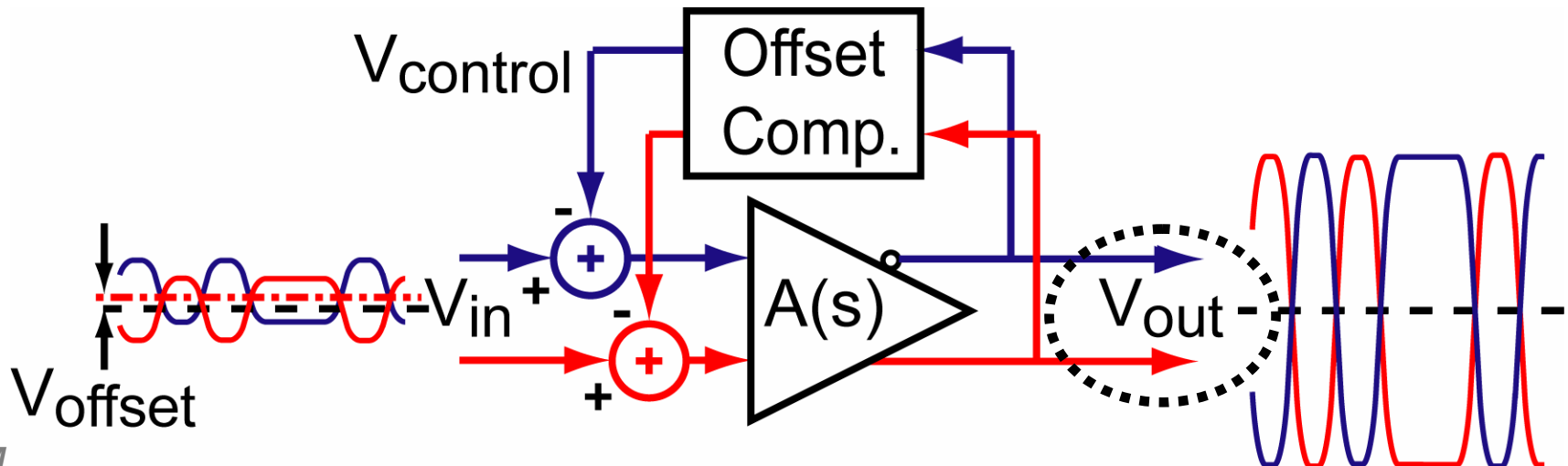


Test System – Measured Results

Offset Compensation Settling time $\approx 1\mu s$

	Data Rate		
Input Amp	1.0Gb/s	2.5Gb/s	3.125Gb/s
2.5mVpp	3.94	3.71	5.90
10mVpp	2.65	2.86	6.30
50mVpp	1.13	2.52	7.98

Meets OC-48 Jitter Spec ($< 4.0ps$ RMS) down to $V_{in,pp} = 2.5mV$

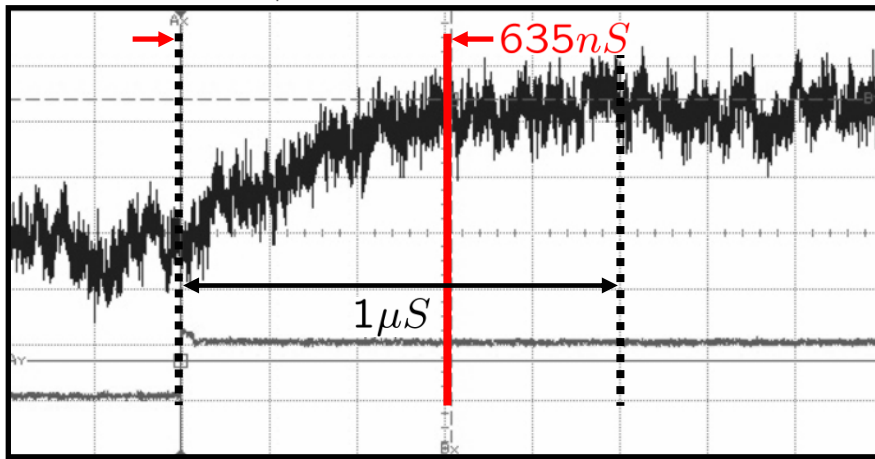


Test System – Measured Results

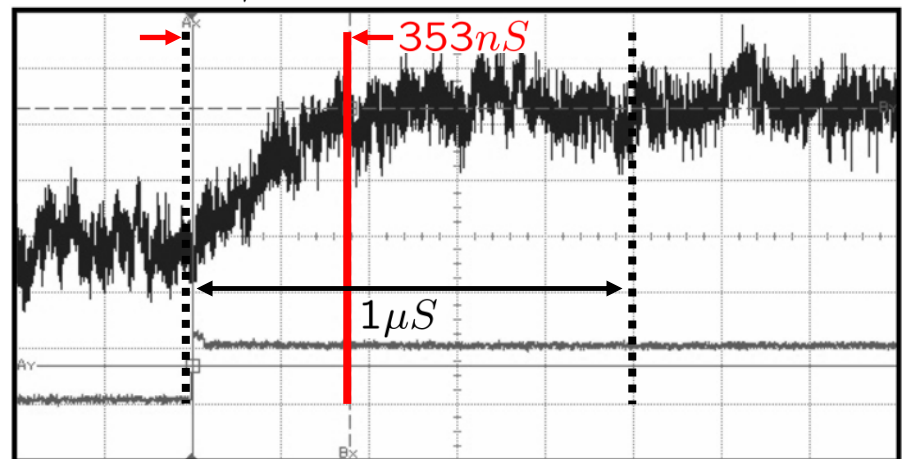
Control voltage step-response with a $5.0mV_{pp}$ PRBS $2^{31} - 1$ input

Compensation Settling time goal $\approx 1\mu s$
 $3.125Gb/s \rightarrow Jitter = 5.75ps$ RMS

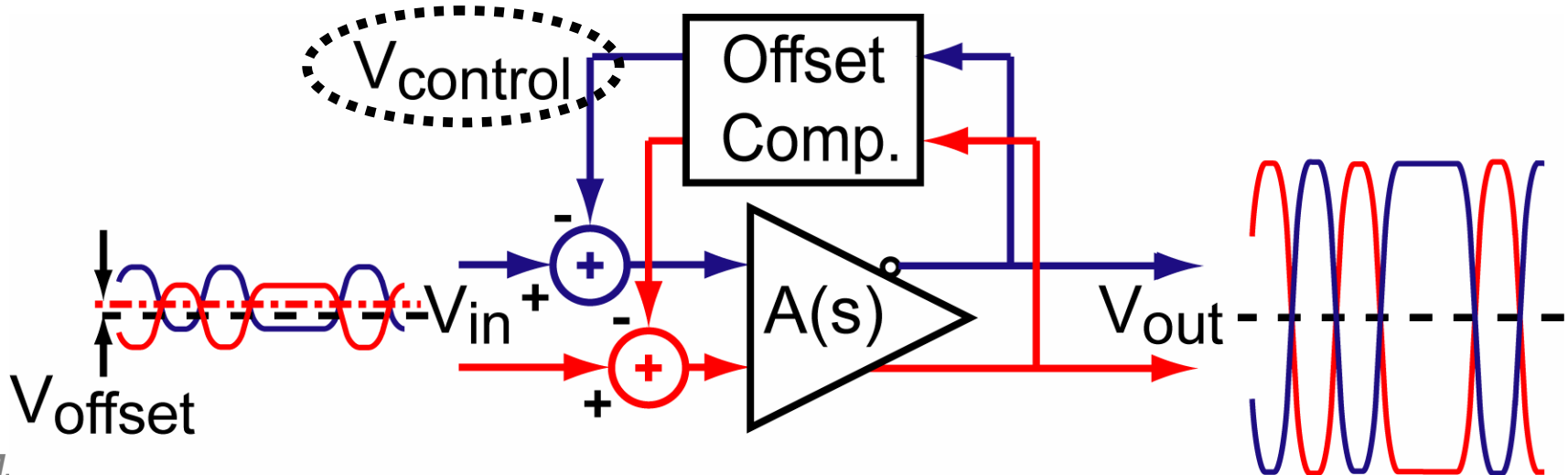
Compensation Settling time goal $\approx 0.33\mu s$
 $3.125Gb/s \rightarrow Jitter = 5.90ps$ RMS



Horizontal Scale: 200ns/div Vertical Scale: 5mV/div



Horizontal Scale: 200ns/div Vertical Scale: 5mV/div



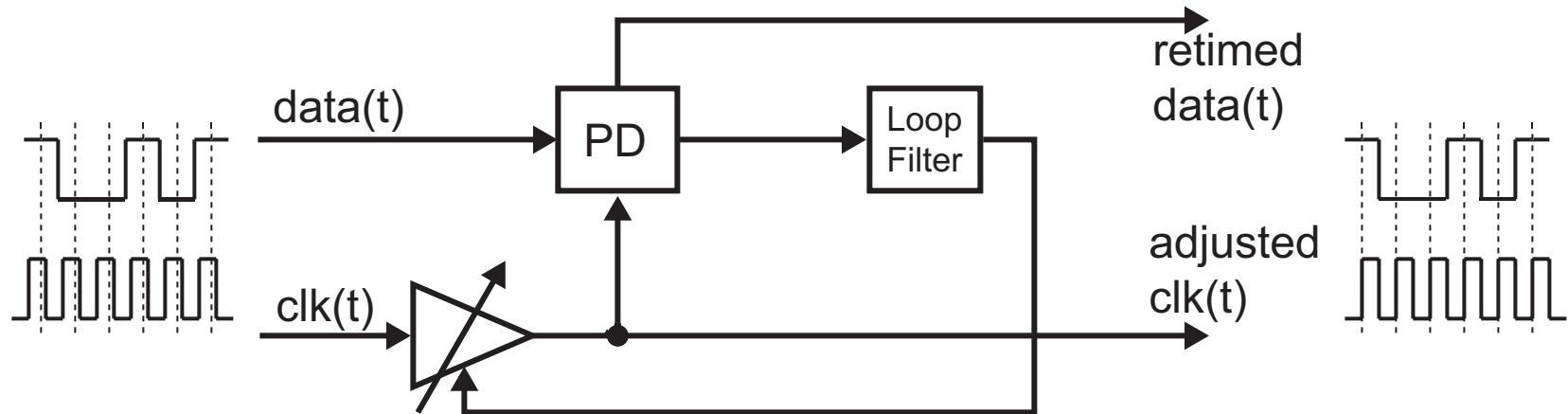
Summary

- Proposed peak detector design enables a *1000x improvement* in the trade-off between settling time and output jitter by changing relationship between peak detector bandwidth and output droop
- Implemented and tested system with proposed offset compensation method that has *2.5mVpp input sensitivity* and that meets OC48 jitter specifications (< 4ps RMS @ 2.5Gb/s)
- Behavior model download:
 - <http://www.cppsim.com>

***A Delay-Locked Loop using a Synthesizer-based
Phase Shifter for 3.2 Gb/s
Chip-to-Chip Communication***

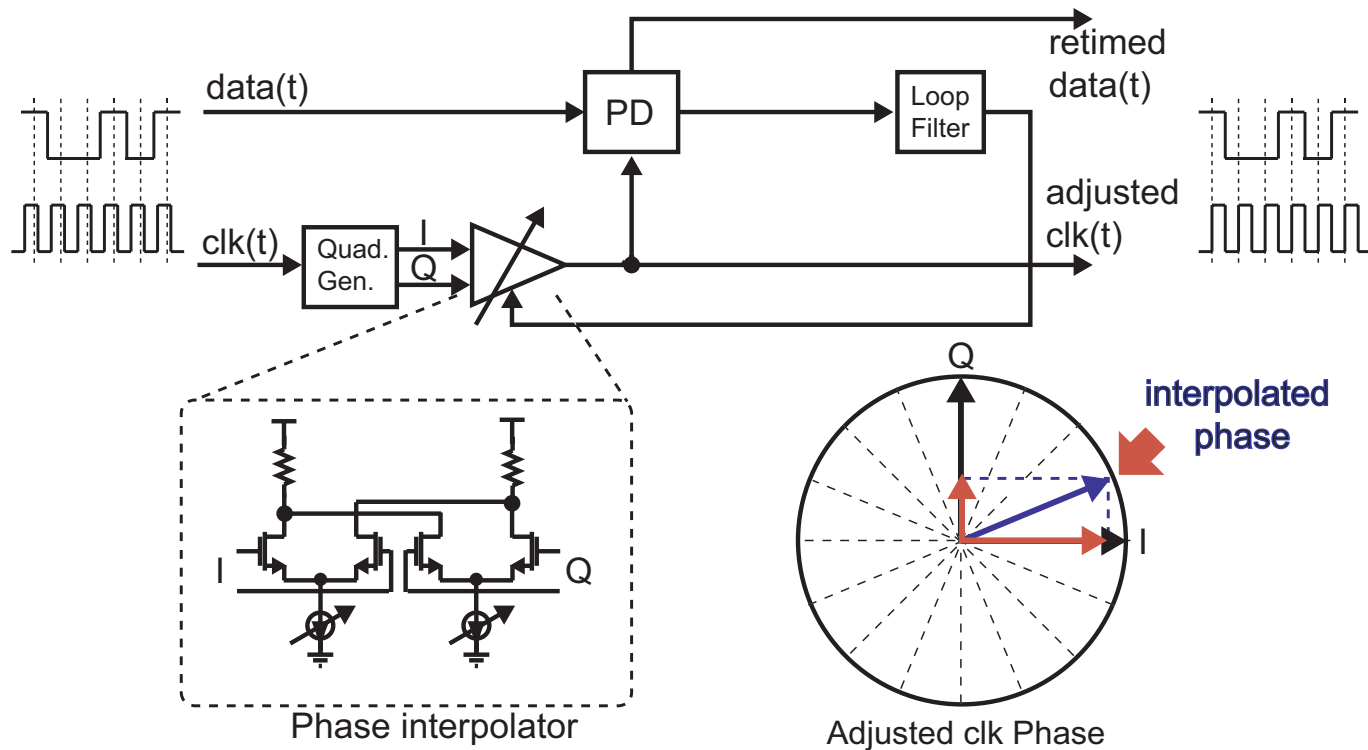
**Chun-Ming Hsu, Charlotte Y. Lau, Michael H. Perrott
Massachusetts Institute of Technology**

Delay-Locked Loop for Data Recovery



- In some applications, a reference clock that is perfectly matched in frequency to data sequence is available
 - Phase mismatch is present due to different propagation delays between clock and data on the PC board
- A delay-locked loop limits adjustment to phase (as opposed to phase and frequency)
 - Faster, and much simpler to design than PLL structure

Delay-Locked Loop using Phase-Interpolator

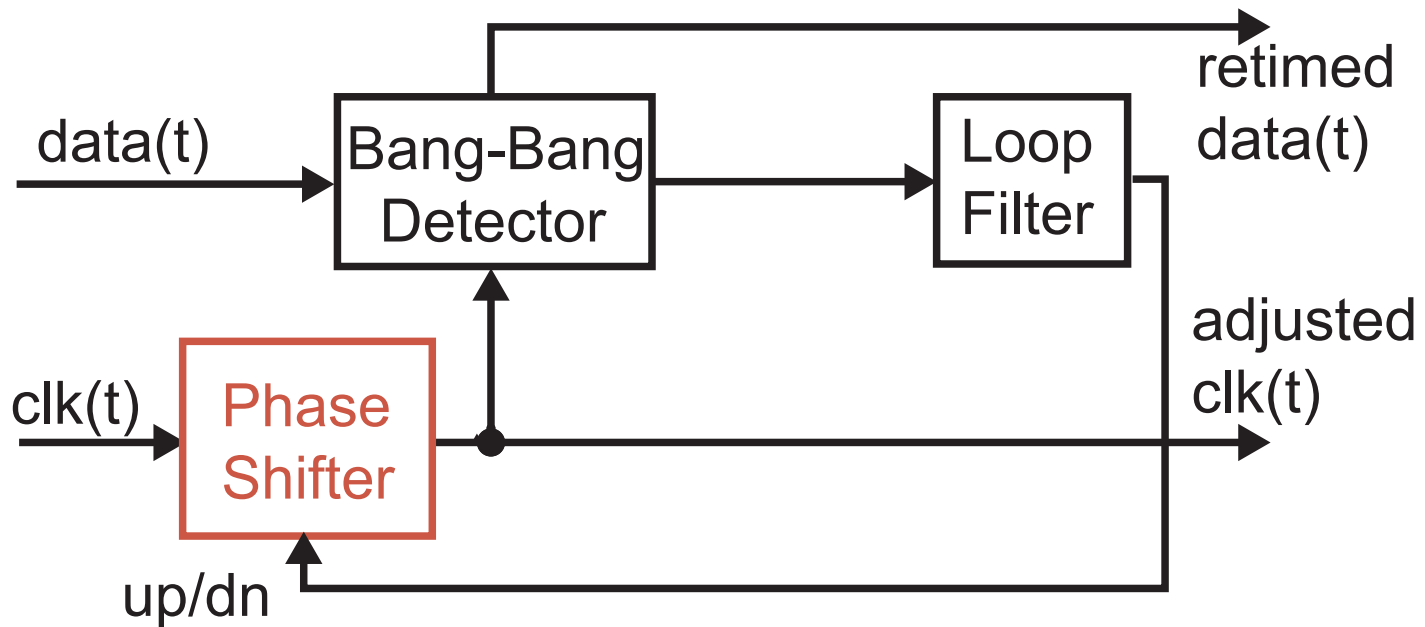


- Infinite delay range and good jitter performance
- Issue:

**Good matching needed for accurate phase control,
but future processes promise high variation ...**

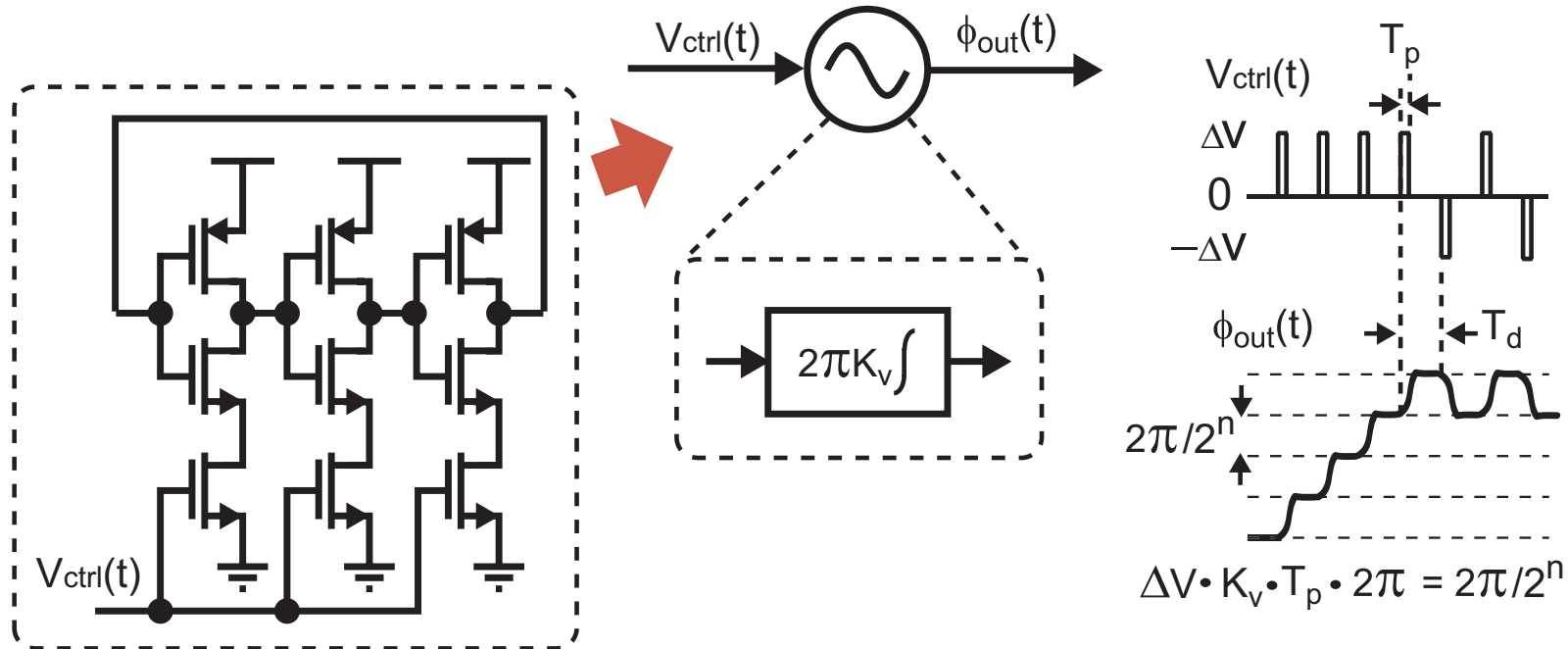
Can we eliminate the need for good matching?

Proposed DLL



- Use Σ - Δ frequency synthesizer as a phase shifter

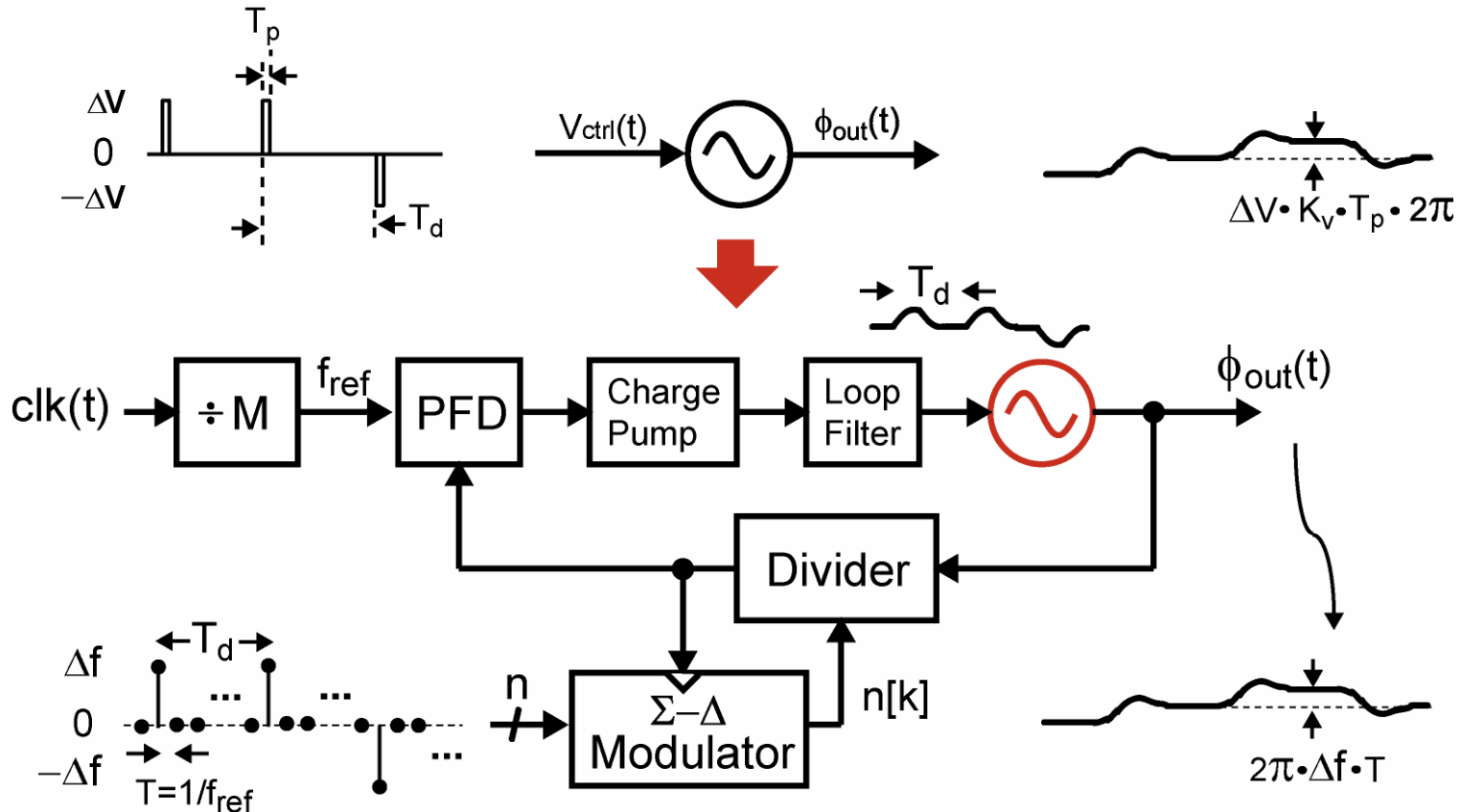
VCO-based Phase Shifter



- VCO output phase increases or decreases by a step when a pulse is fed into it
- Fine phase resolution and infinite range are achieved

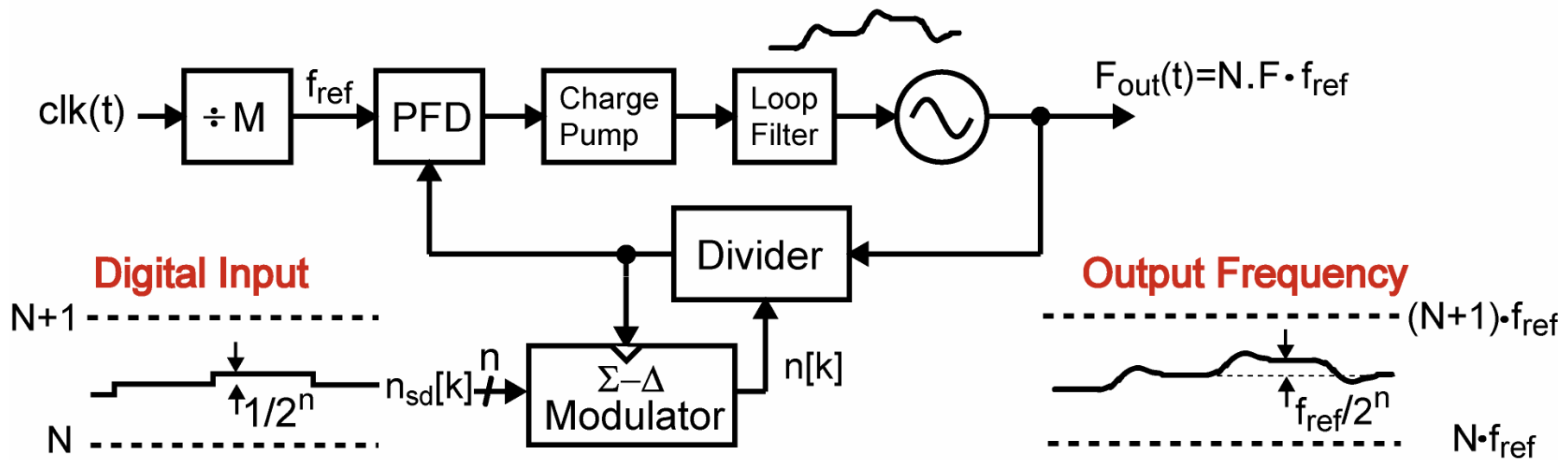
Issue1: How to control the VCO frequency accurately?
Issue2: How to control the phase step accurately?

Solution: Synthesizer-based Phase Shifter



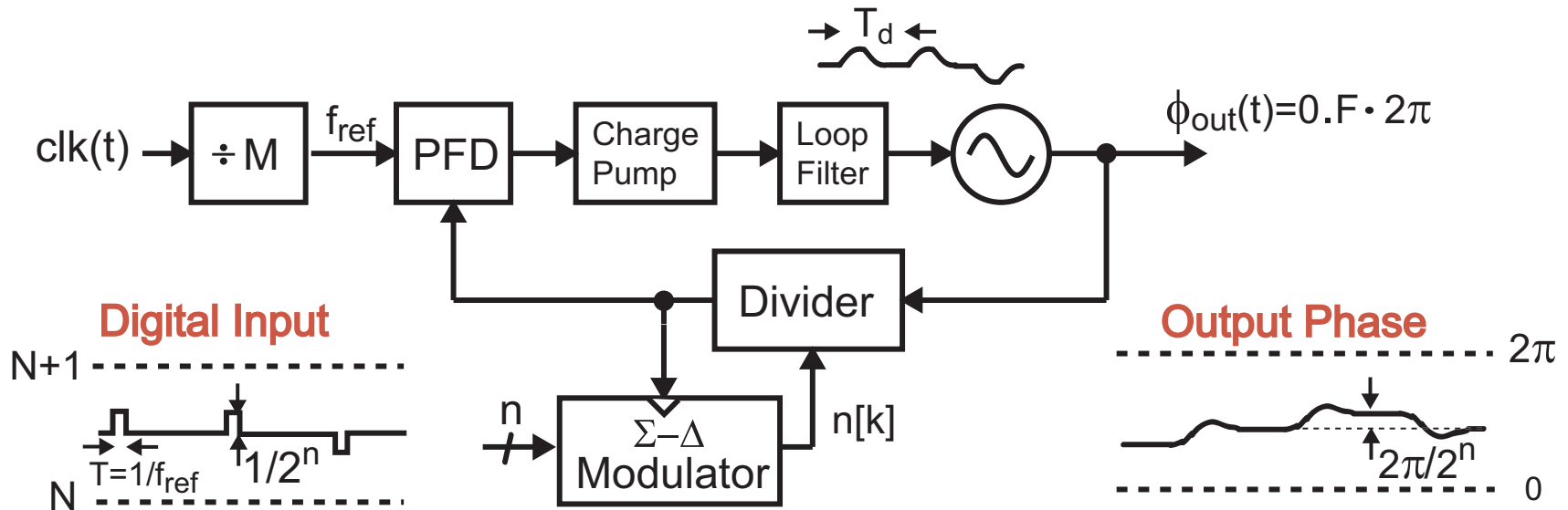
- Use a PLL to lock VCO frequency to received clock
- Use Σ - Δ technique *in digital domain* to control the VCO phase

Most Synthesizer Applications Look at **Frequency**



- Fractional output frequency is provided by a fractional-N frequency synthesizer

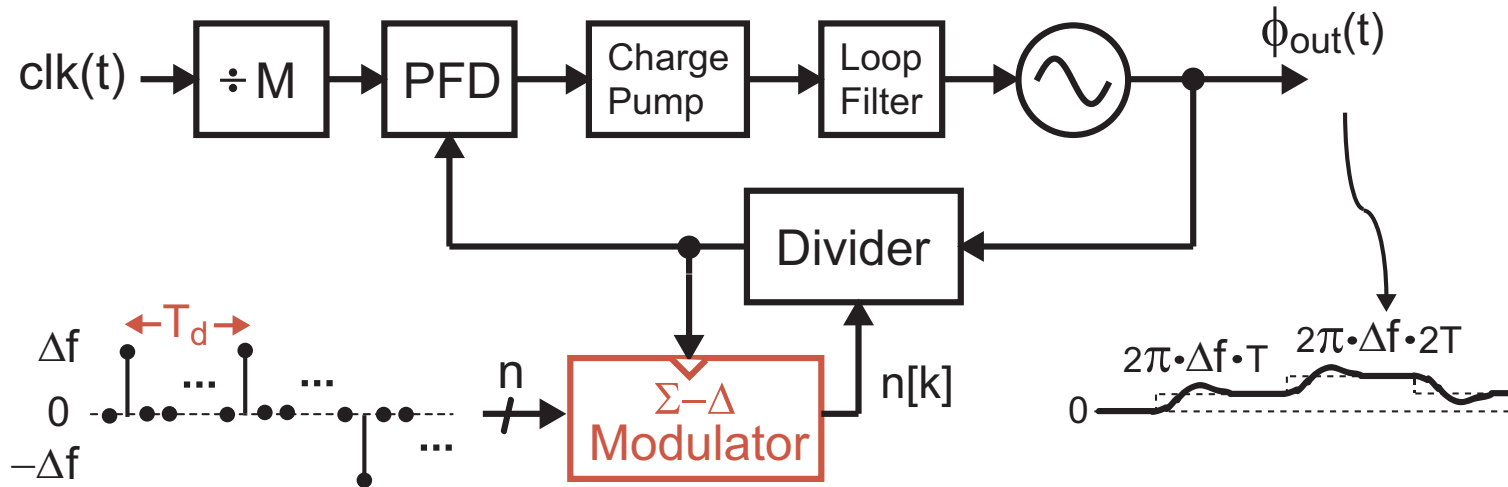
Here We Will Look at **Phase**



- Phase step decreases together with pulse height

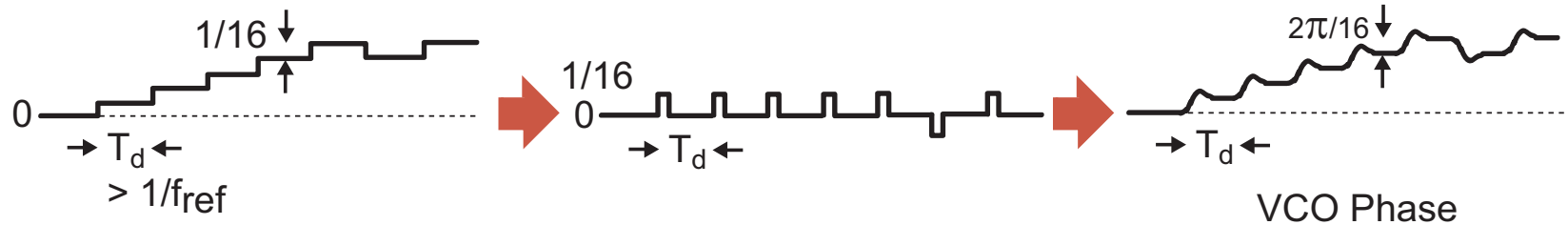
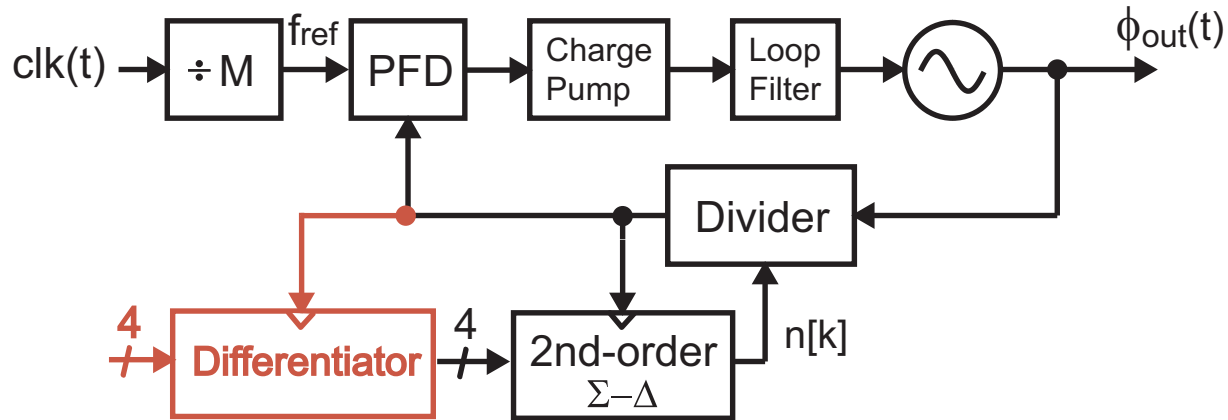
Phase step is determined only by the number of bits of the $\Sigma-\Delta$ modulator \rightarrow No process, voltage, and temperature (PVT) variations

Design Consideration of the Phase Shifter



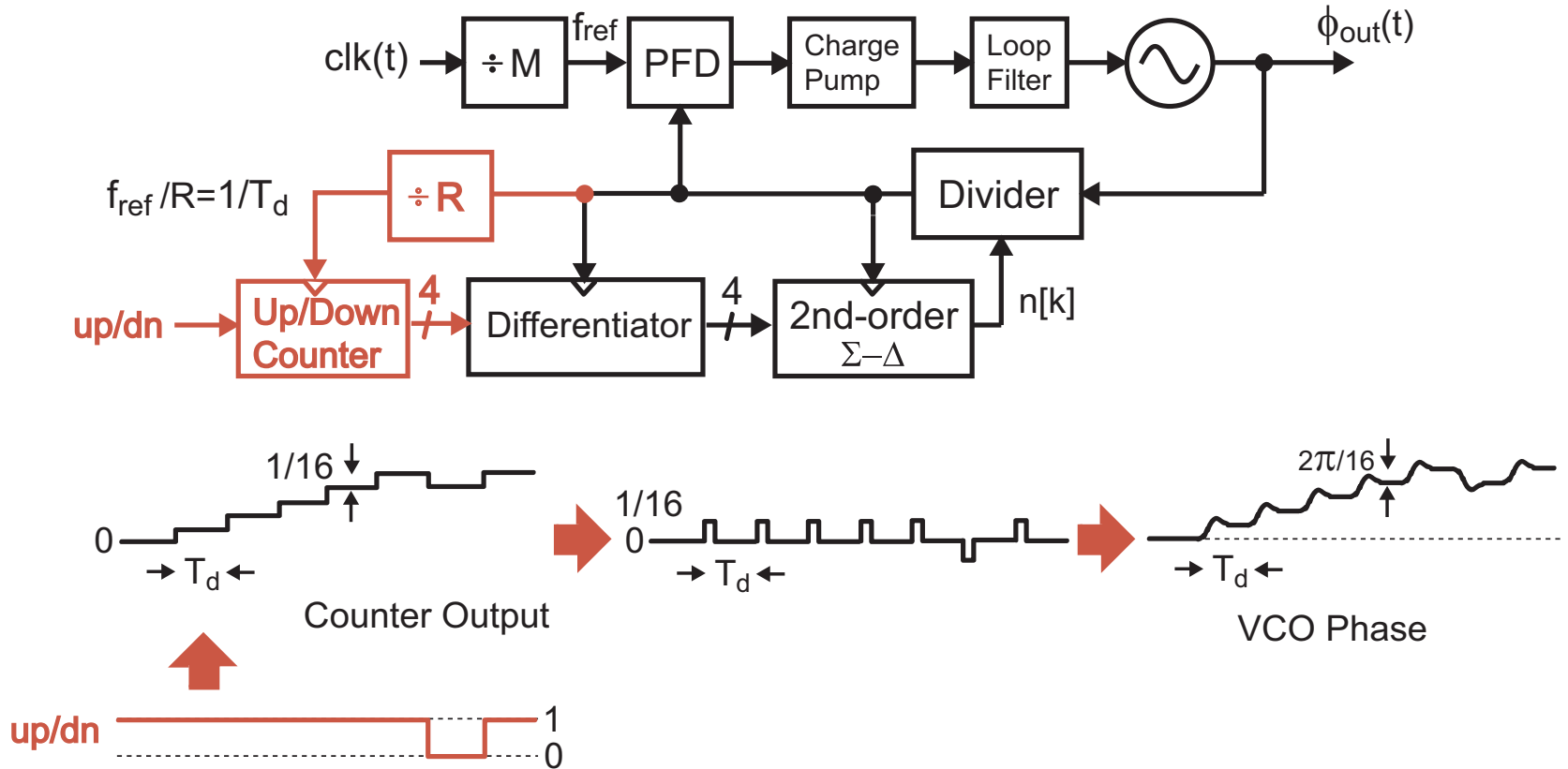
- Wait enough time before feeding next pulse to allow proper settling of VCO phase → $T_d > 1/\text{bandwidth}$
- How to implement a simple $\Sigma-\Delta$ modulator?

Phase Shifter Guided by Staircase Input



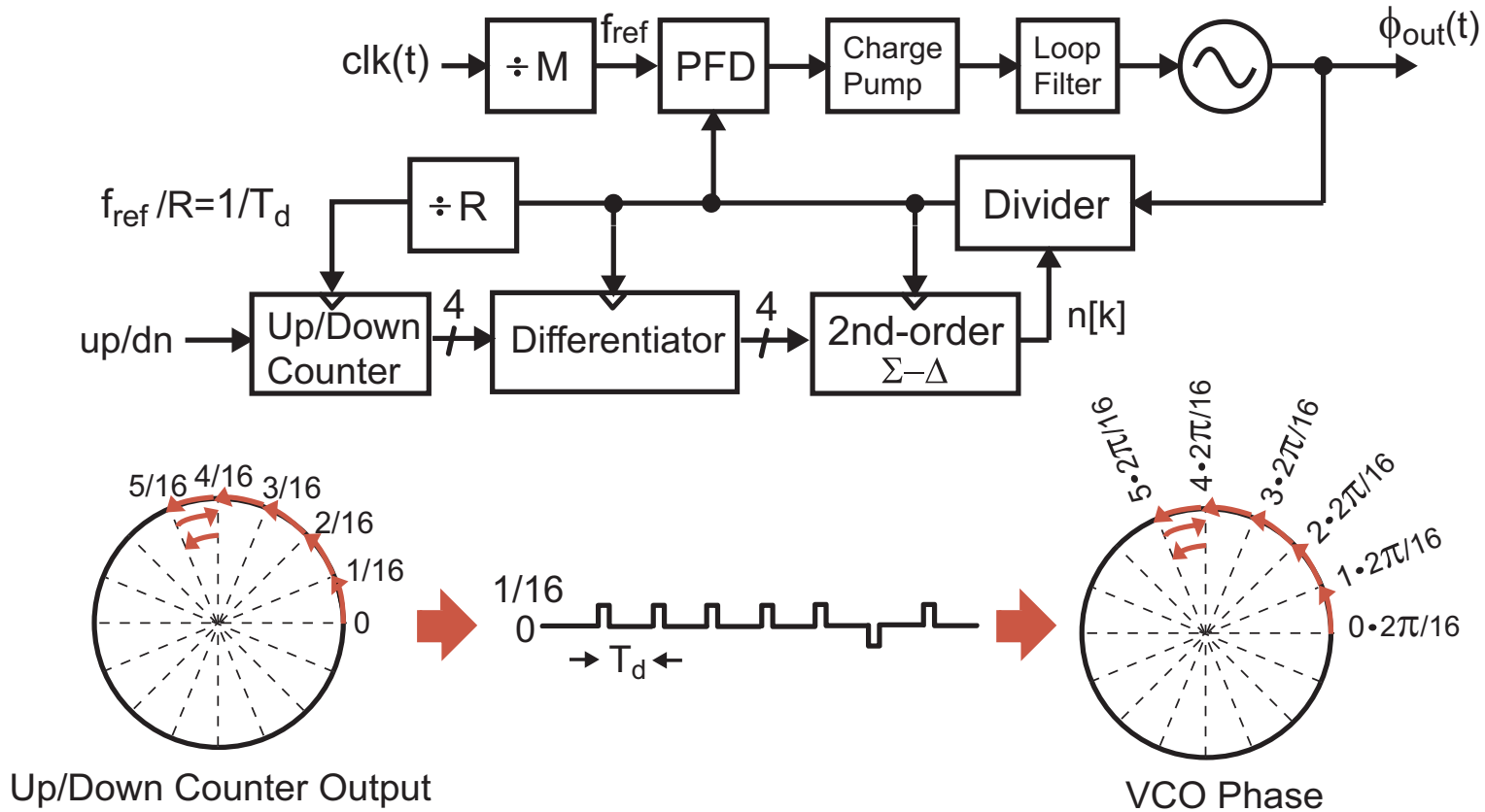
- Use a differentiator to generate the pulses from a staircase input

Phase Shifter Guided by Up/Down Counter



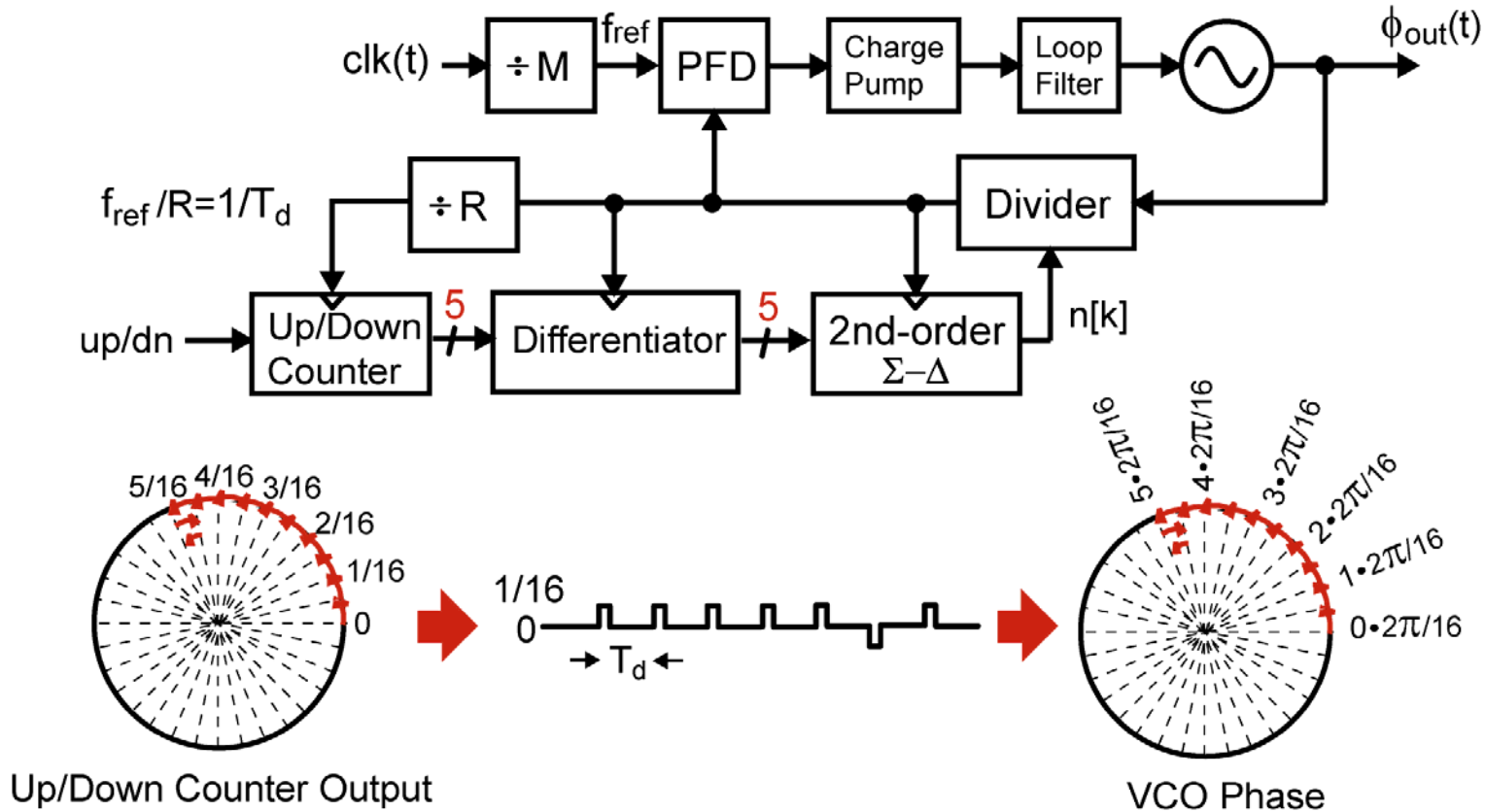
- VCO phase shifts according to Up/Down counter

Phase Shifter Guided by Up/Down Counter (cont'd)



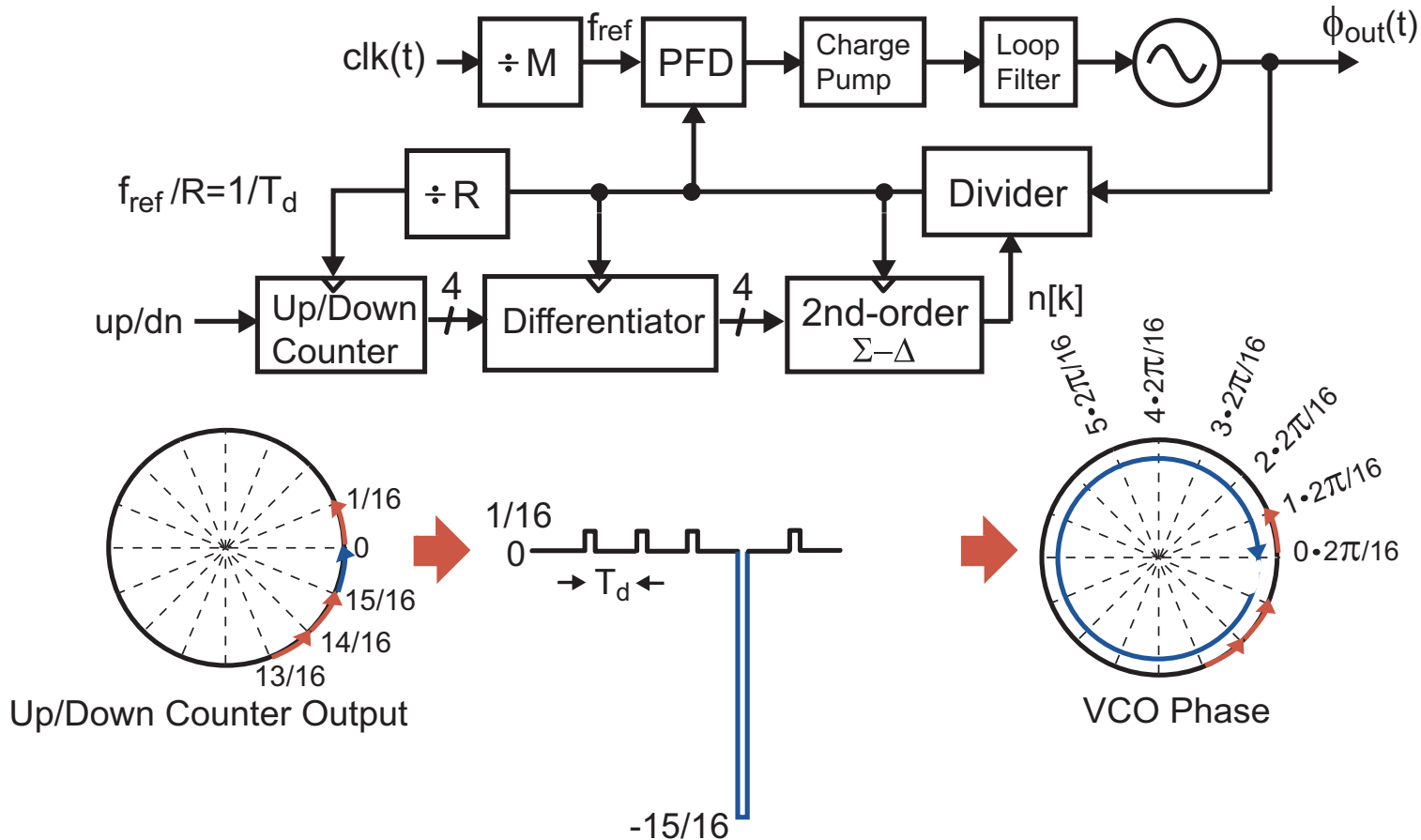
- VCO phase shifts according to Up/Down counter

Phase Shifter Guided by Up/Down Counter (cont'd)



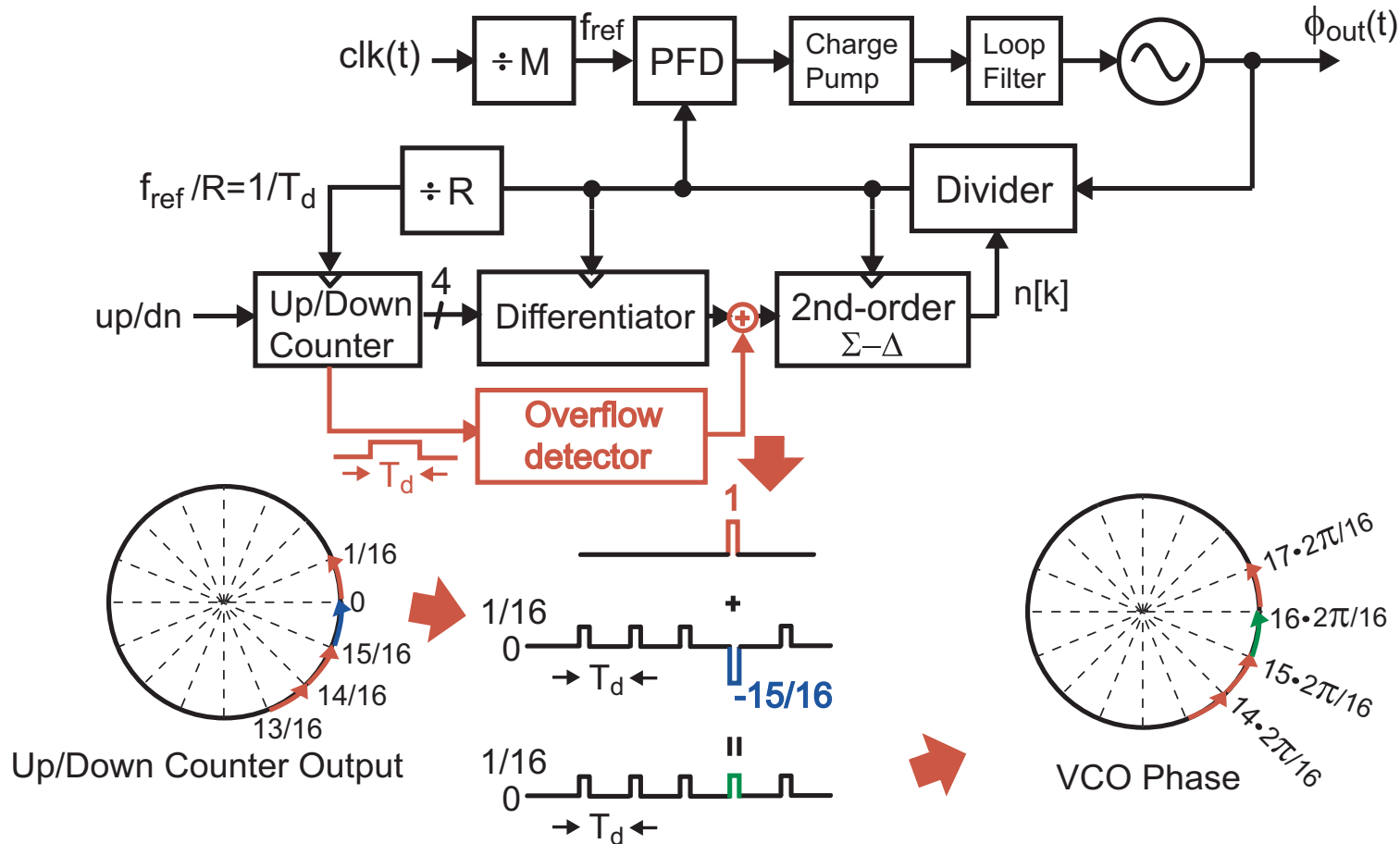
- Phase resolution improves by increasing number of bits in the hardware

Problem: Up/Down Counter Overflows



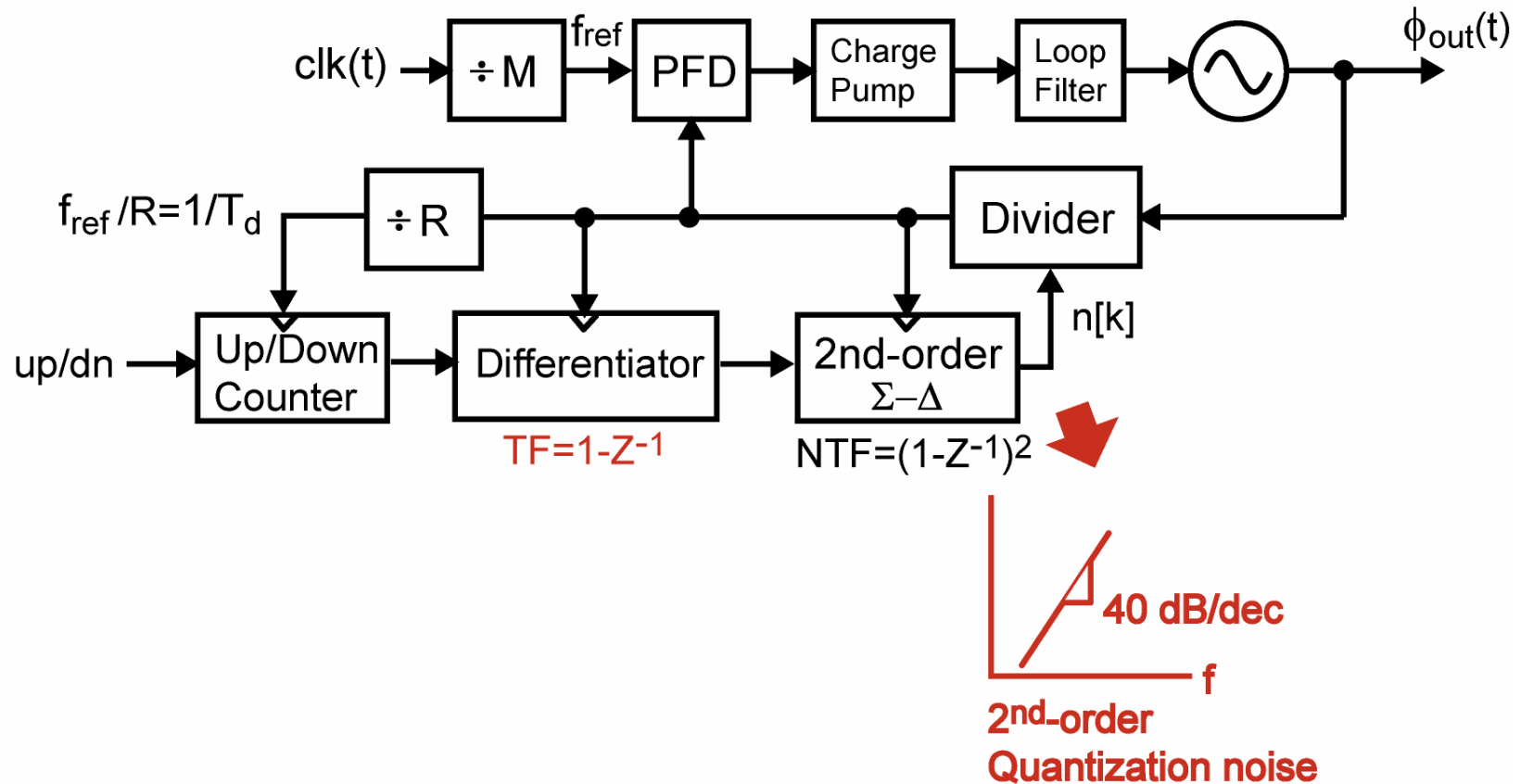
- Large negative pulse caused by overflow rotates VCO phase by a large step in the wrong direction
- Phase shifter provides a phase range of only 2π

Solution: Add Overflow Signal to Output



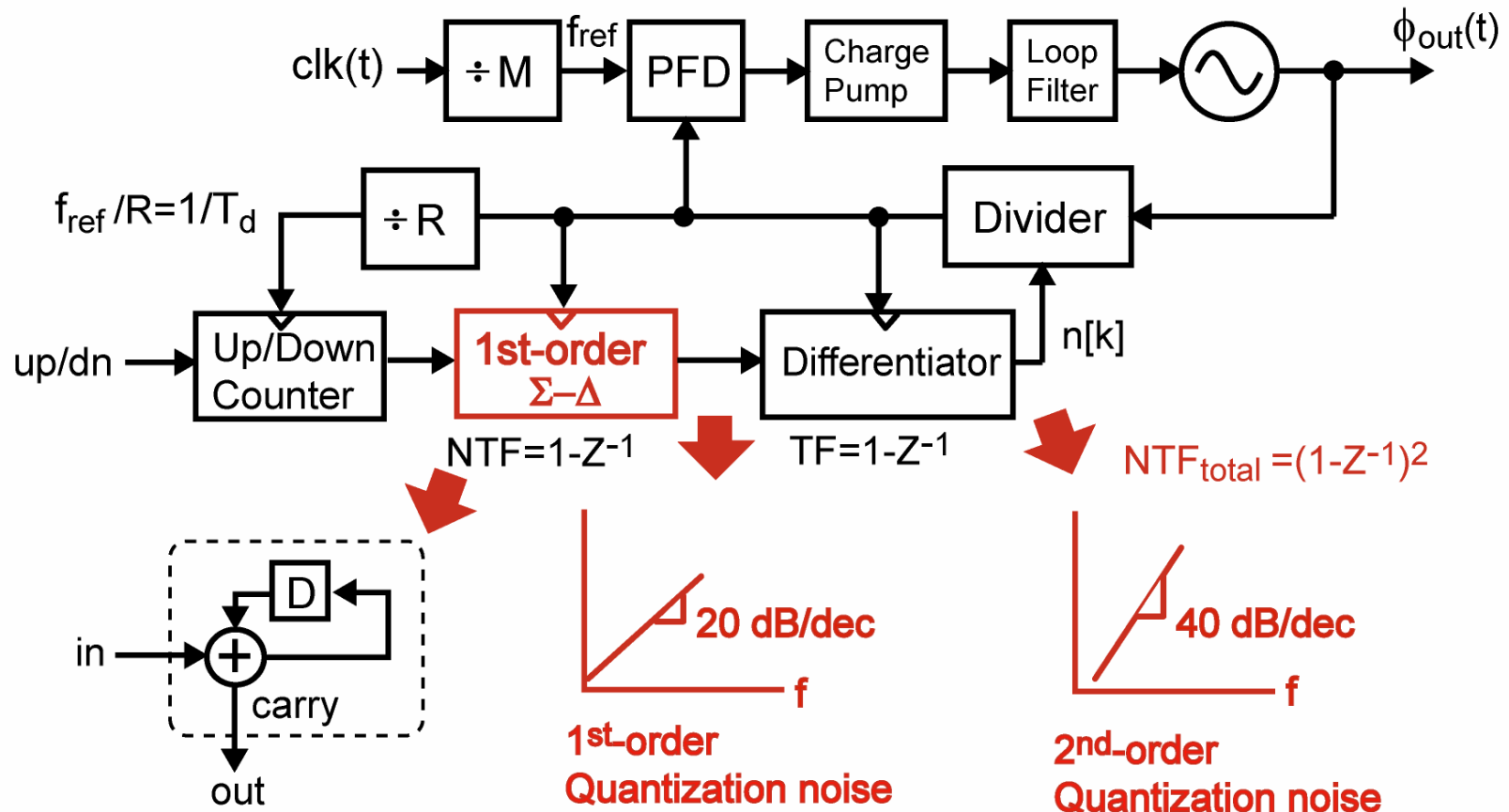
- Generate a +1 pulse to cancel the undesired -15/16 pulse
- Phase shifter provides an infinite phase range

Quantization Noise of Phase Shifter



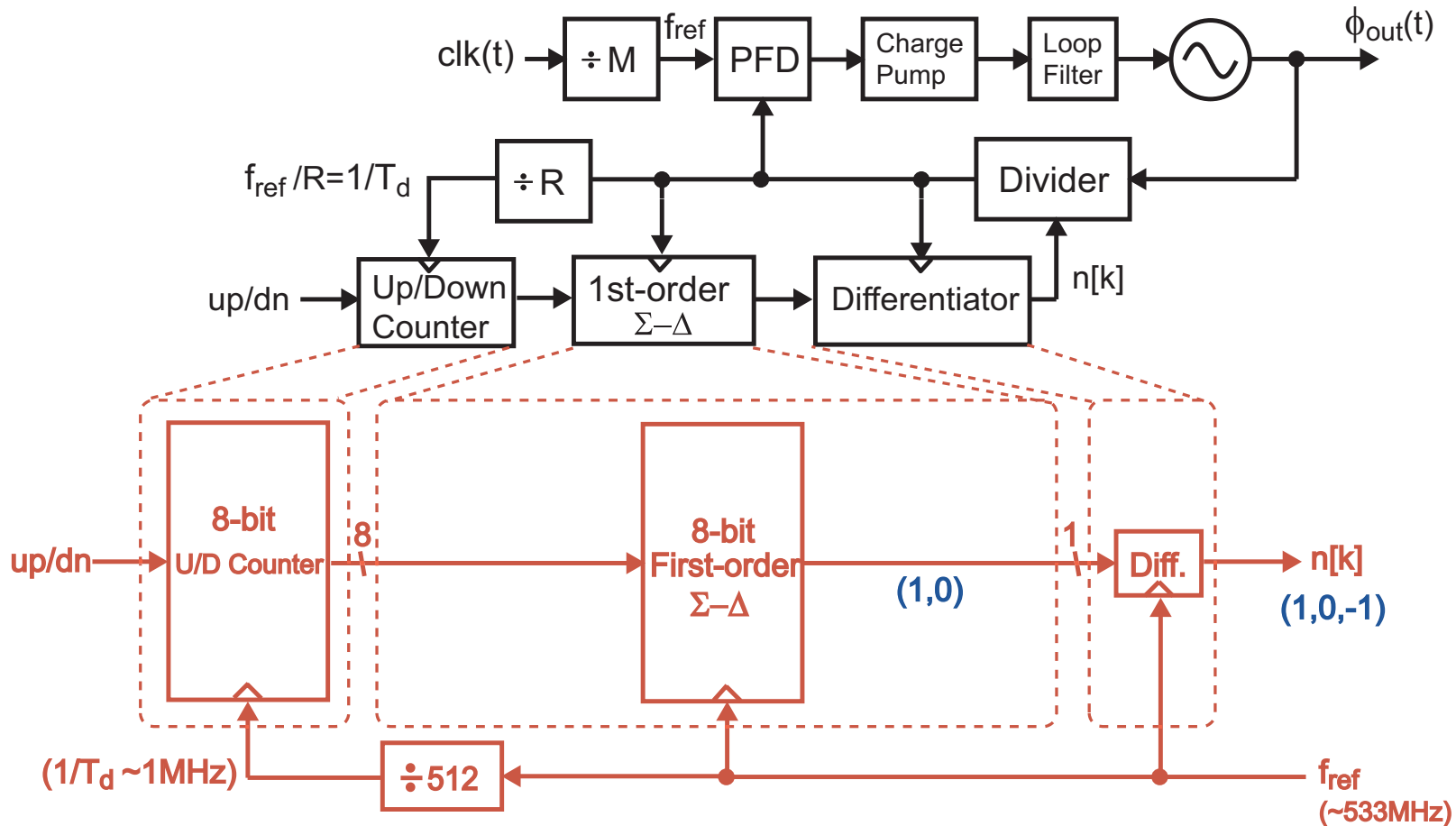
- Second-order quantization noise exists
- Transfer function of a differentiator is the same as noise transfer of a first-order $\Sigma-\Delta$ modulator

Quantization Noise of Phase Shifter (cont'd)



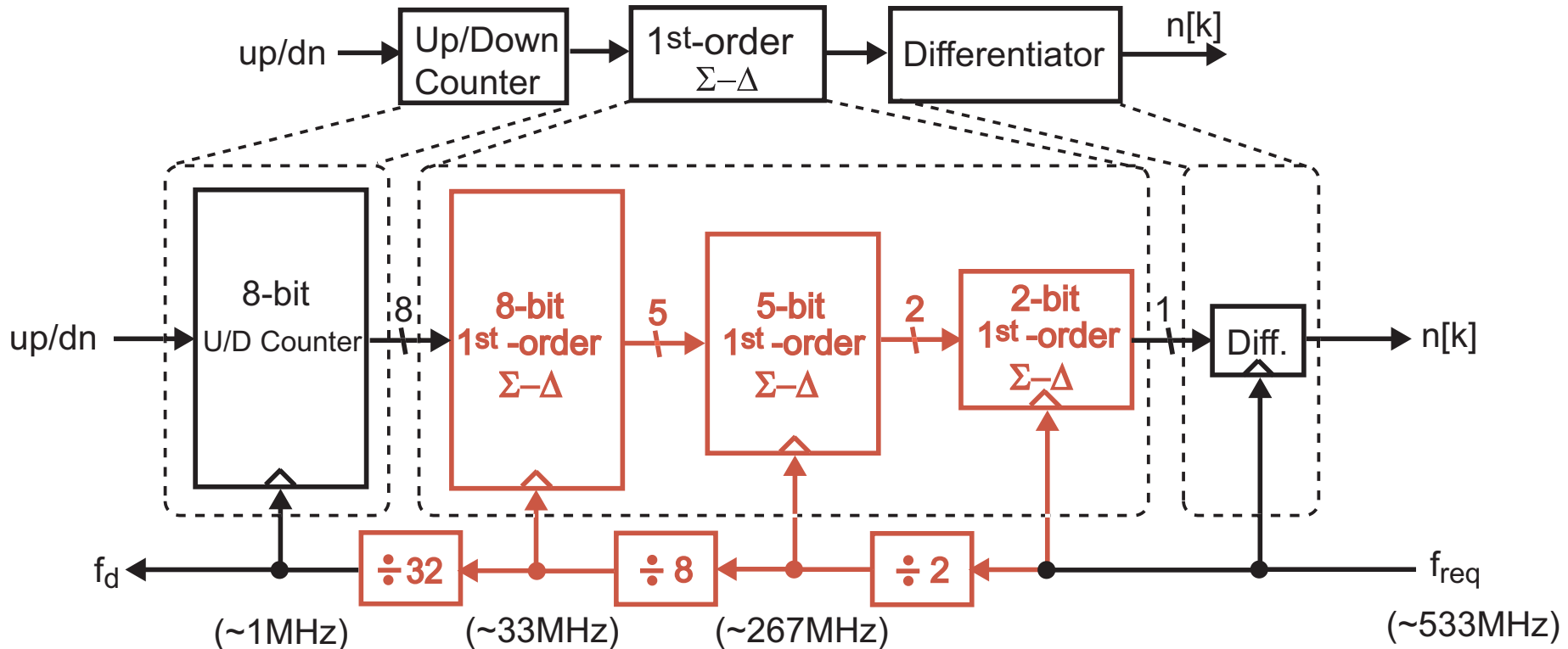
- Change the order of differentiator and modulator
- Same quantization noise obtained with a first-order $\Sigma-\Delta$ modulator → Less circuit complexity

Proposed Σ - Δ Modulator



- Output is three-value (1,0,-1)
- Divider with three division ratios (N-1, N, N+1) is necessary

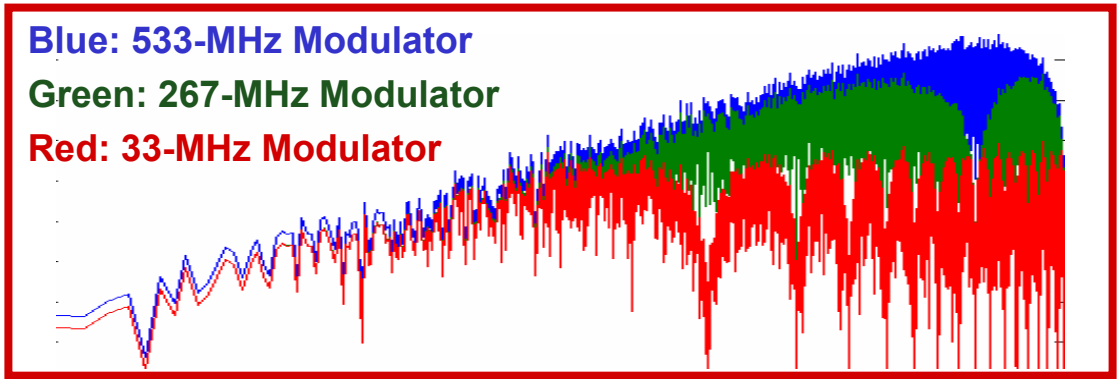
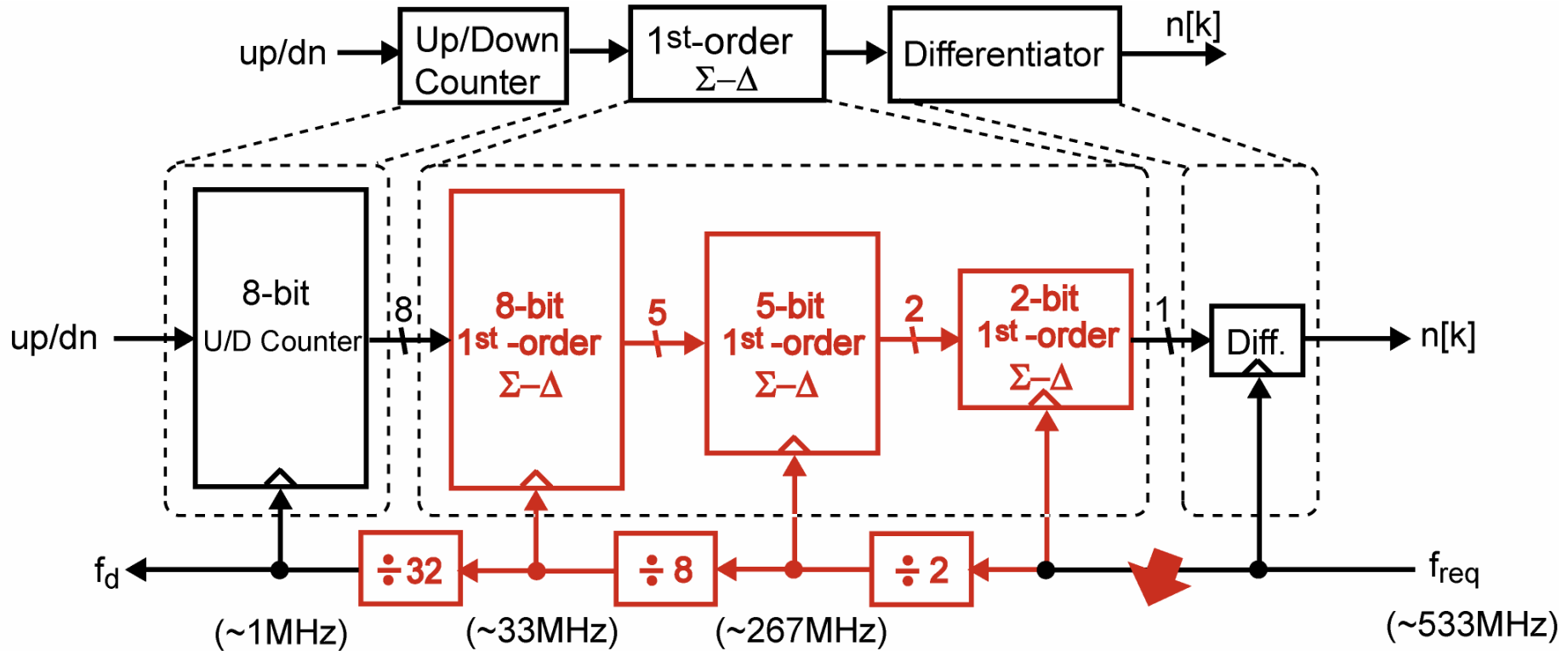
Proposed Σ - Δ Modulator (cont'd)



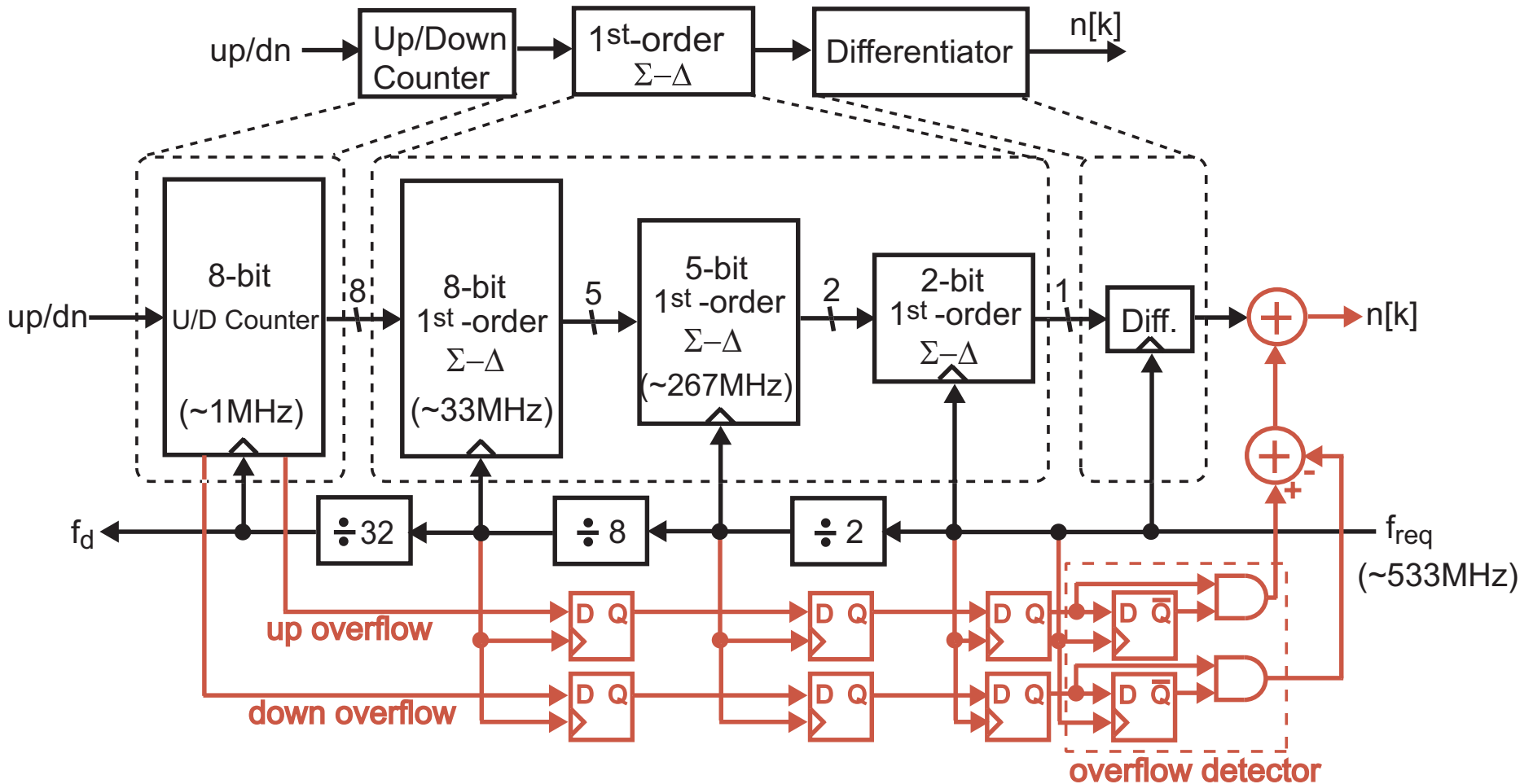
- **Multiple first-order Σ - Δ Modulators are used**
 - Bit number decreases as operating frequency increases
 - Metastability and synchronization problems are avoided

Easy Design and low power

Proposed Σ - Δ Modulator (cont'd)

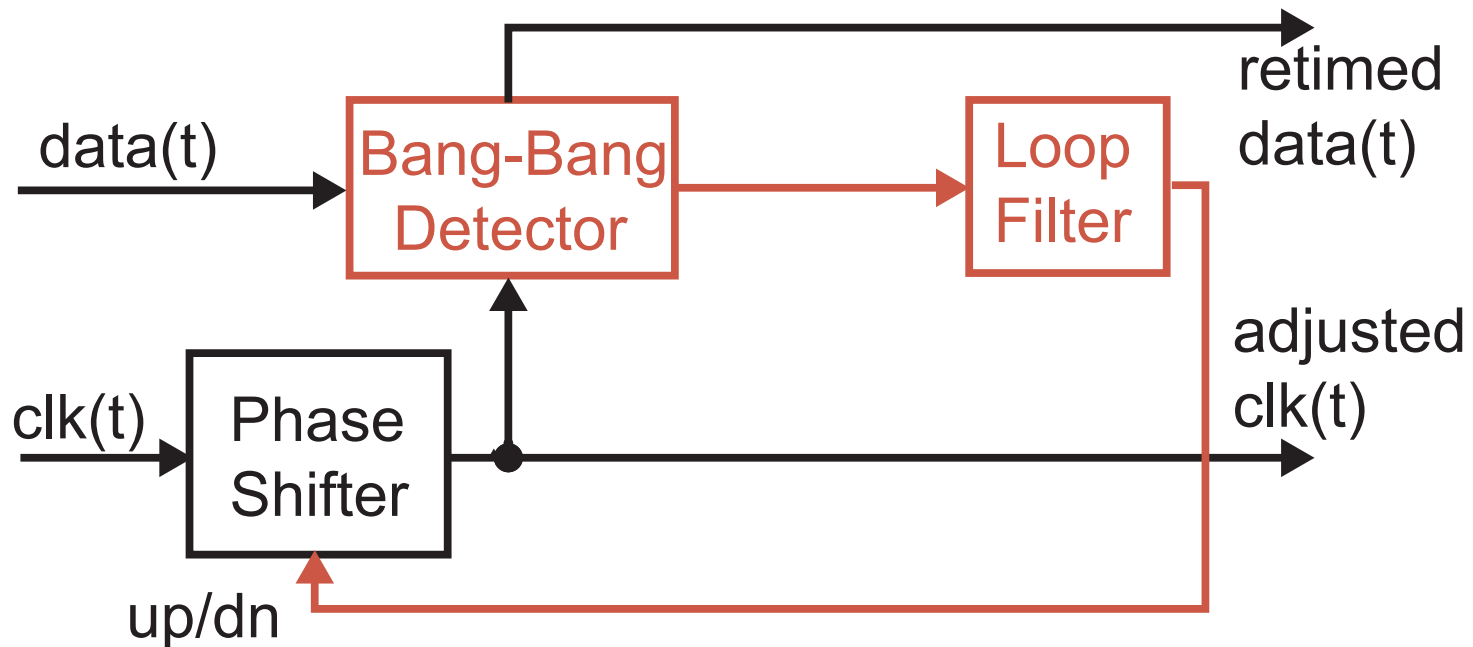


Proposed Σ - Δ Modulator (cont'd)



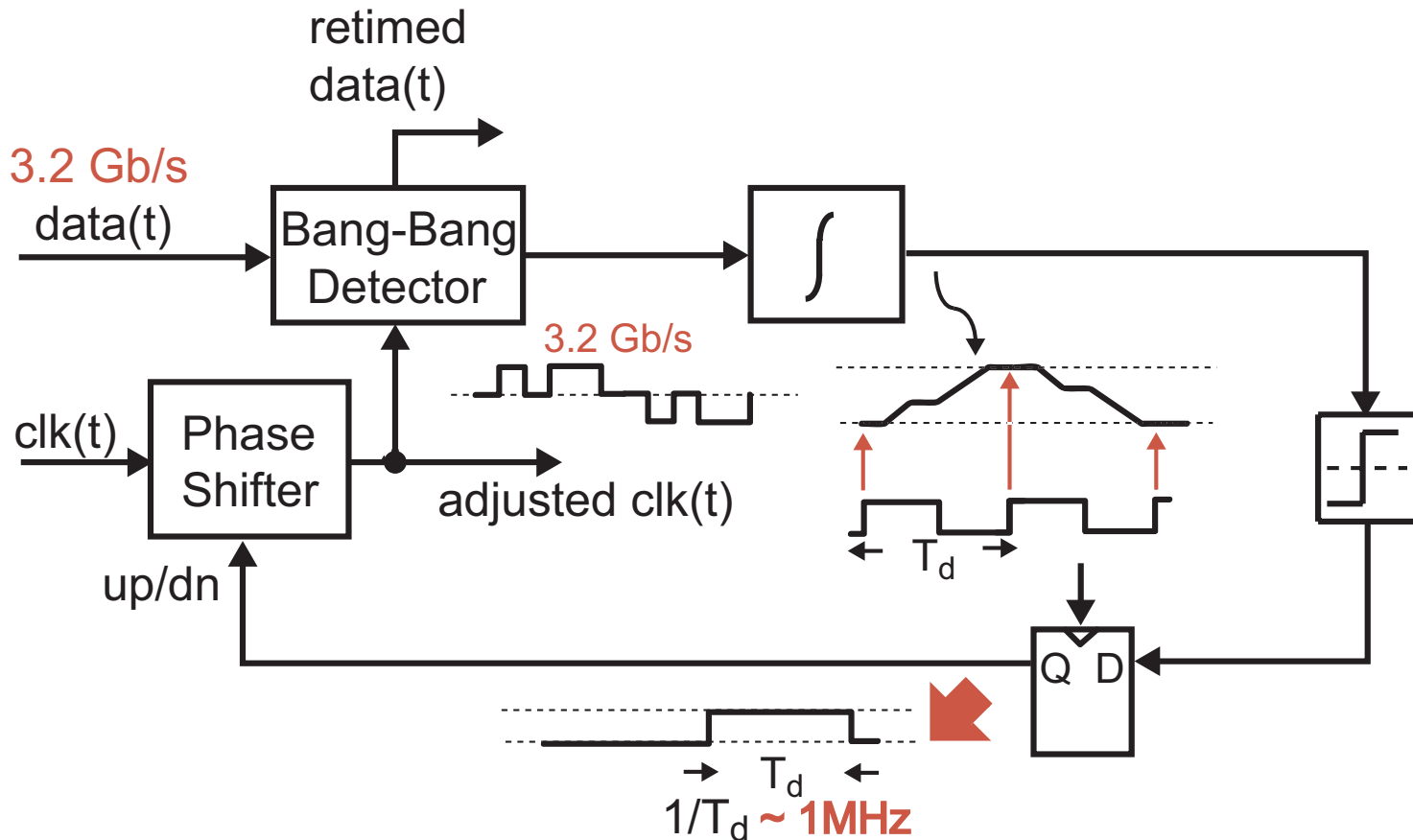
- **Overflow signals are realigned to main signals in each domain**
- **Output is still three-value even with the extra adder**

Proposed DLL



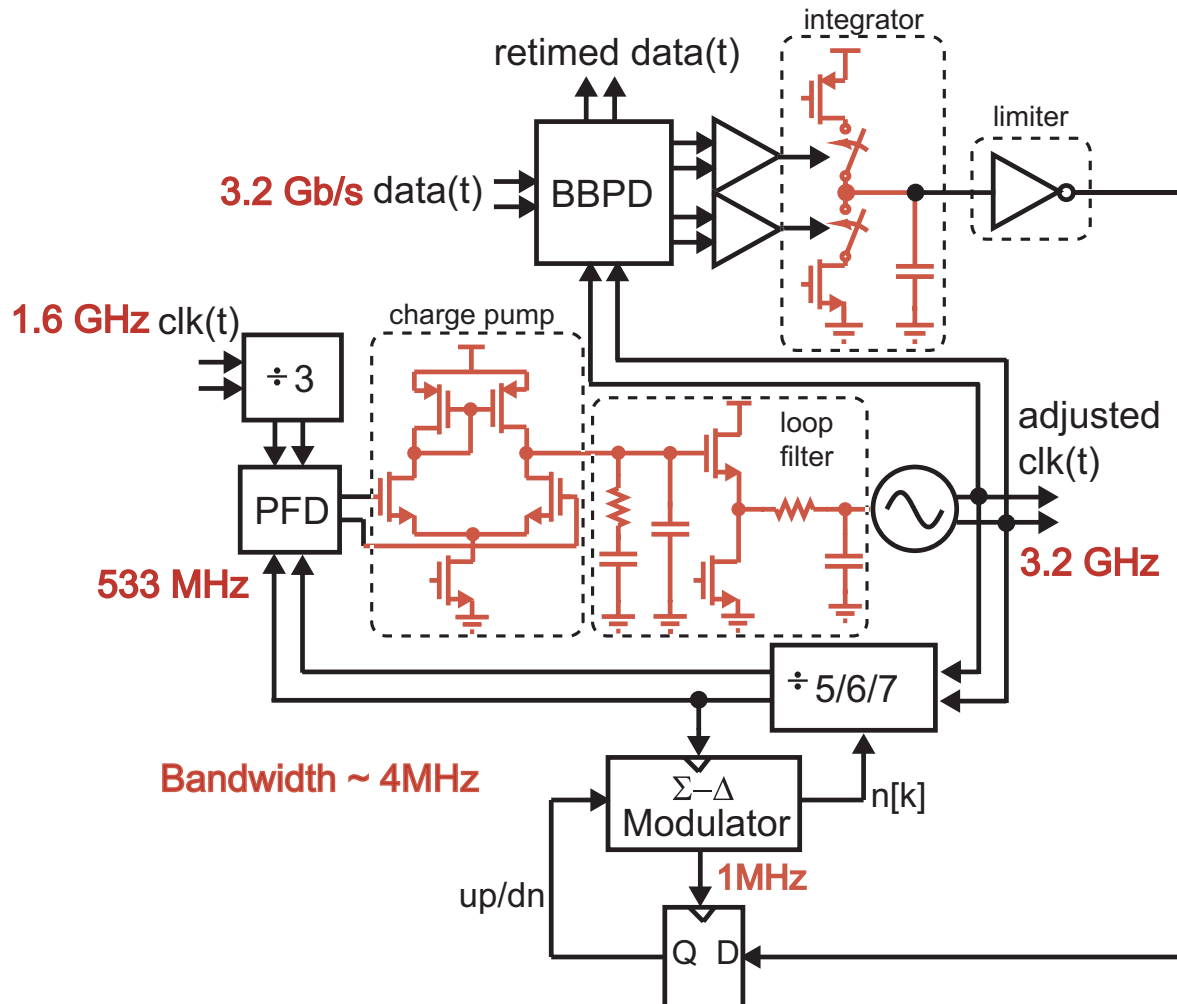
- Use Bang-Bang detector for phase comparison

Proposed Bang-Bang Architecture



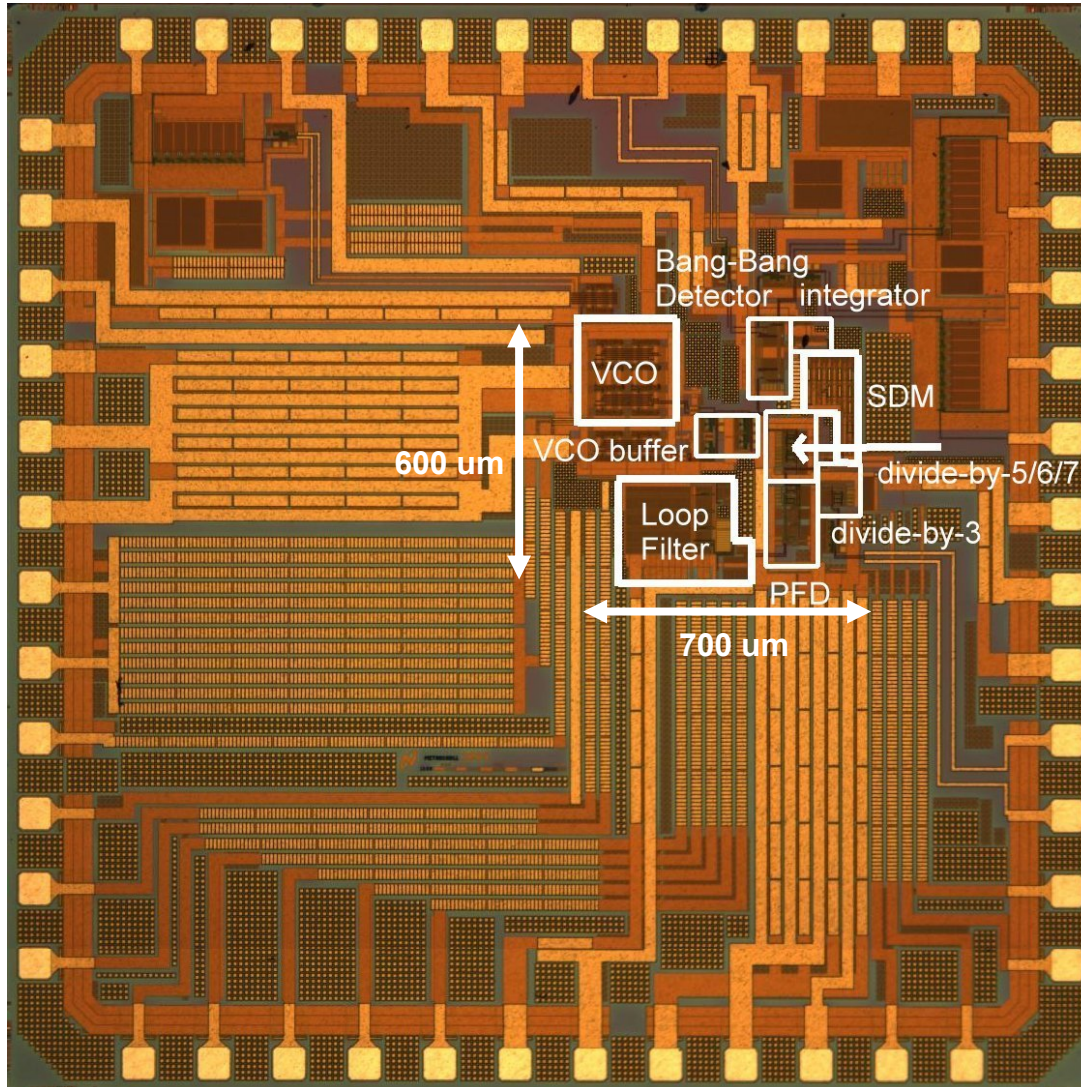
- An analog integrator, whose output is saturated to VDD or GND, is used to accumulate bang-bang detector output

DLL Prototype Chip for 3.2 Gb/s Communication



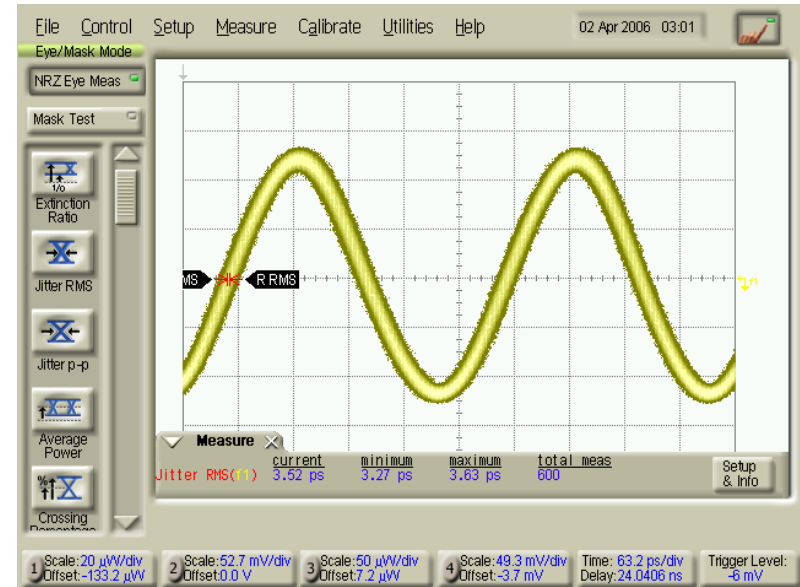
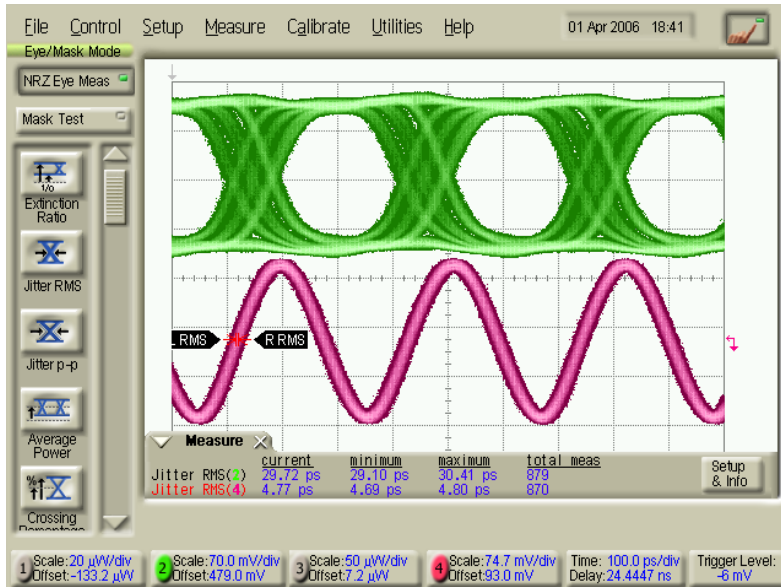
- 8-bit Σ - Δ modulator \rightarrow 1.4° phase resolution
- Simple analog components without need of good matching

Chip Microphotograph



- Implemented by 0.18μm CMOS Process
- Core Area: 600μm X 700 μm
- 1.8 V, 55 mA (excluding I/O buffer)

DLL Measured Jitter



- **Left: 3.2Gb/s PRBS 2³¹-1**
 - Single-ended clock jitter < 4.8ps
 - Single-ended data jitter < 30.5ps
- **Right: 3.2Gb/s PRBS 2³¹-1**
 - Differential clock Jitter < 3.7ps
- **BER < 10⁻¹²**

From Measurement

3.4 ps from thermal noise (mainly from VCO and pump)

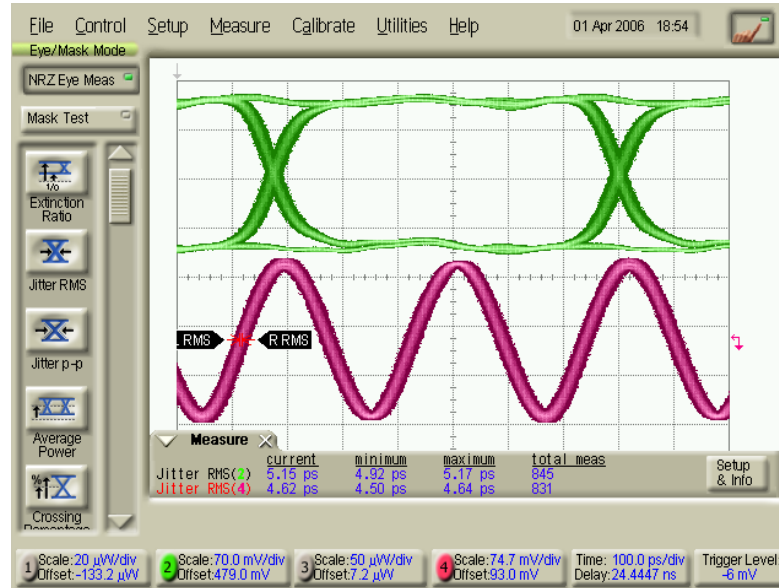
From Behavior Simulation

jitter due to bang-bang detector and $\Sigma-\Delta$ modulator is on the same order as the thermal noise

Remaining Jitter

probably from output buffer

Non-ISI-limited DLL Jitter



- 1.6Gb/s PRBS 2⁷-1
 - Single-ended clock Jitter < 4.7ps
 - Single-ended data jitter < 5.2ps
- BER < 10⁻¹²

Conclusion

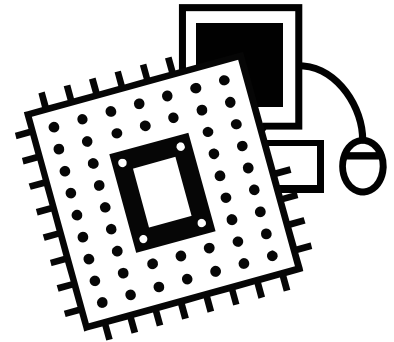
- A DLL architecture is proposed
 - Σ - Δ synthesizer is used as the phase shifter
 - A compact and low-power Σ - Δ modulator
 - Simple Bang-bang detector is used for phase detection
- Prototype is implemented for 3.2 Gb/s chip-to-chip communication
- The DLL provides a digitally-controlled phase adjustment with fine-resolution and infinite-range that is not sensitive to PVT variations
- The overall architecture is insensitive to mismatch
 - Well suited for more advanced CMOS processes with high variability

Low Jitter, Highly Digital, MDLL-based Clock Multiplier

**Belal M. Helal, Matthew Z. Straayer,
Gu-Yeon Wei* and Michael H. Perrott**

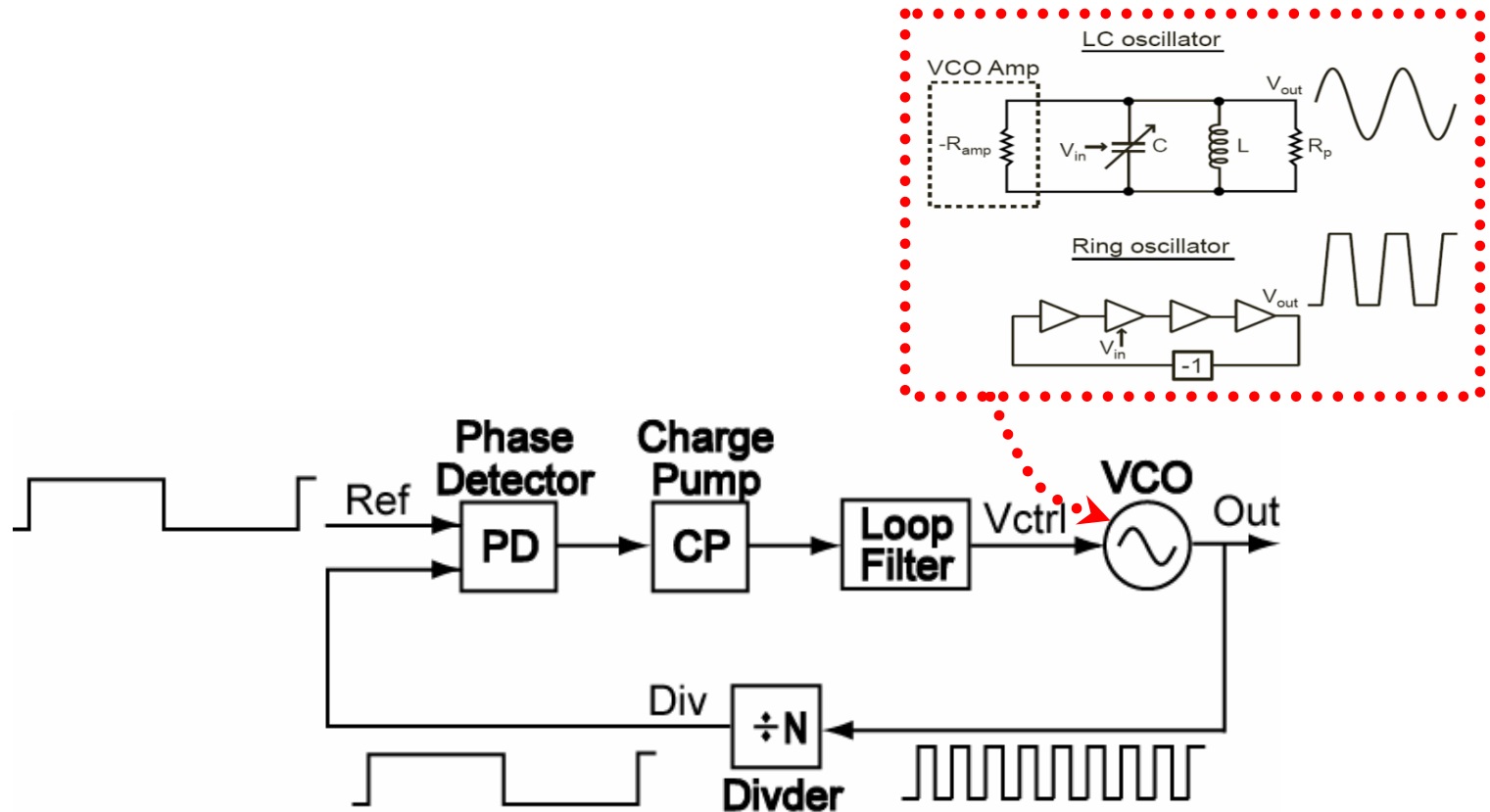
Motivation

- **Issue:** Clock multiplication using phase-locked loops complicates the design of digital chips.
- **Goal:** Achieve a highly digital clock multiplier that can be easily ported across different CMOS processes.
 - Do not compromise on jitter performance



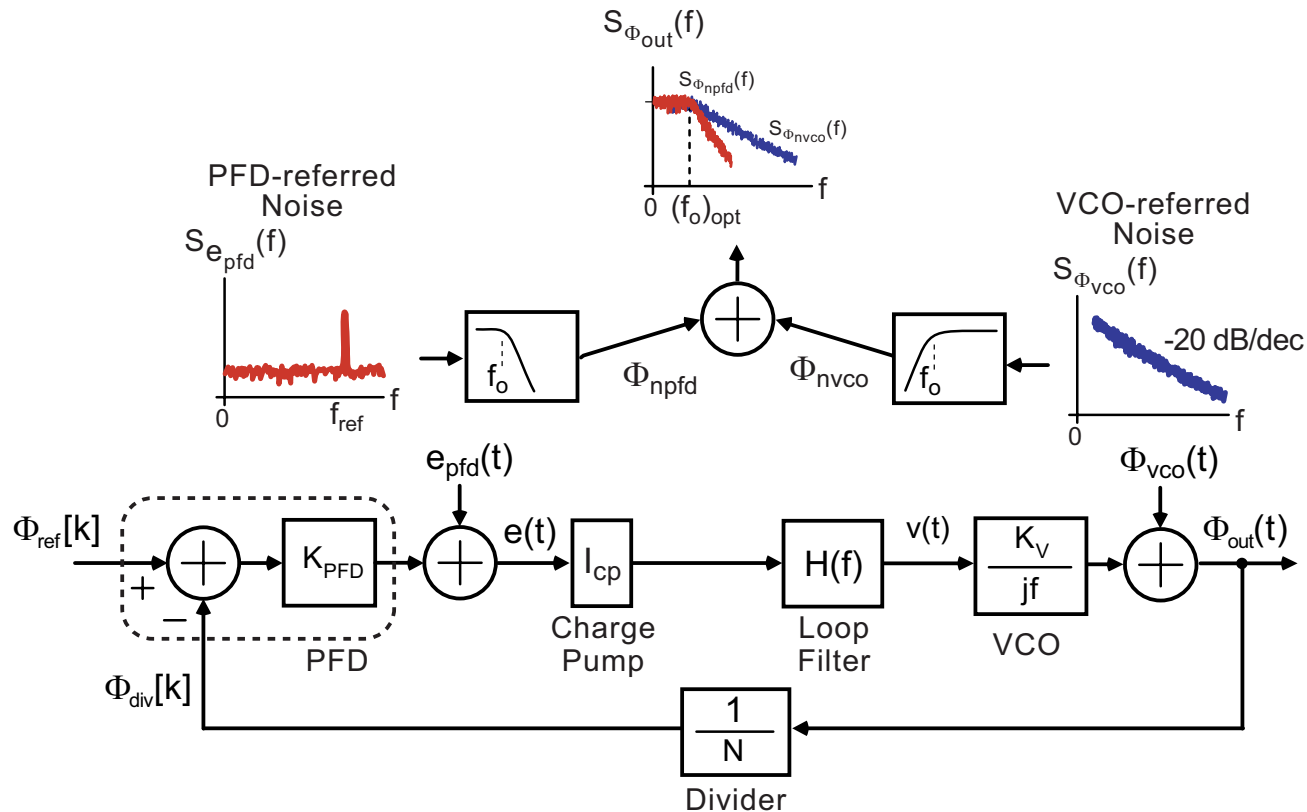
We will present a non-PLL based clock multipliers that achieves sub-ps jitter performance

PLL: Typical Architecture for Clock Multiplication



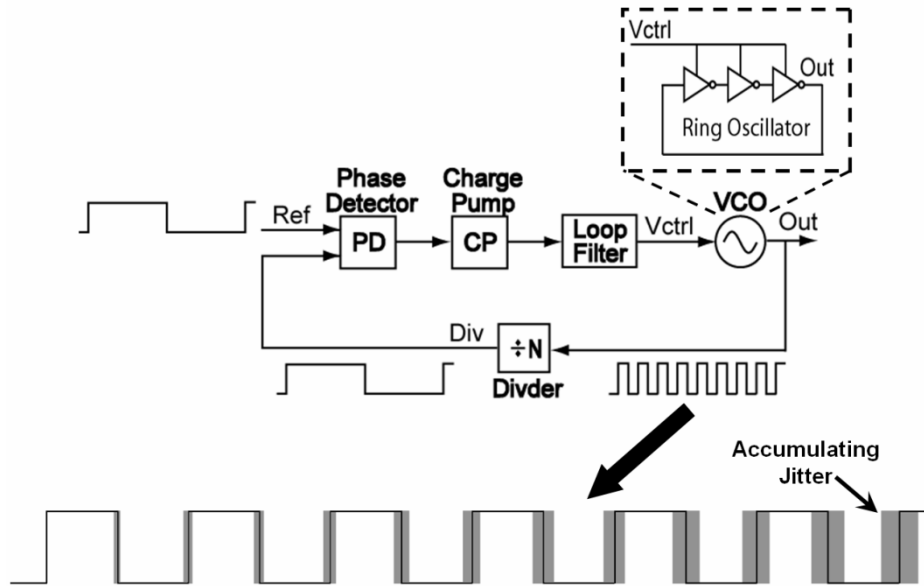
- Application determines VCO type
 - Lowest noise → LC oscillator
 - Smallest area → Ring oscillator
- How to reject the high phase noise of a ring oscillator?

Rejection of High Phase Noise in Ring Oscillators

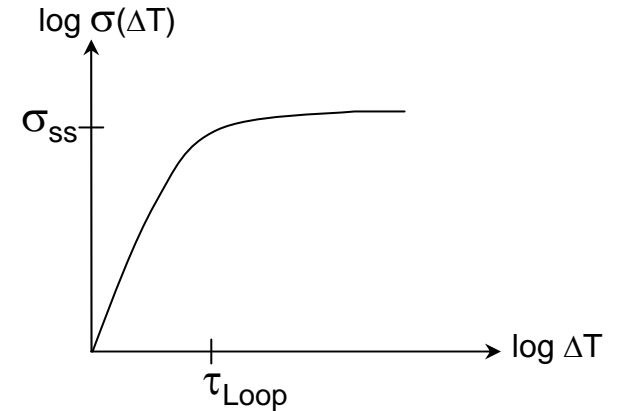


- **Phase noise contributors: VCO and PFD noise**
 - Affected differently by PLL bandwidth, f_0
- **VCO noise: high-pass filtered PFD noise: low-pass filtered**
 - Tradeoff: bandwidth $\uparrow \rightarrow$ VCO noise \downarrow , PFD noise \uparrow
- **Can we suppress VCO noise without large bandwidth?**

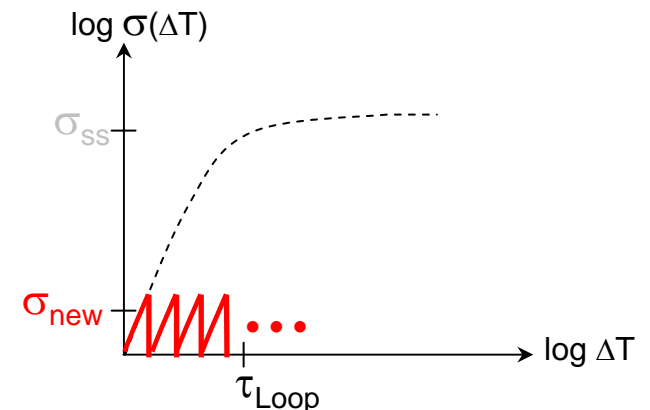
Time Domain View: Reducing VCO Jitter



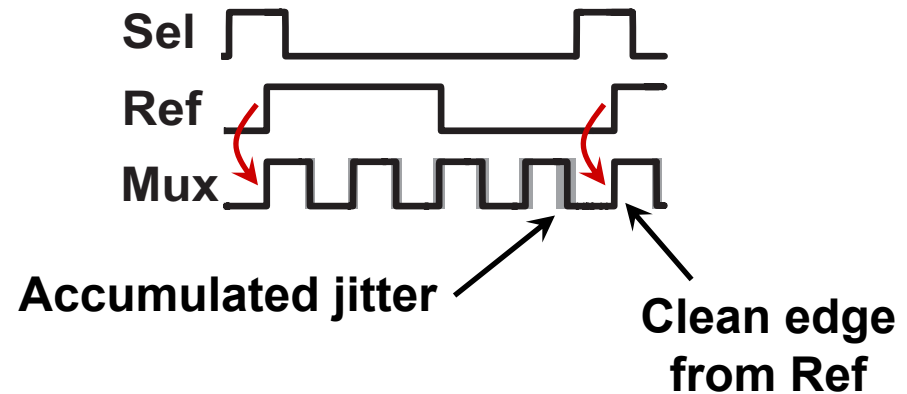
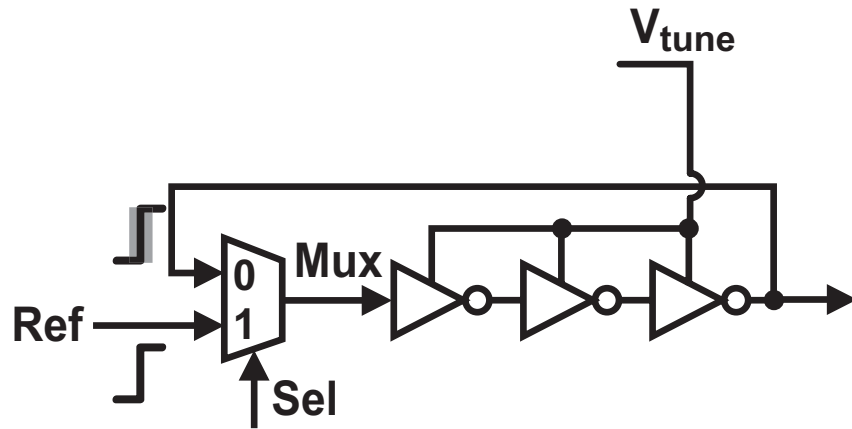
McNeill, *JSSC*,
June 1997



- **Problem: Jitter accumulates with time according to loop dynamics to a steady state level, σ_{ss}**
- **Solution: reset jitter at a rate faster than the loop BW**
 - How?



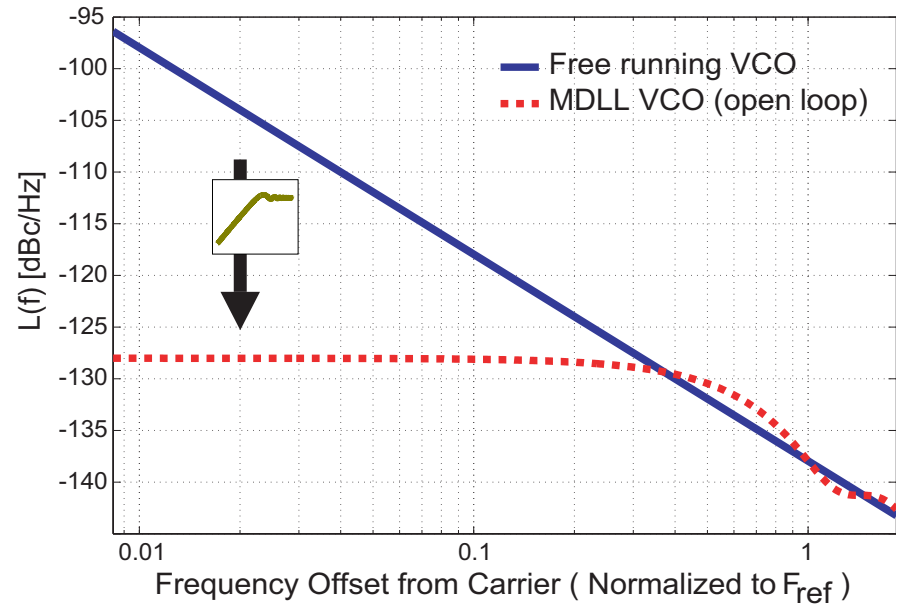
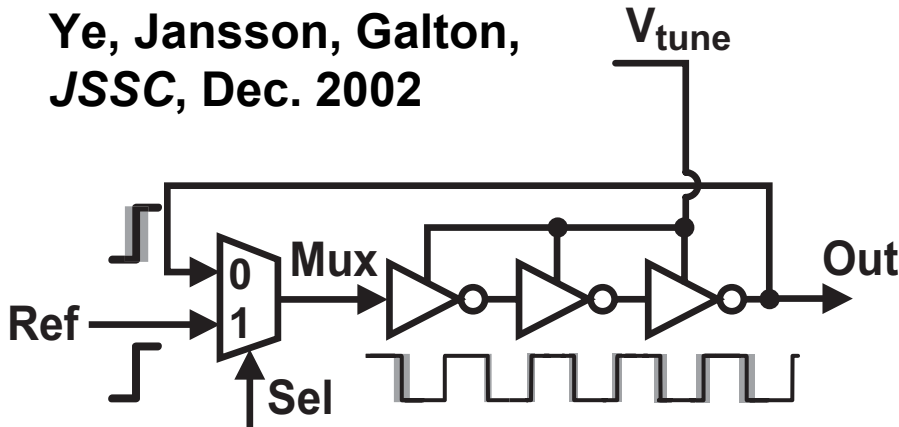
Multiplying DLL Concept



- **Goal: Create a higher frequency clock from an input reference signal**
- **Replace jittery edge with clean Reference edge**
 - Accumulated jitter is periodically removed

The Benefit of the MDLL Approach

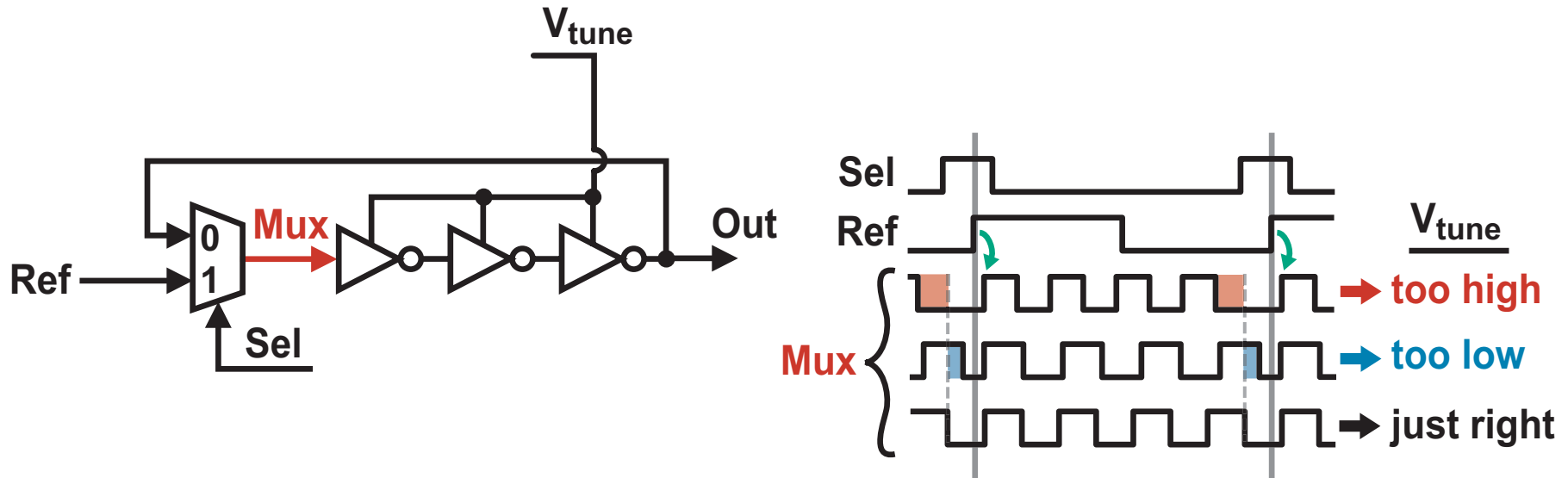
Ye, Jansson, Galton,
JSSC, Dec. 2002



- Phase noise of ring oscillator is suppressed by the periodic multiplexing of reference edge
- Transfer function approximates a 1st order high pass filter
 - $f_{hpf} \approx f_{Ref} / 4$

High bandwidth suppression of phase noise
independent of loop bandwidth

Deterministic Jitter in MDLLs



- Key issue: Need to precisely tune ring oscillator frequency
- Offset in frequency results in inconsistent period
→ deterministic jitter

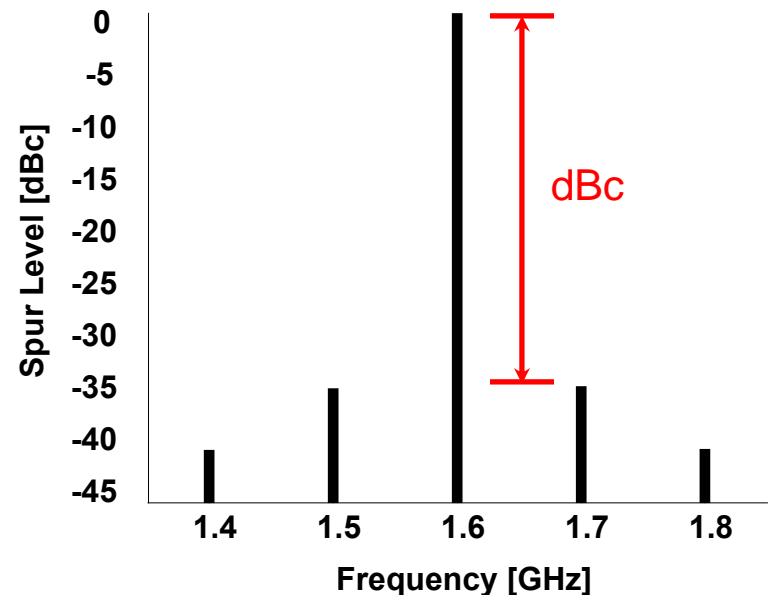
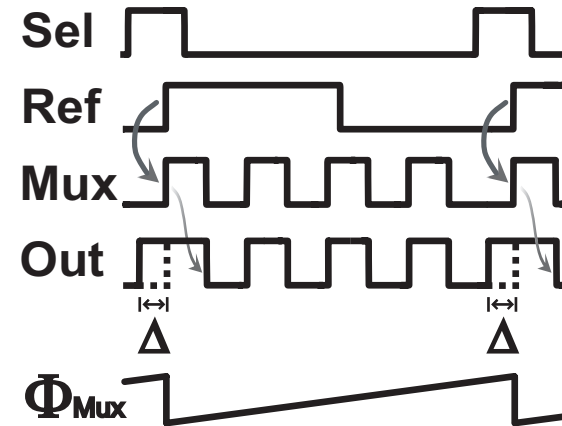
Goal: Reduce deterministic jitter to the level of random jitter

Deterministic Jitter Observed in Output Spectrum

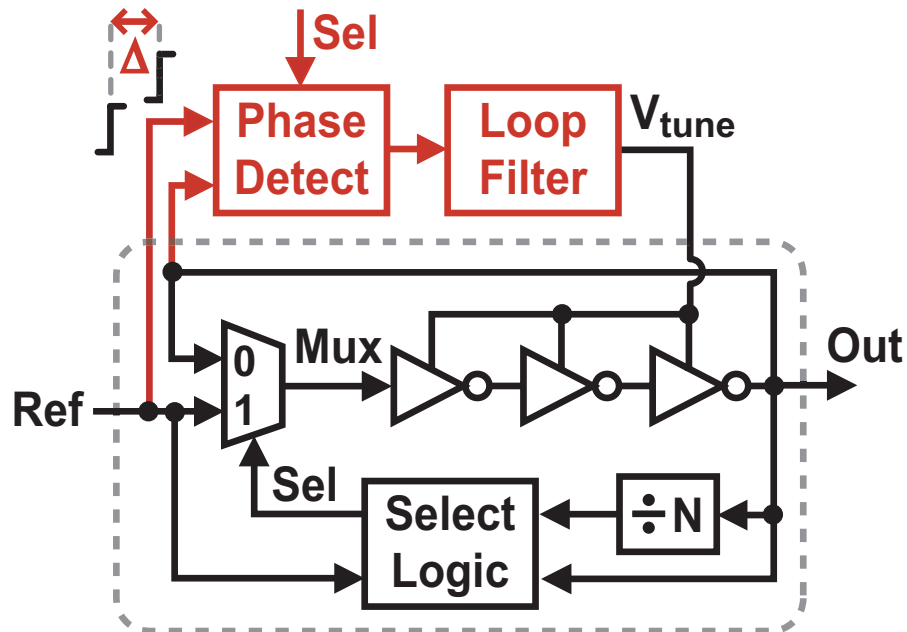
- Deterministic jitter shows up as reference spurs
- Relationship by Fourier analysis

$$\Delta \approx T_{out} \times 10^{Spur(dBc)/20}$$

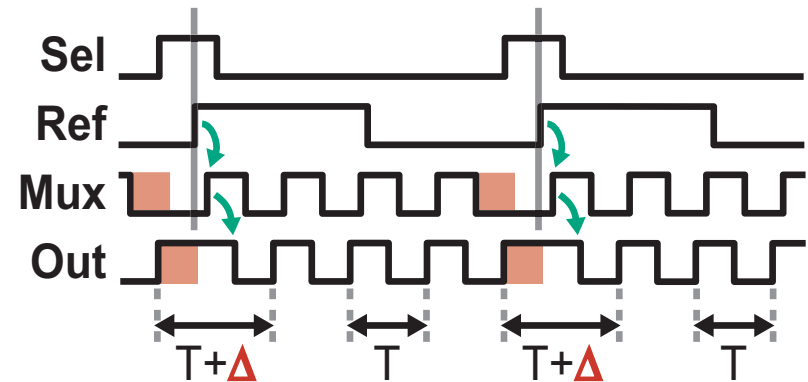
Deterministic Jitter can be estimated from reference spurs



Classical Analog Approach



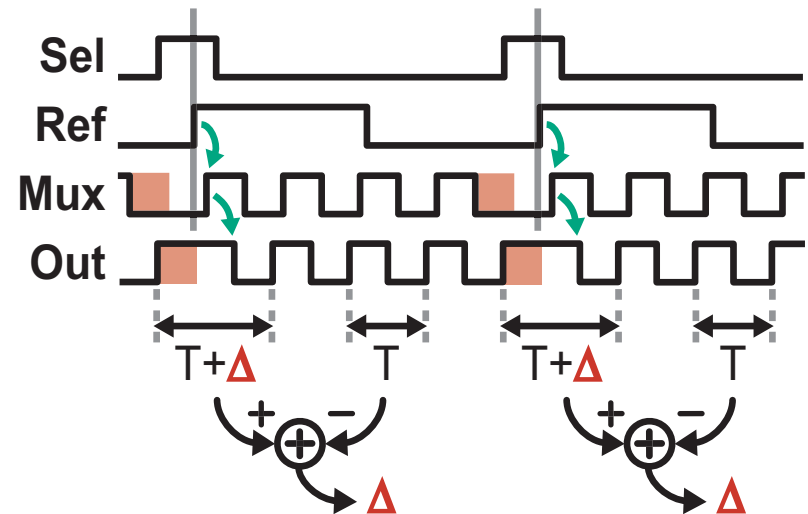
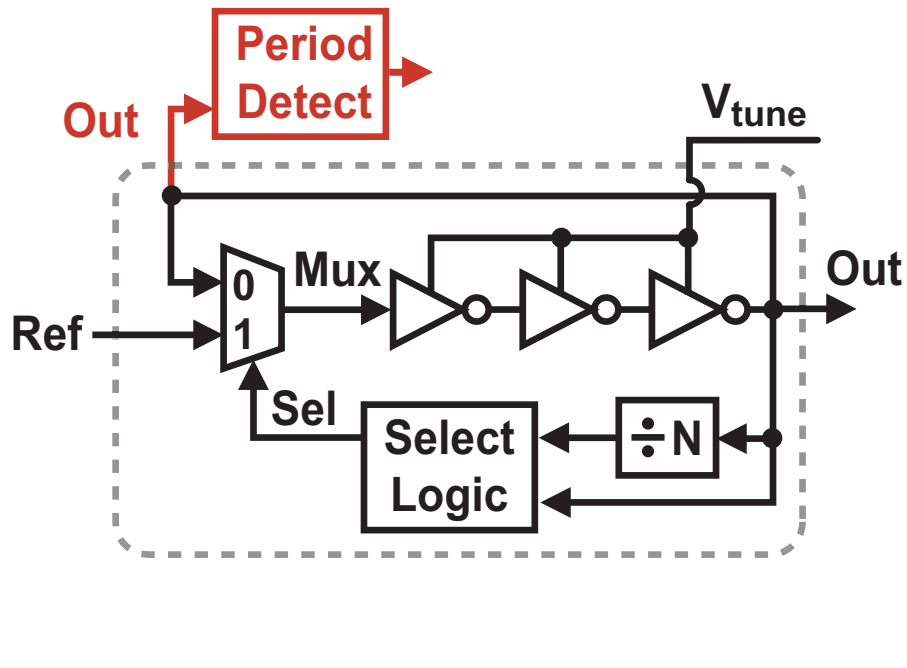
Farjad-Rad et. al., *JSSC*, Dec. 2002.



- **Key idea: Compare edges of MDLL output and reference to detect error (Δ)**
 - Integrate error to adjust V_{tune}
- **The problem: Mismatches and offsets in the phase detector and integrator limit reduction of Δ**

Low deterministic jitter is challenging to achieve

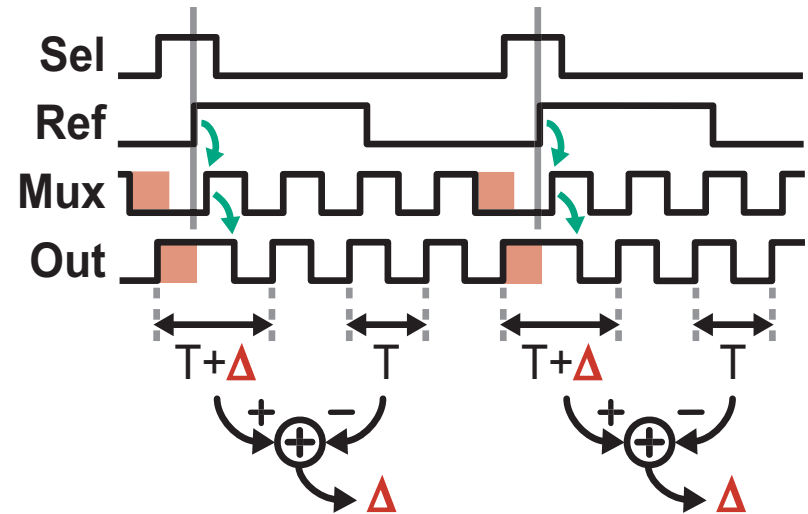
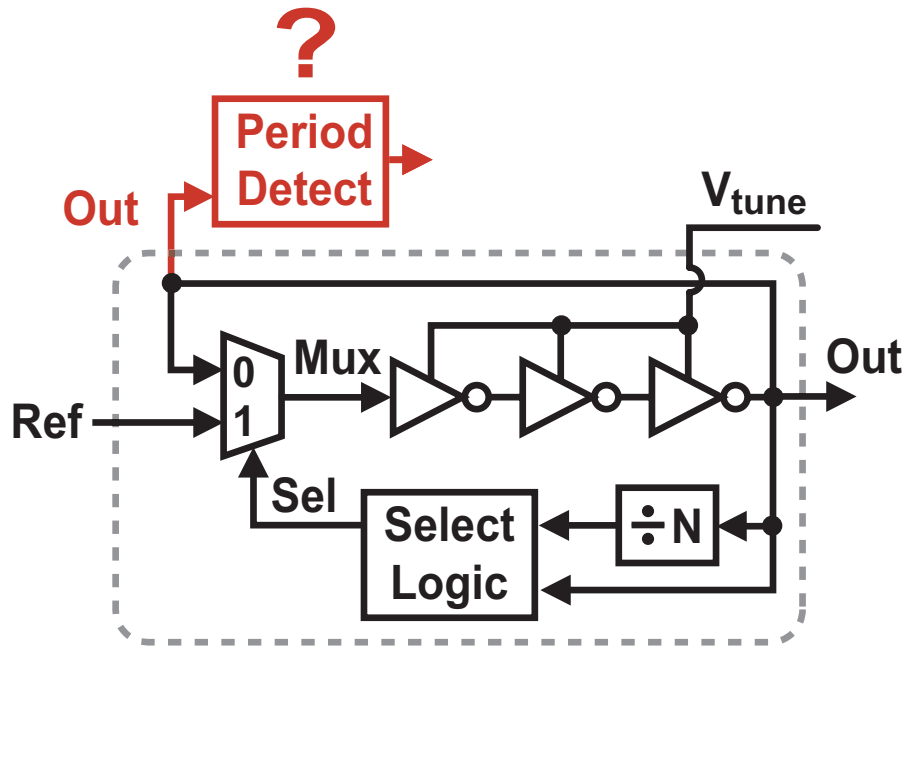
Proposed Detection Approach



- Compare cycle periods of MDLL output
- Infer error (Δ) from difference between cycle periods of the MDLL output

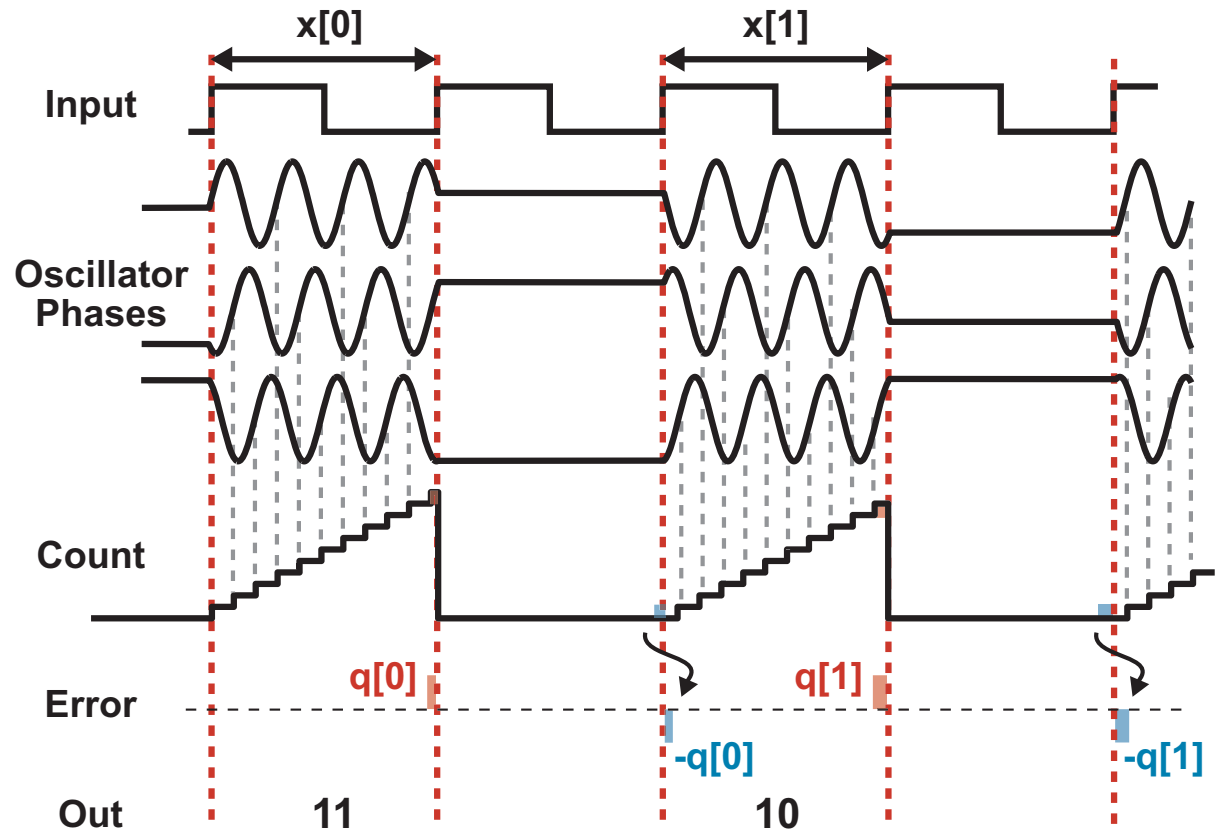
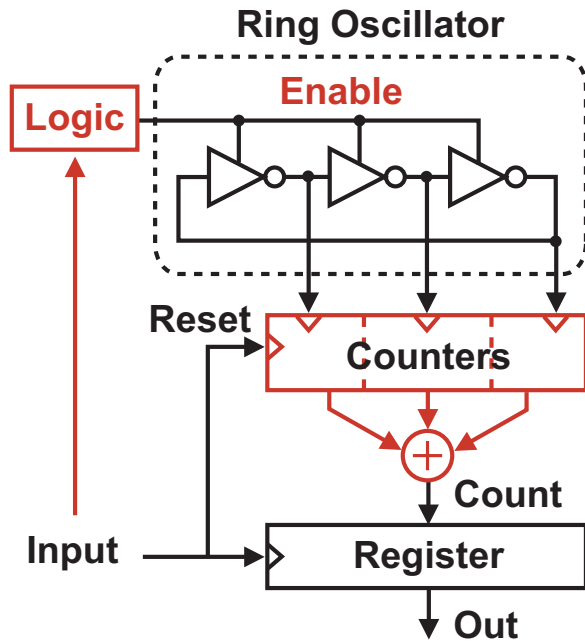
Comparison of same signal eliminates path mismatch

Detection of the Output Period



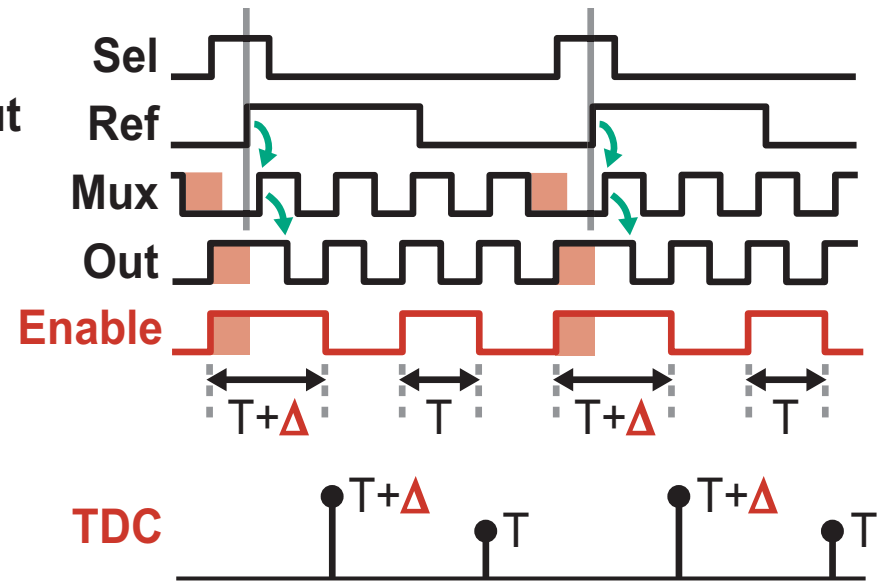
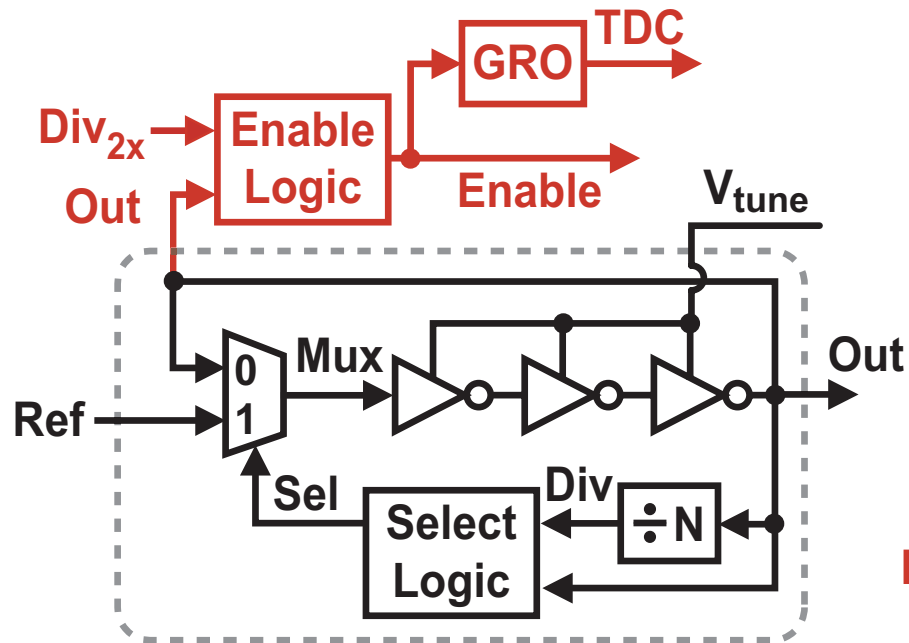
- **Need an accurate period detector**
 - Error removal is limited by the effective resolution of the detector
- **A digital detector has many advantages**
 - Time-to-digital converter (TDC)

Scrambling TDC (developed by Matt Straayer)



- Gated Ring Oscillator (GRO) is ON during the measured period
- Raw resolution is one inverter delay
- Quantization noise is scrambled (and first order noise shaped)
- Effective resolution improved by averaging

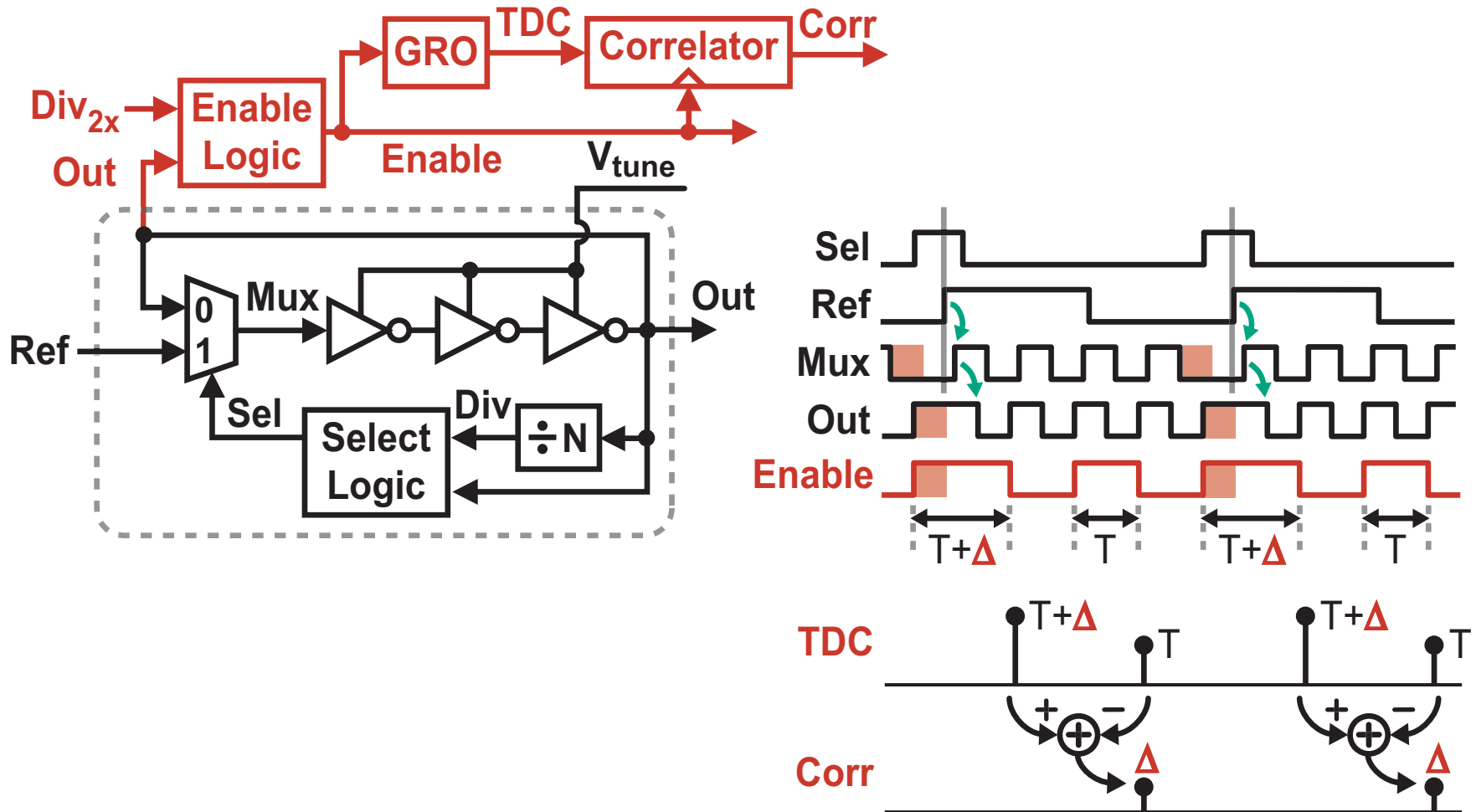
Using the GRO in the proposed MDLL Architecture



- Div_{2x} selects two output periods per reference cycle
- Sub-picosecond effective resolution is possible
 - $T_{gro} = 50 \text{ ps}$, $F_s = 100 \text{ MHz}$, $BW = 10 \text{ KHz} \rightarrow \text{Eff. Res.} \approx 0.7 \text{ ps}$

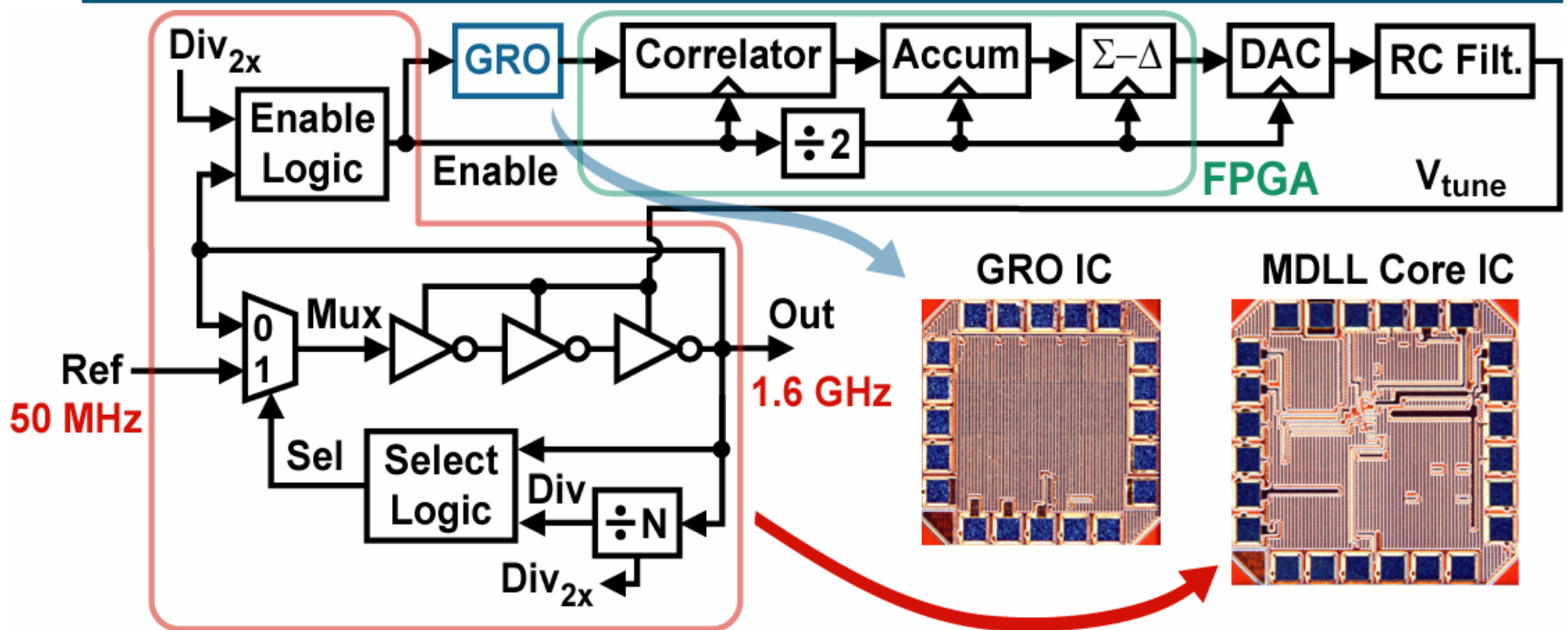
GRO Detects the Output Period Accurately

Digital Correlator Extracts the Error



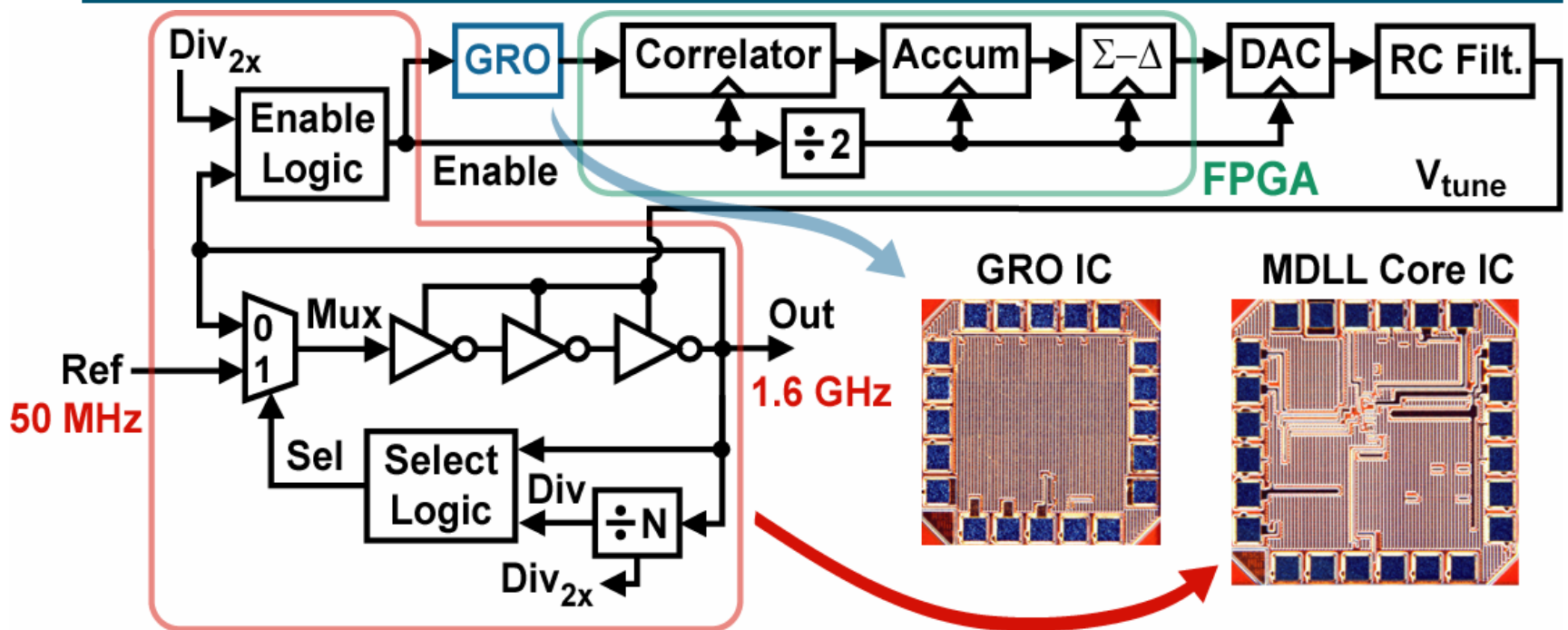
- Digital version of correlated double-sampling technique

MDLL Prototype



- Two custom 0.13 μm CMOS ICs
 - GRO (Matt Straayer) and core MDLL structures
- FPGA
 - Digital Correlator, Accumulator and digital $\Sigma\Delta$ -modulator
- Discrete 16-bit DAC and RC lowpass filter (3 MHz pole)
 - DAC using 8 effective bits (by using the $\Sigma\Delta$ -modulator)

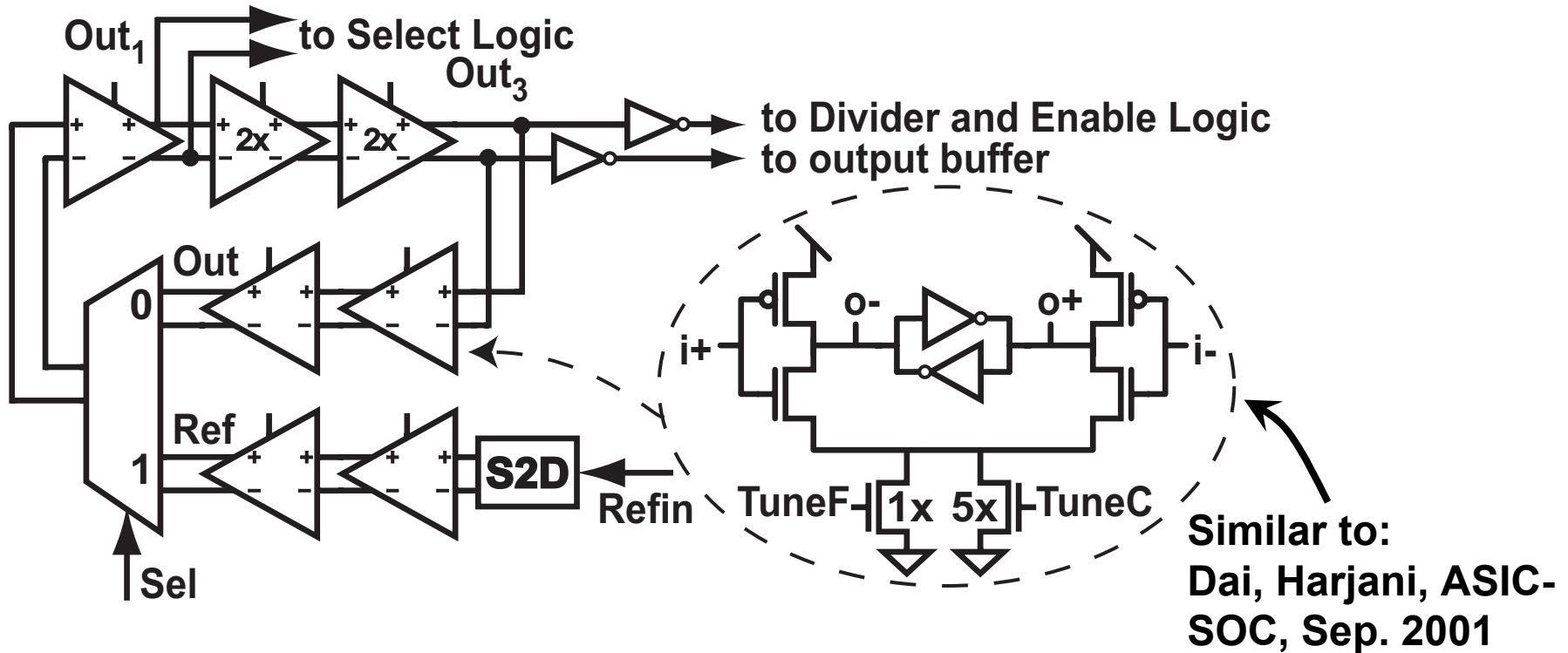
Power Consumption and Area



- **Core MDLL**
 - Area: 0.04 mm²
 - Power: 3.9 mW
- **GRO-based TDC**
 - Area: 0.02 mm²
 - Power: 1.2 mW

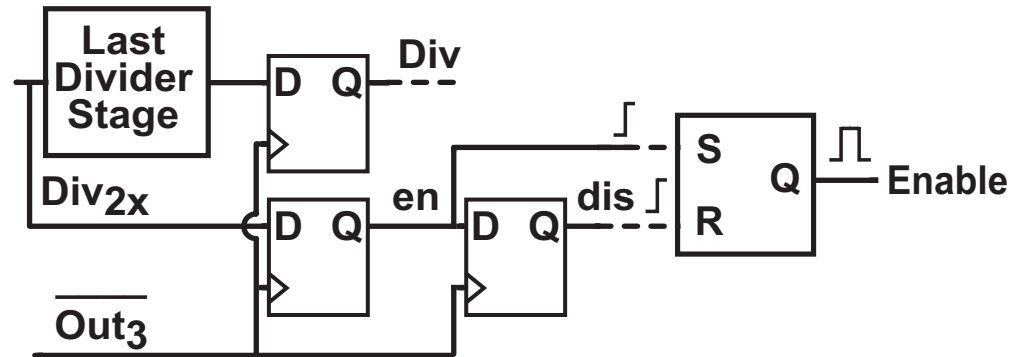
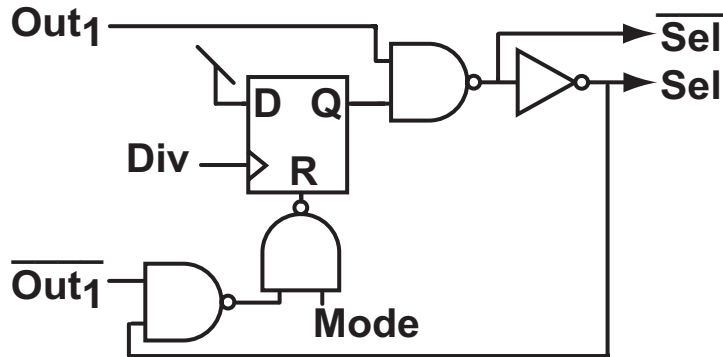
Circuit Details

Multiplexed Ring Oscillator



- **Balanced differential loading**
→ Better PSRR and 1/f noise
- **Five delay stages, no external connections to multiplexer**
→ Faster edges → better multiplexing

Select Logic and Enable Logic



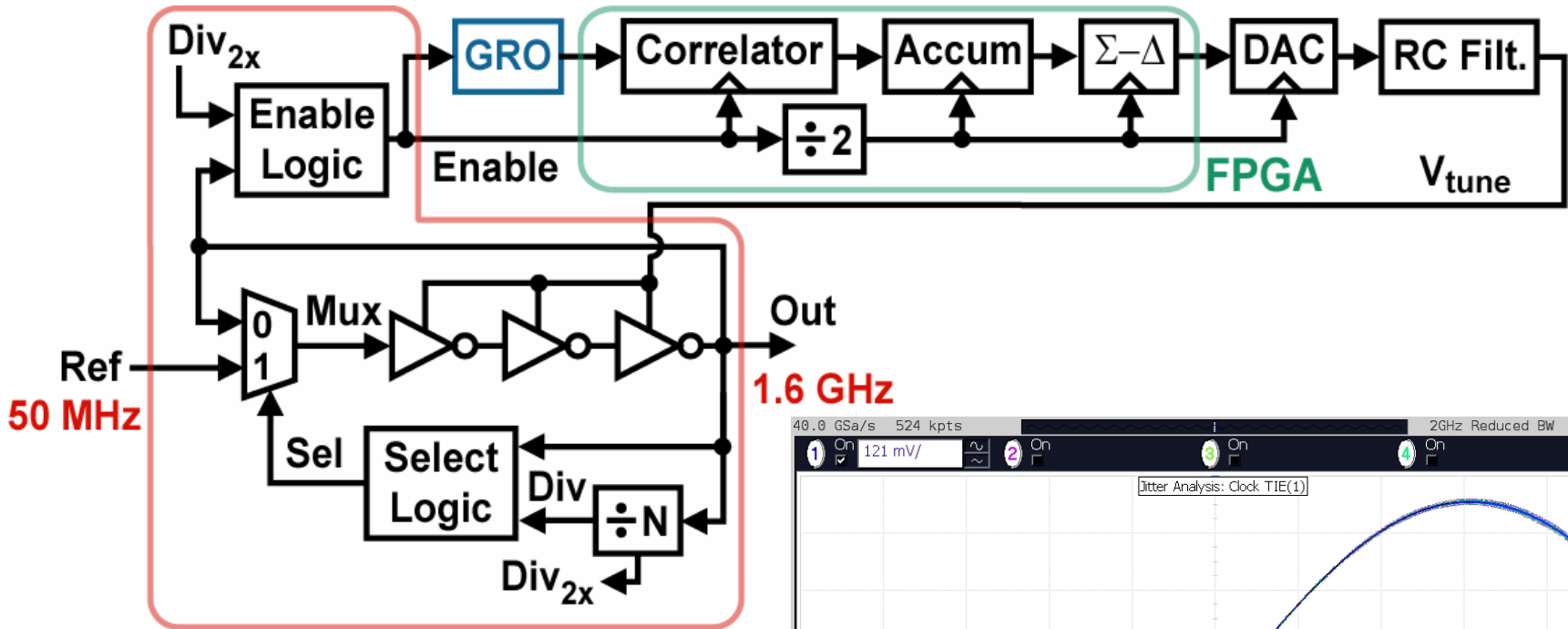
■ Select Logic

- Mostly standard cells
- Relaxed timing
- Sel at middle of output transition
→ better multiplexing

■ Enable Logic

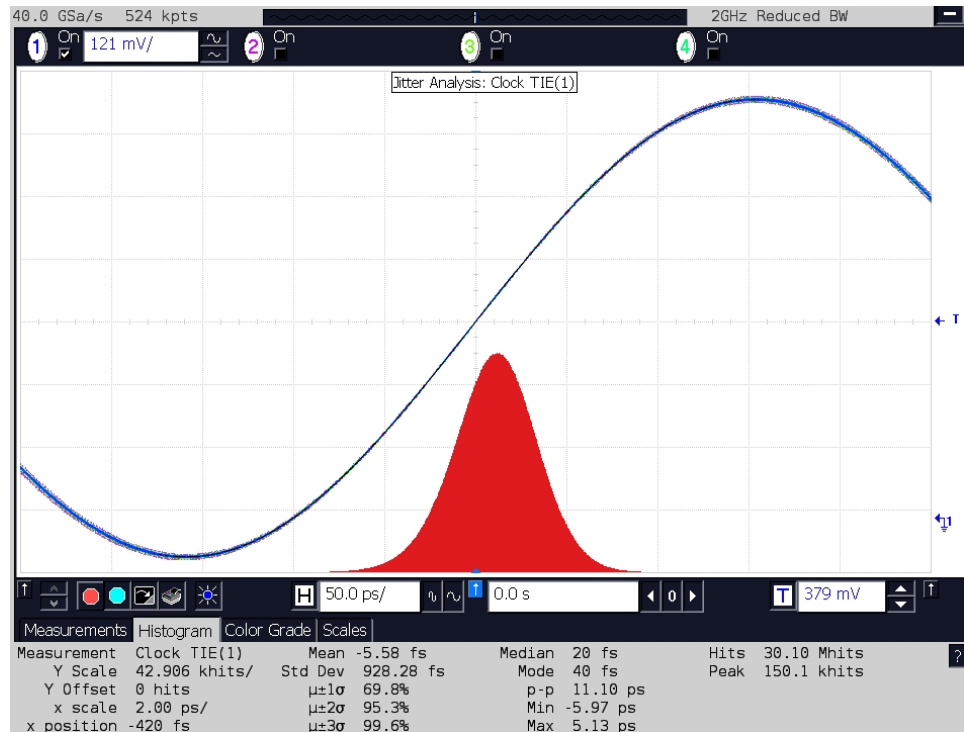
- Simple implementation
- Single path detection

Measured Overall Jitter

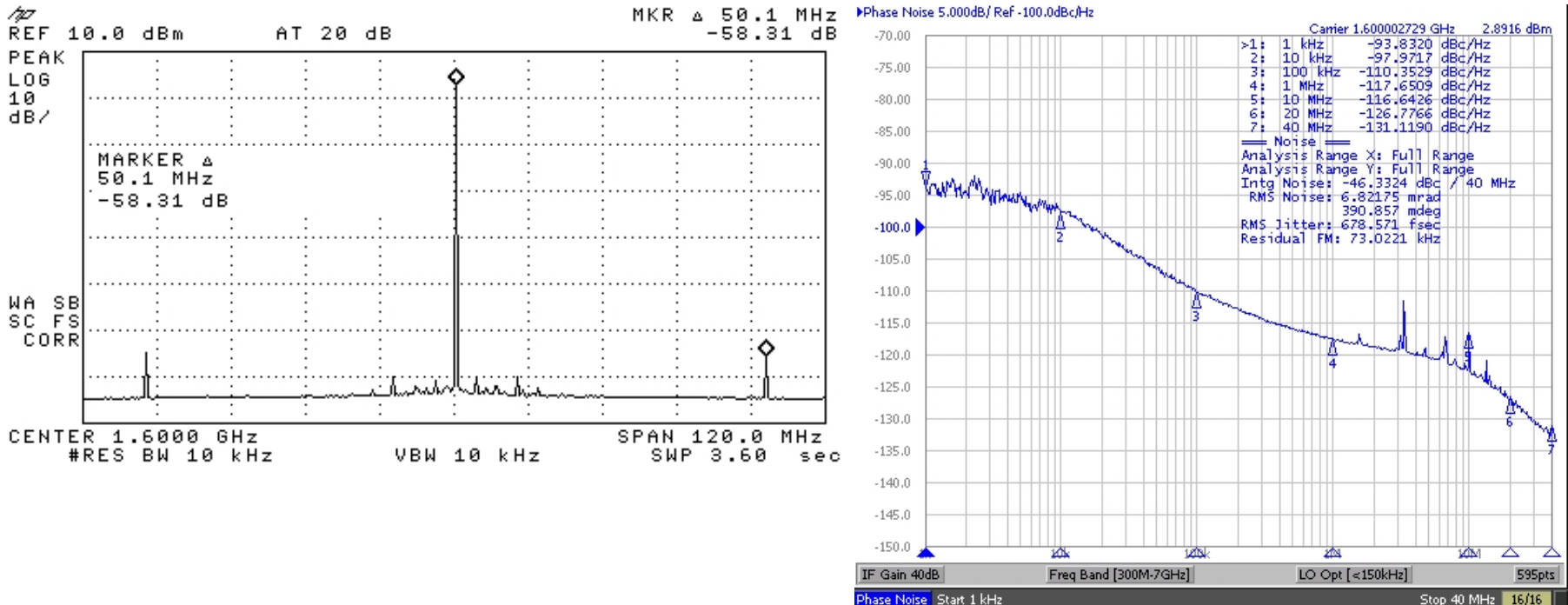


- Measured overall jitter:
 - 928 fs (rms)
 - 11.1 ps (peak-to-peak)

Sub-picosecond jitter



Jitter Estimation from Measured Ref. Spur and Ph. Noise



- Reference spur: -58.3 dBc
- Deterministic jitter: ≈ 760 fs (peak-to-peak)
- Random jitter : 679 fs (rms)
 - From integrated phase noise (1 kHz to 40 MHz)

Sub-picosecond of estimated random and deterministic jitter

Performance Comparison

	[ISSCC 2002]	[CICC 2006]	[CICC 2006]	This work
Output Frequency (GHz)	2.0	1.216	0.176	1.6
Reference Frequency (MHz)	250	64	8	50
Reference Spur (dBc)	-37	-46.5	-70 (estimated)	-58.3
Deterministic Jitter (ps pp) estimated from meas. Spurs (Figure-of-merit)	7.06	3.89	1.80	0.76

Performance Comparison

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Deterministic Jitter (ps pp) estimated from meas. Spurs (Figure-of-merit)	7.06 (reported DJ: 12)	3.89	1.80	0.76
Random Jitter (ps rms) from integrated phase noise	N/A	N/A	5 (1.8 simulated) (1 kHz to 10 MHz)	0.68 (1 kHz to 40 MHz)
Overall Jitter	1.62 ps (rms) 13.11 ps (p-p) 25 khits	(@2.16 GHz) 1.6 ps (rms) 12.9 ps (p-p) 12.2 khits	N/A	0.93 ps (rms) 11.1 ps (p-p) 30.1 Mhits
Technology (CMOS)	0.18 μm	0.18 μm	0.18 μm	0.13 μm

Conclusion

- **Digital Period Correlator**
 - Detects tuning error without path mismatch
 - Enables a digital loop filter

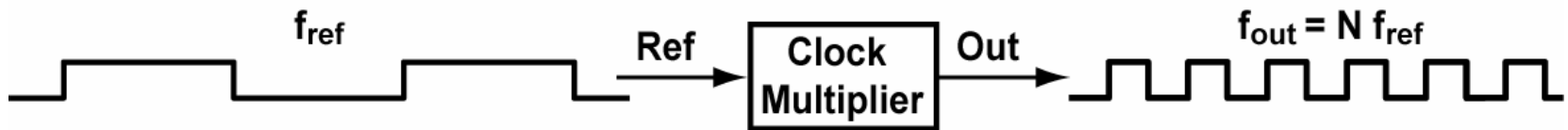
- **Highly-digital tuning technique**
 - Avoids analog non-idealities
 - Enables low bandwidth without leakage or large area

- **Highly digital MDLL**
 - 1.6 GHz from 50 MHz reference
 - Significantly-reduced deterministic jitter
 - Sub-picosecond jitter

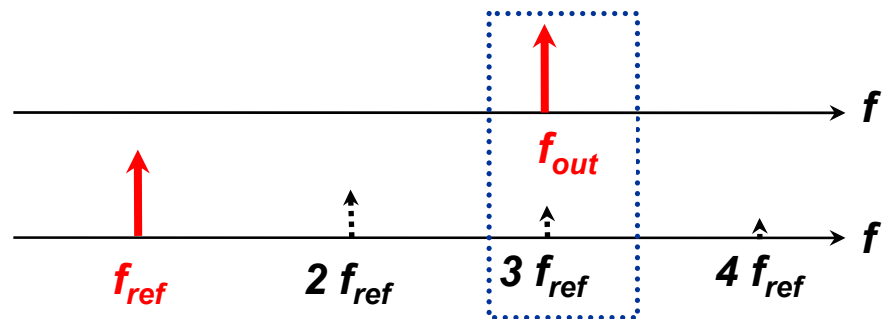
A Low Noise Programmable Clock Multiplier based on a Pulse Injection-Locked Oscillator with a Highly-Digital Tuning Loop

**Belal M. Helal, Chun-Ming Hsu, Kerwin Johnson, and
Michael H. Perrott**

Motivation

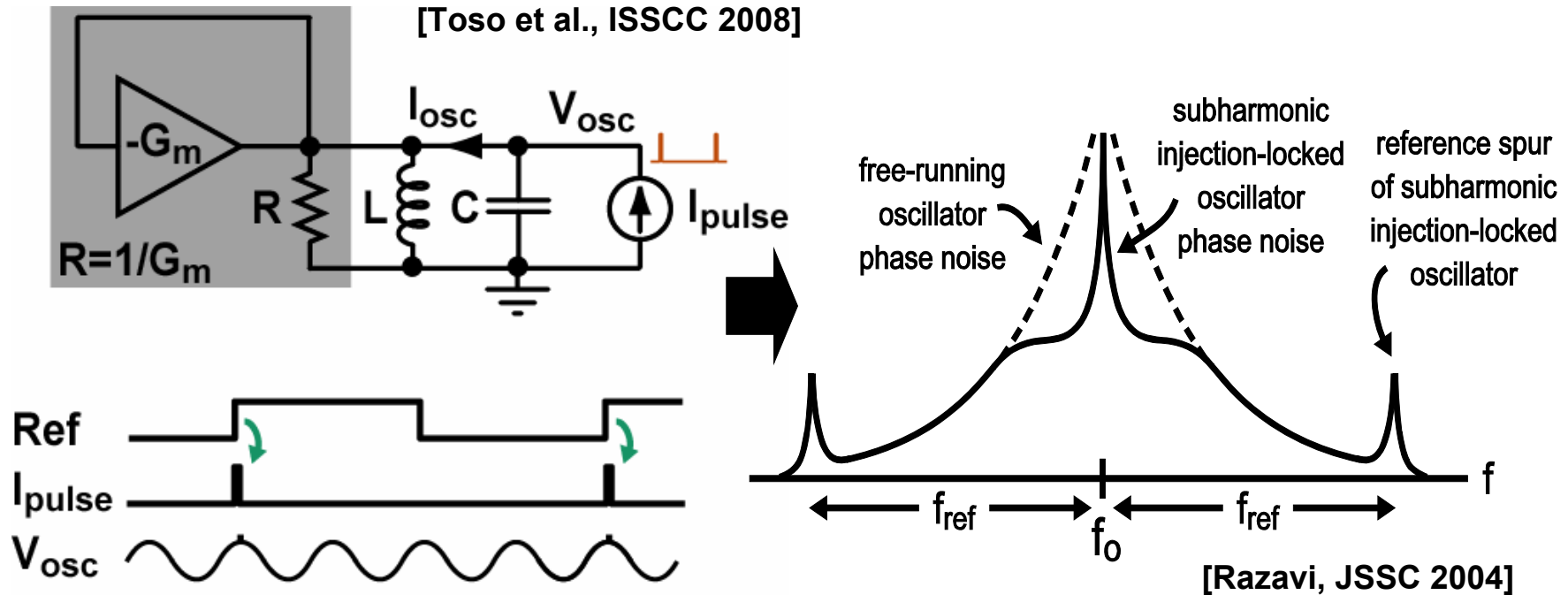


- **Goal: clock multiplication of a clean reference source**
 - Applications: high performance data links, ADCs, processors, etc.
- **Our approach: sub-harmonic injection-locking of an LC oscillator**



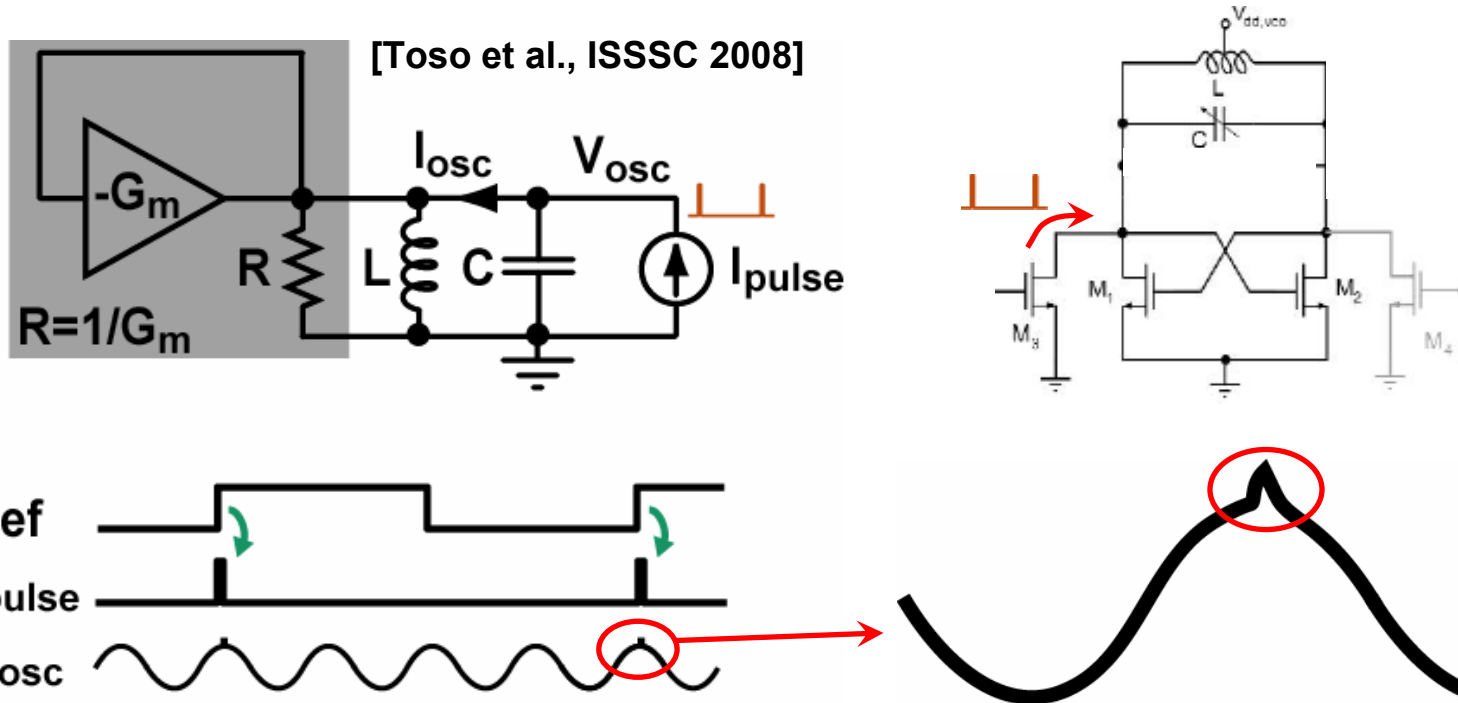
How do we achieve very low jitter levels?

Sub-Harmonic Injection-Locking of an LC Oscillator



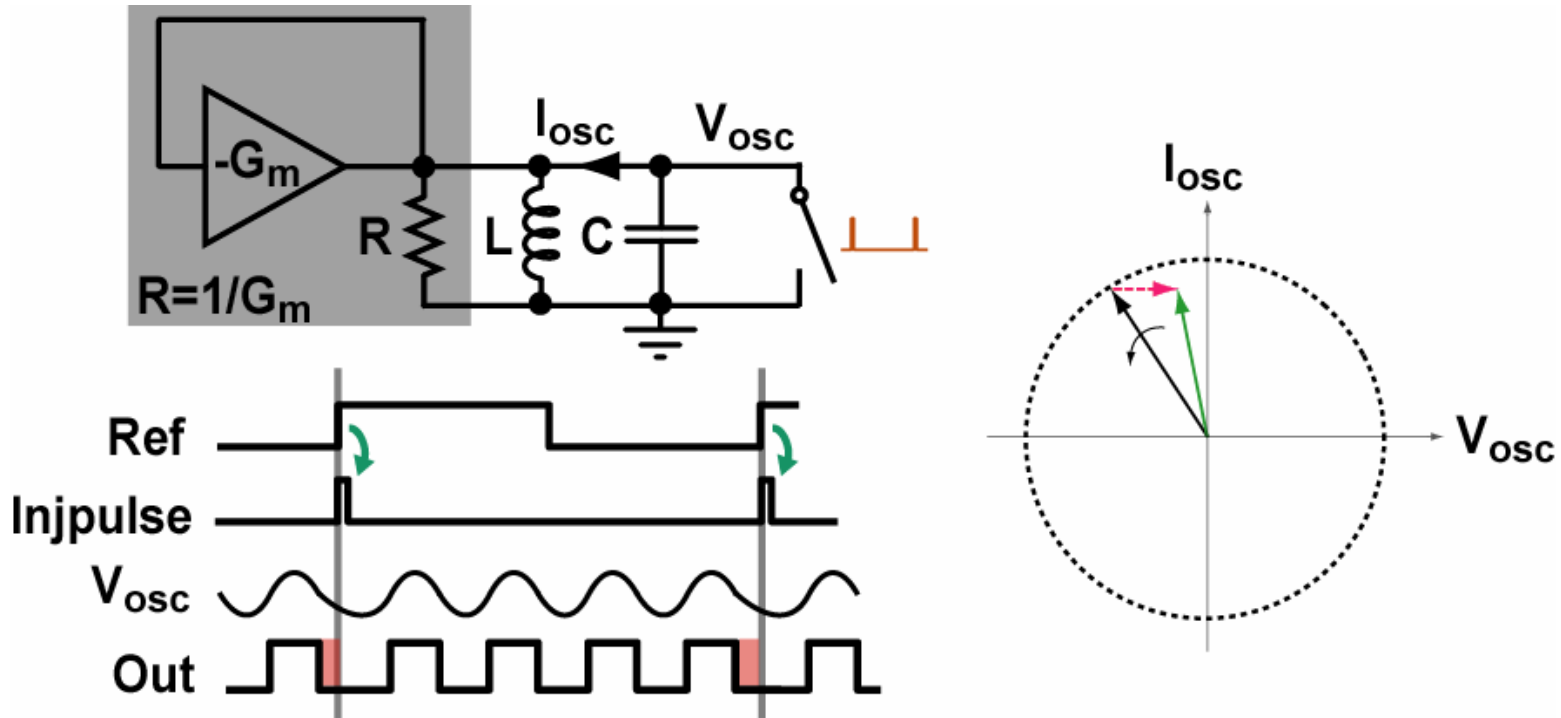
- Sub-harmonic injection locking can be achieved with current pulses
 - Pulses have rich harmonic content to lock to
 - Oscillator locks its voltage peaks to the pulses
 - Locking bandwidth proportional to the injected charge

Problems with Current Pulse Injection Locking



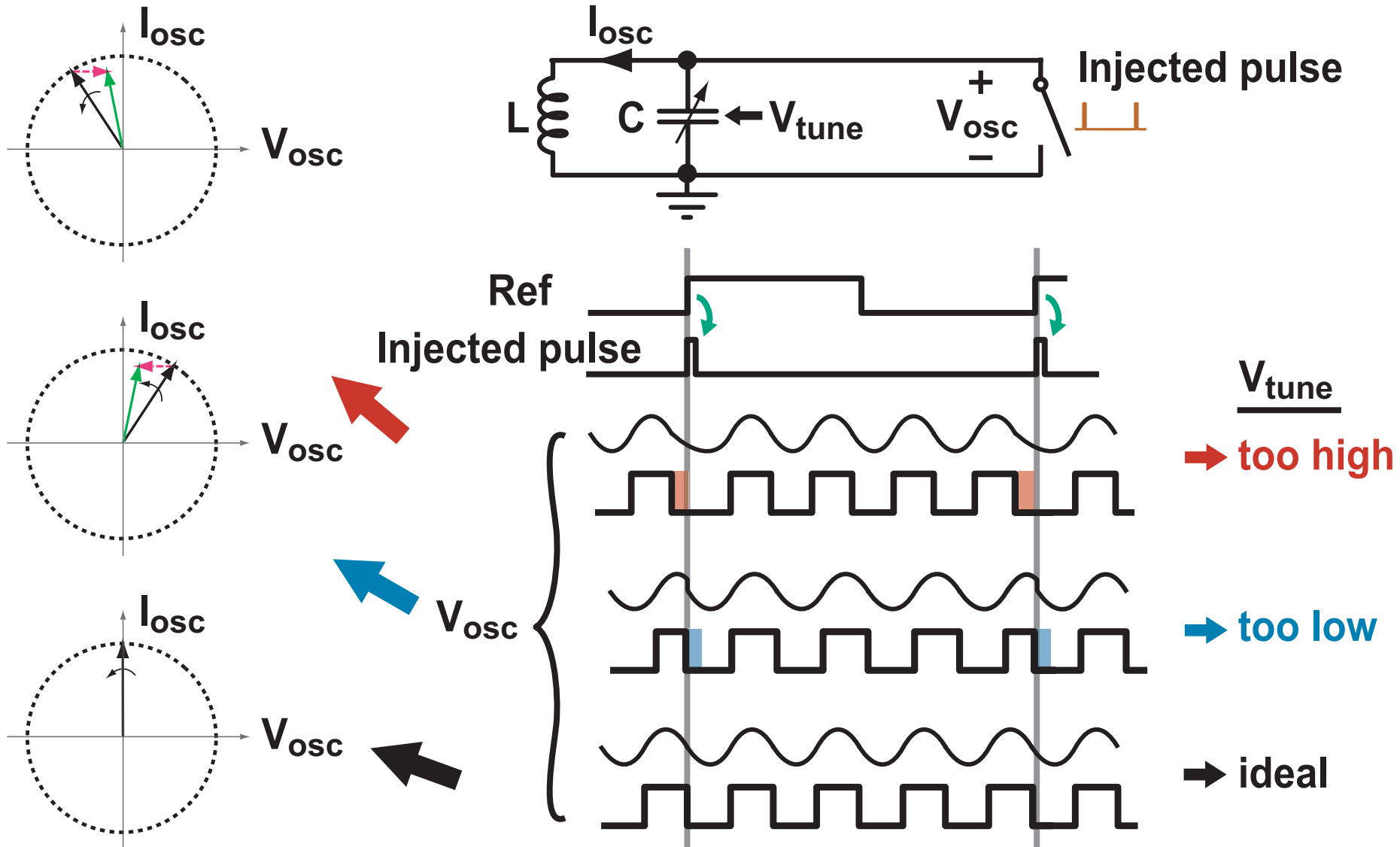
- **Asymmetric injections in differential oscillators**
 - large reference spurs
- **Current pulses have constant level even at ideal tuning**
 - Oscillator amplitude is disturbed periodically
 - increased reference spurs

Proposed Pulse Injection-Locked Oscillator (PILO)



- Injection lock by shorting the tank instead of using constant current pulses
- Injected pulse shifts phase towards zero crossing
- Minimal disturbance to oscillator amplitude when injected with narrow pulses and properly tuned

The Need for Continuous Tuning

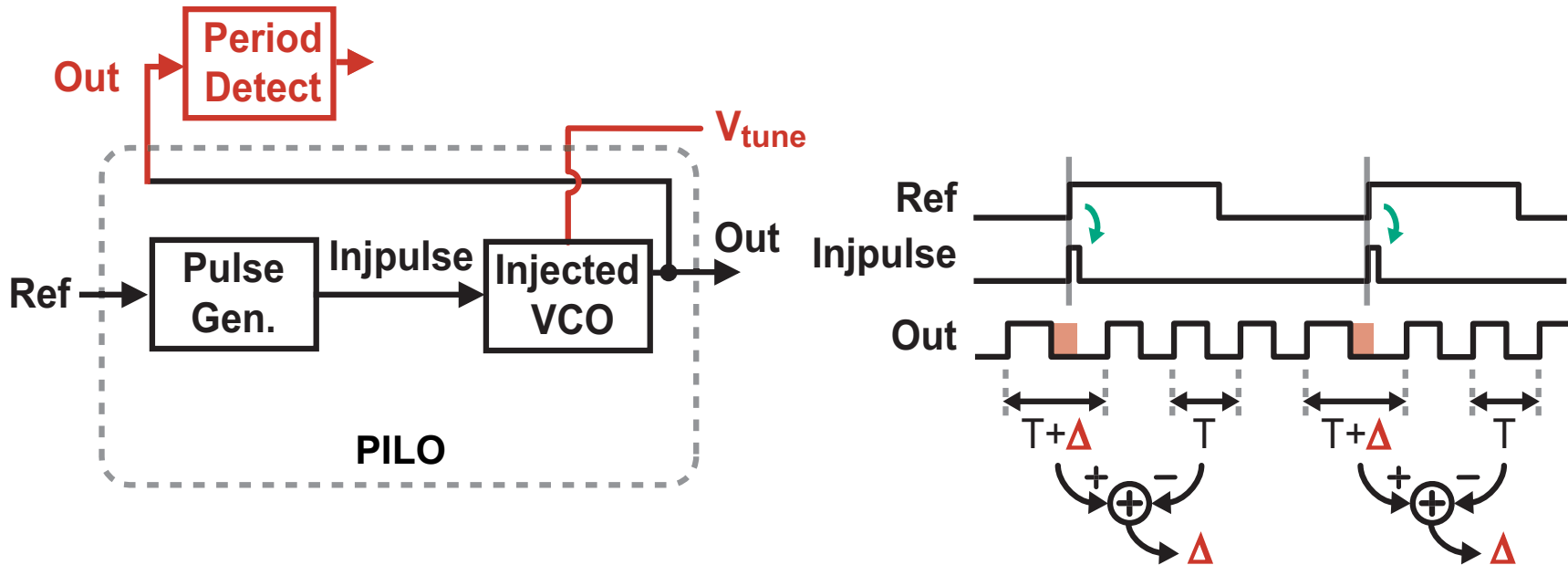


How do we achieve continuous tuning?

Proposed Tuning Approach

- **Leverage a tuning technique originally developed for Multiplying Delay-Locked Loops (MDLLs)**
 - **See Helal et al., JSSC, April 2008**

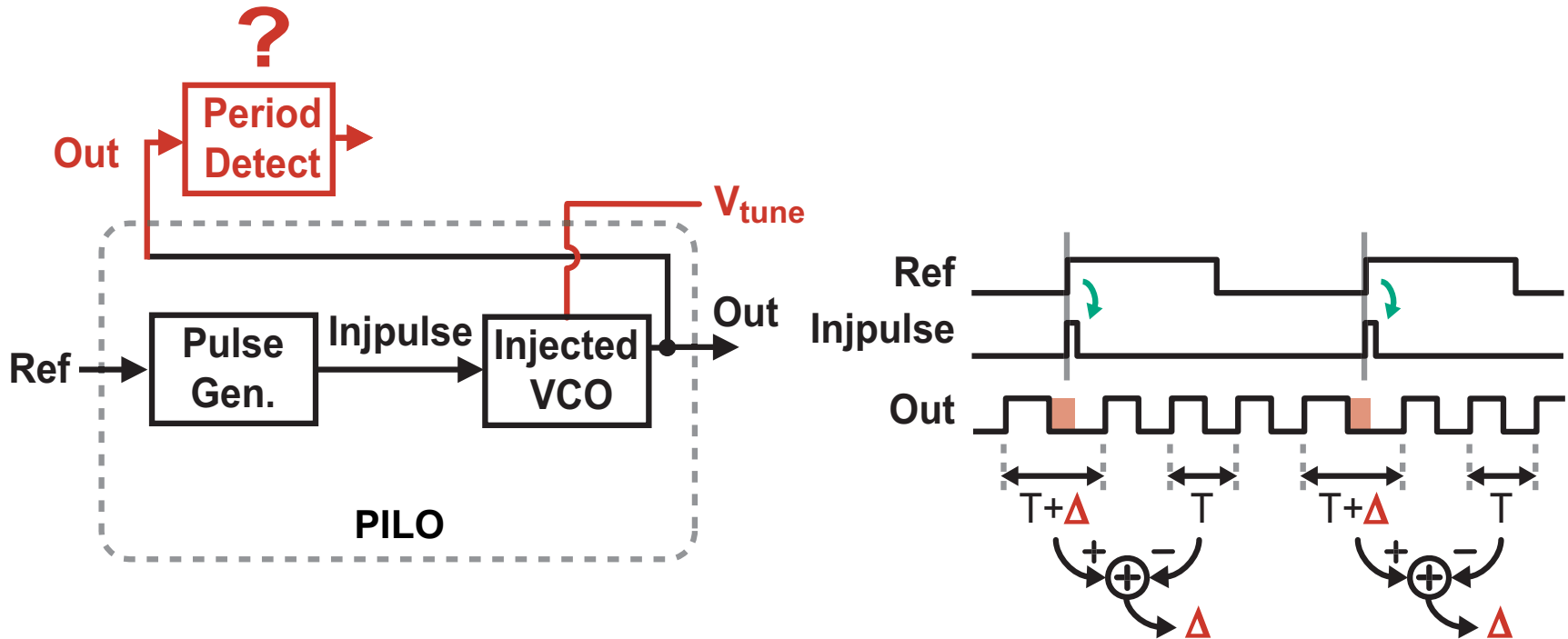
Output Period Detection



- Compare cycle periods of PILO output
- Infer error (Δ) from difference between cycle periods of the PILO output
- Use this information to control V_{tune}

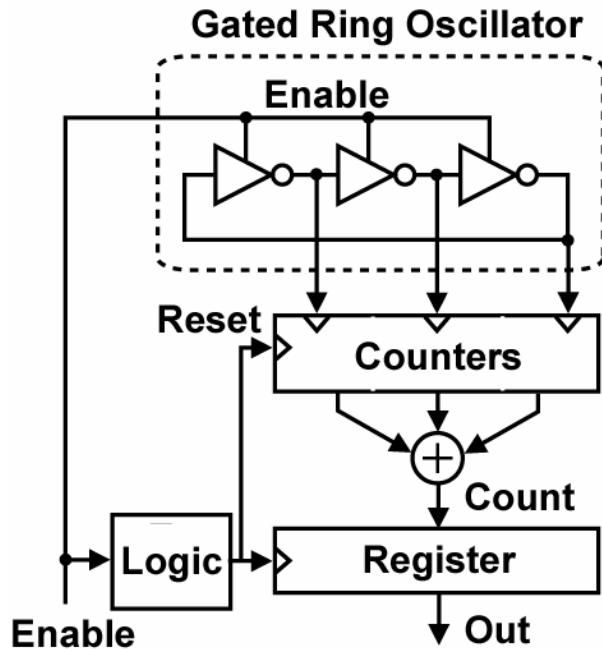
Comparison of same signal eliminates path mismatch

Detection of the Output Period

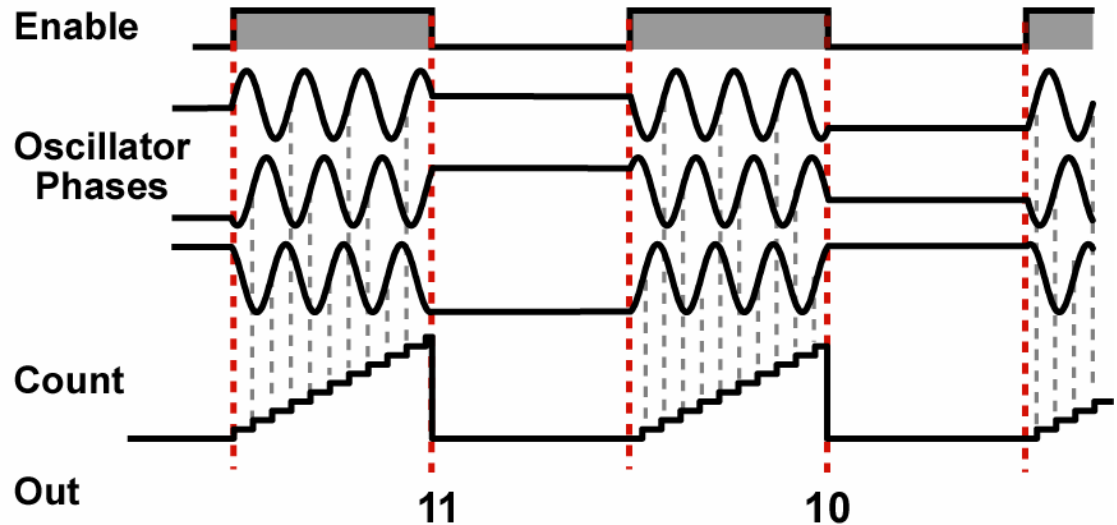


- **Need an accurate period detector**
 - Error removal is limited by the effective resolution of the detector
- **A digital detector has many advantages**
 - Time-to-digital converter (TDC)

Scrambling TDC

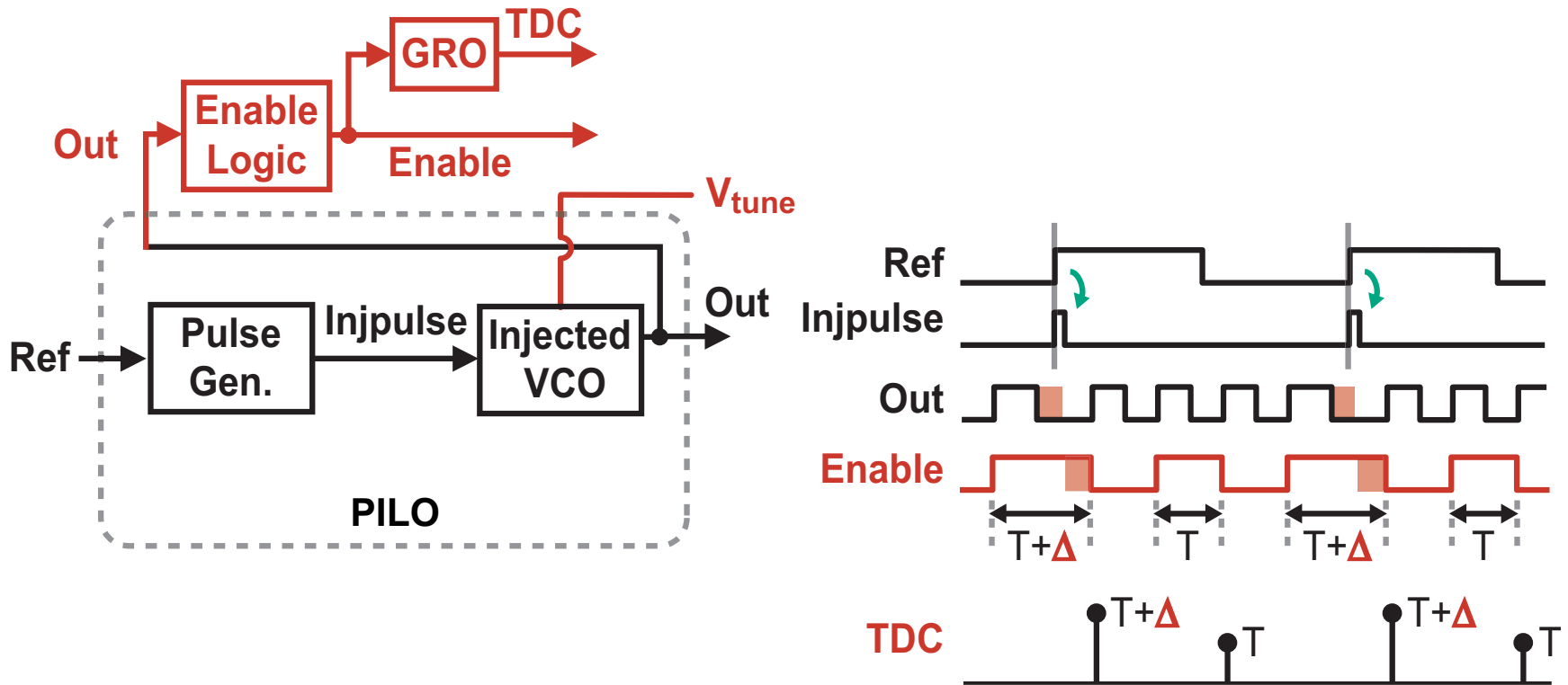


[Helal, Straayer, et al., JSSC 2008]



- **Gated Ring Oscillator (GRO) is ON during the measured period**
- **Quantization noise is scrambled (and first order noise shaped)**
 - Effective resolution improved by averaging
- **We are using a new version of the GRO**
 - Details in Straayer, et al., VLSI 2008

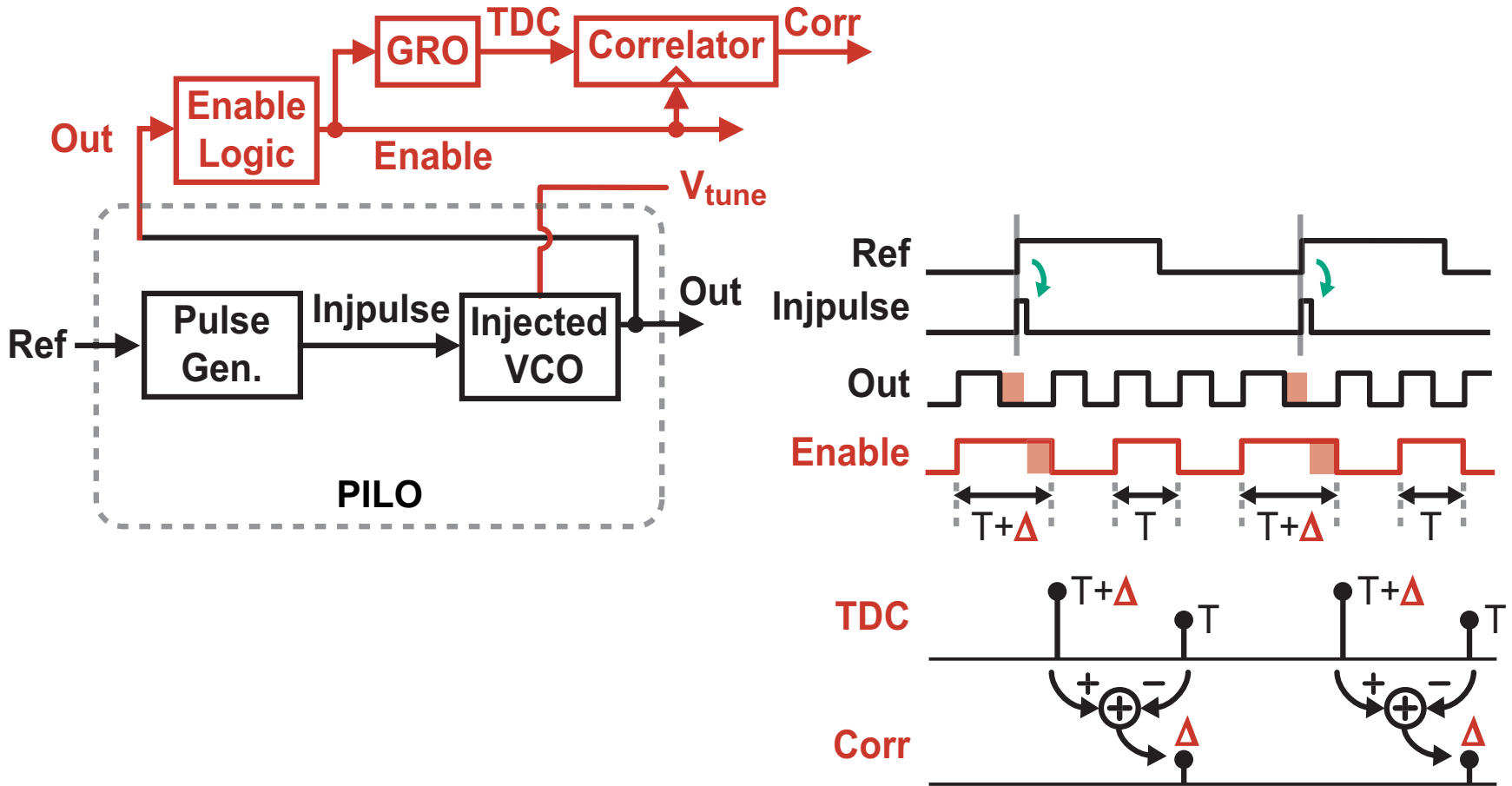
Using the GRO in the proposed PILO Architecture



- Oversampling improves the effective resolution significantly
 - $T_{gro} = 20 \text{ ps}$, $F_s = 100 \text{ MHz}$, $BW = 1 \text{ kHz}$
→ Effective resolution $\approx 90 \text{ fs}$

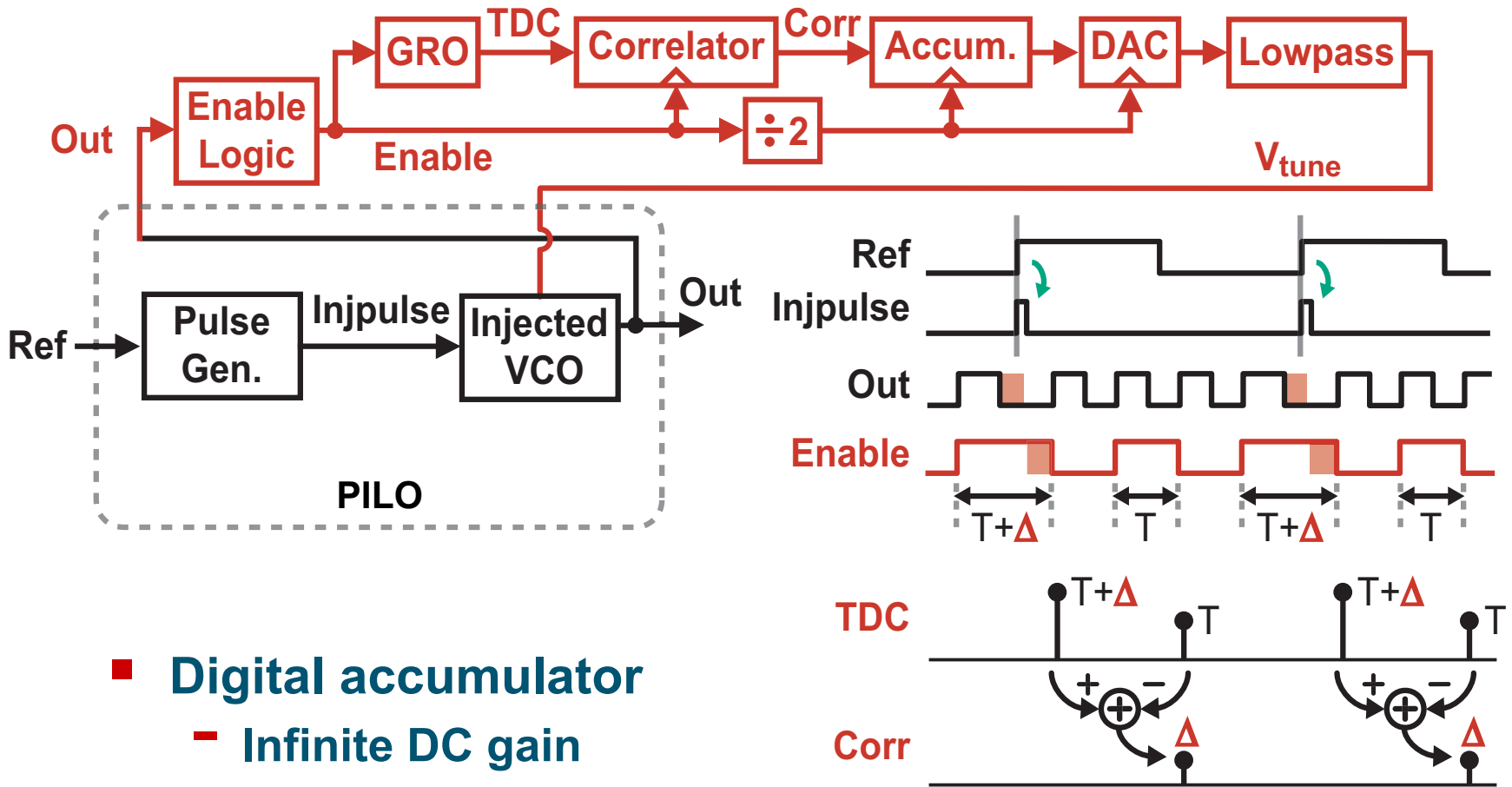
GRO detects the output period accurately

Digital Correlator Extracts the Error



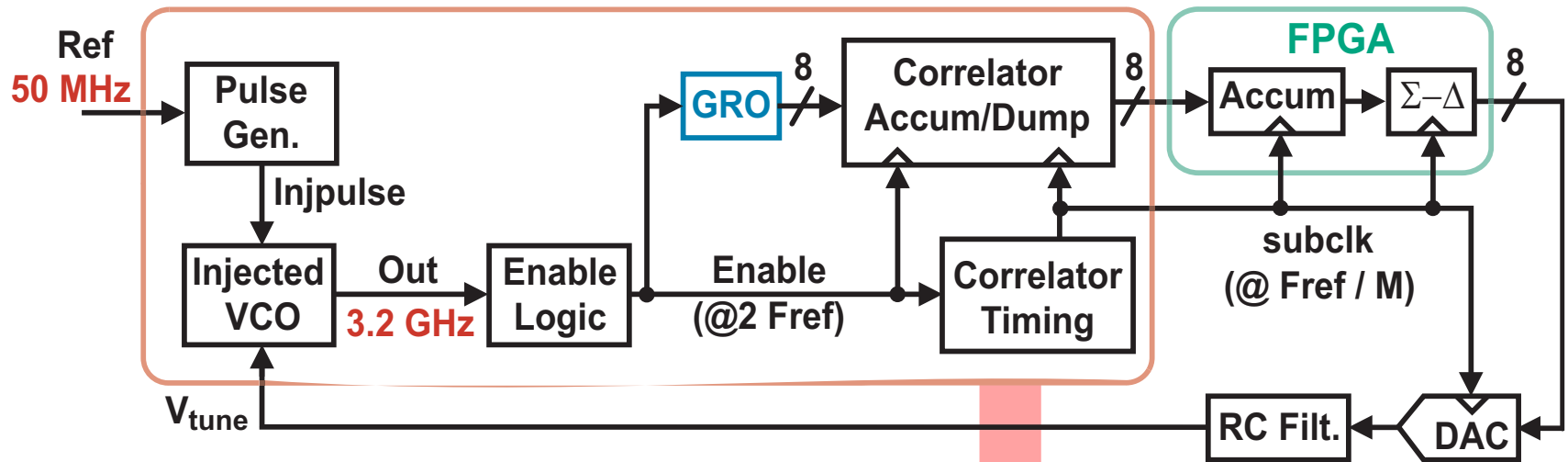
- Digital version of correlated double-sampling technique

Close the Loop



- **Digital accumulator**
 - Infinite DC gain
 - No DC offsets
 - Allows low bandwidth without leakage or large area
- V_{tune} adjustment only needs to track thermal variations

PILO Prototype



- Custom 0.13 μm CMOS IC

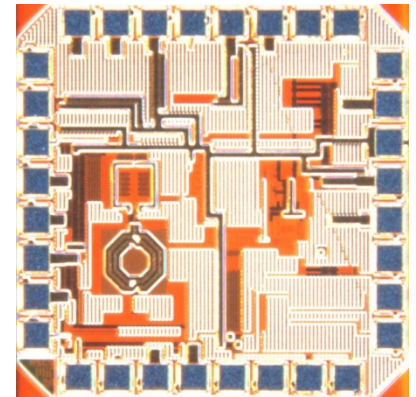
- Active area: 0.4 mm²
- Active Power: 28.6 mW

- FPGA

- Accumulator and digital $\Sigma\Delta$ -modulator

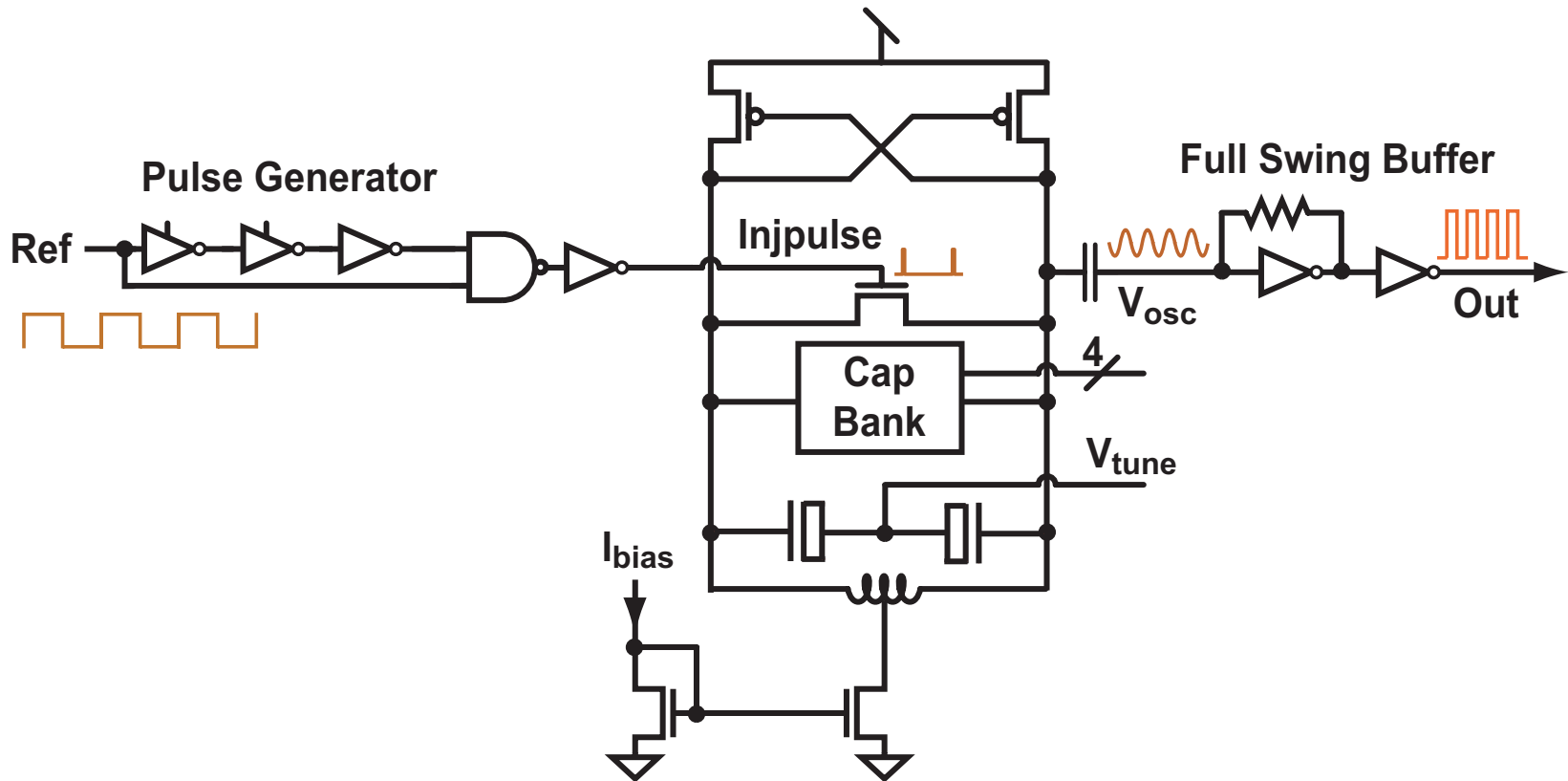
- Discrete 16-bit DAC and RC lowpass filter (500 kHz pole)

- DAC using 8 effective bits (by using the $\Sigma\Delta$ -modulator)



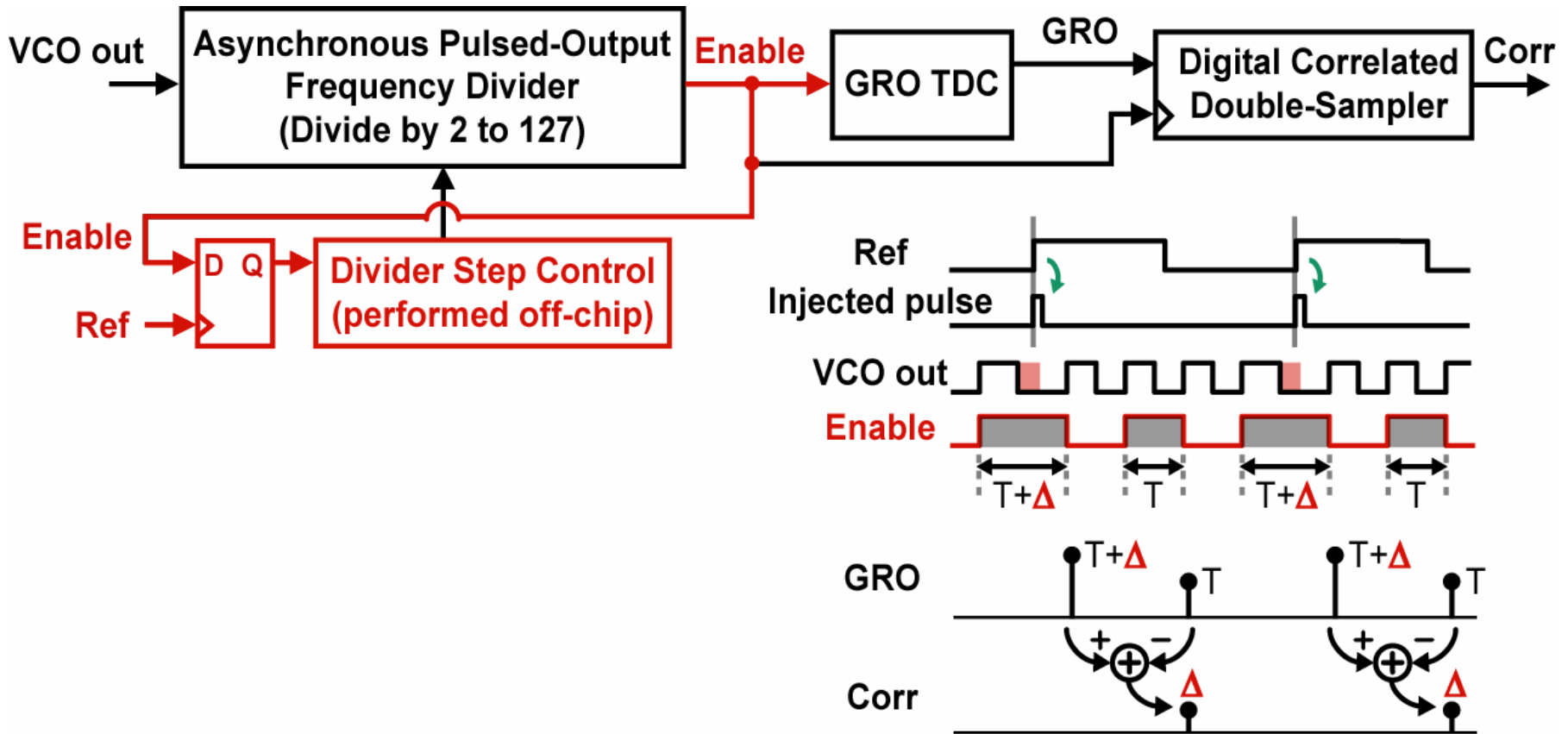
Circuit Details

Proposed PILO Implementation



- **Differential Injection by shorting**
 - Minimizes deterministic jitter by preserving injection symmetry
- **Narrow pulses minimize effect on Q of the tank**
 - Minimal residual effect when tuned

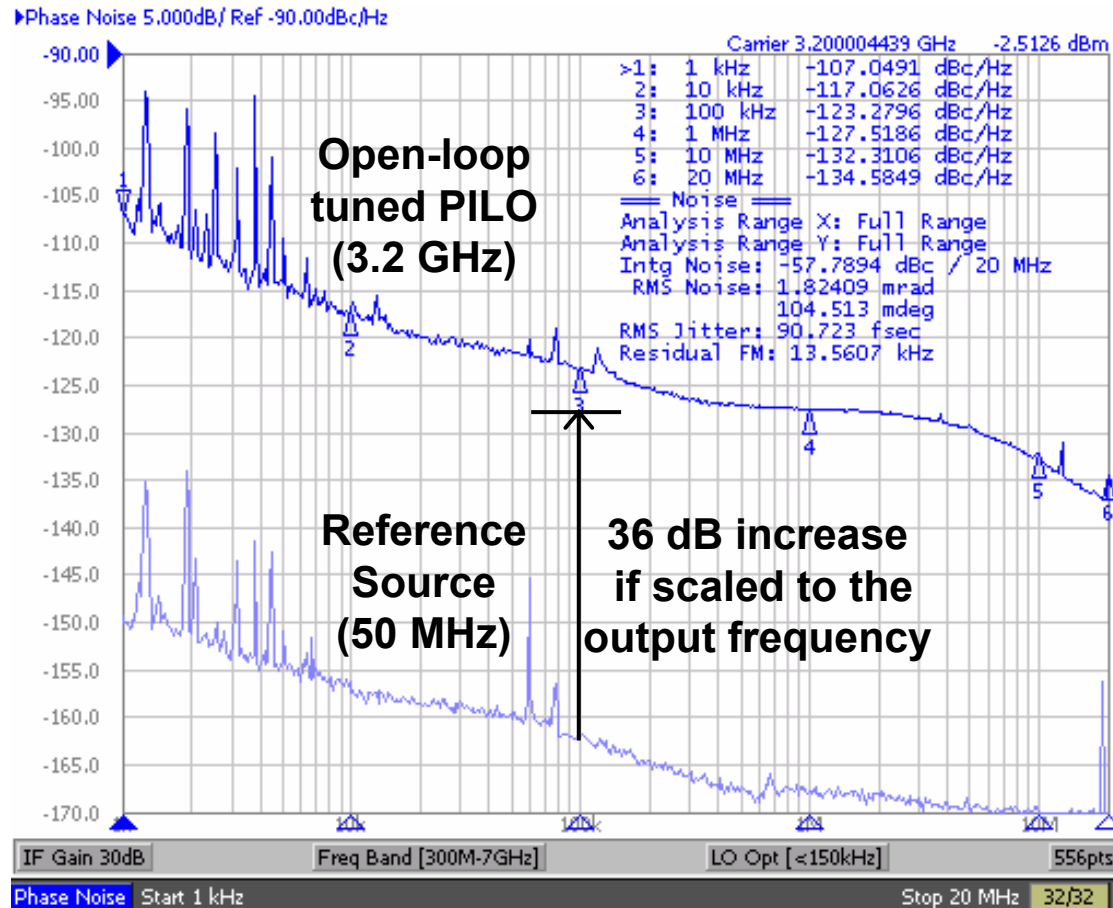
Enable Logic: Divider Step Control



- **GRO TDC must capture periods that includes the injected pulse**
 → Divider stepped until *Ref* rises during *Enable*

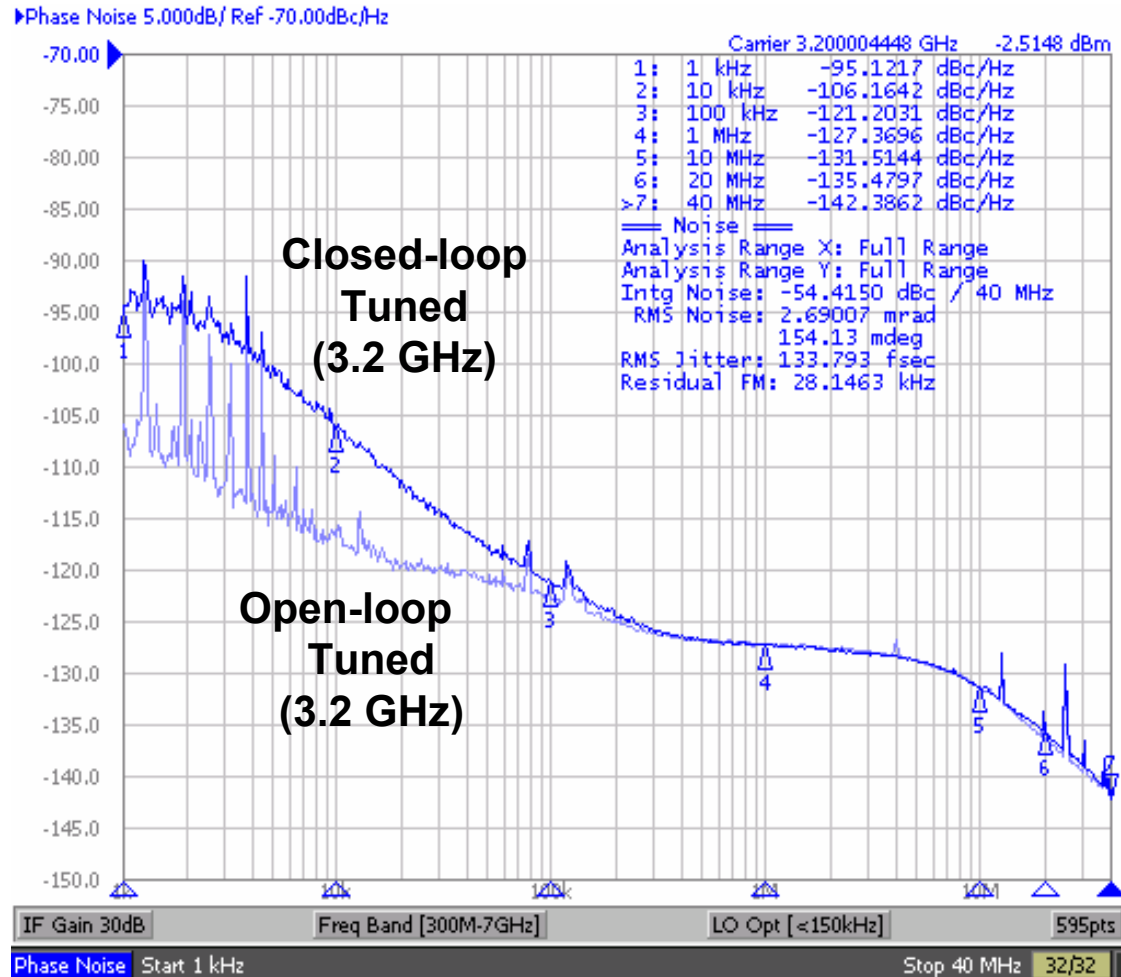
Measured Results

Measured Phase Noise (Open-loop tuned PILO)



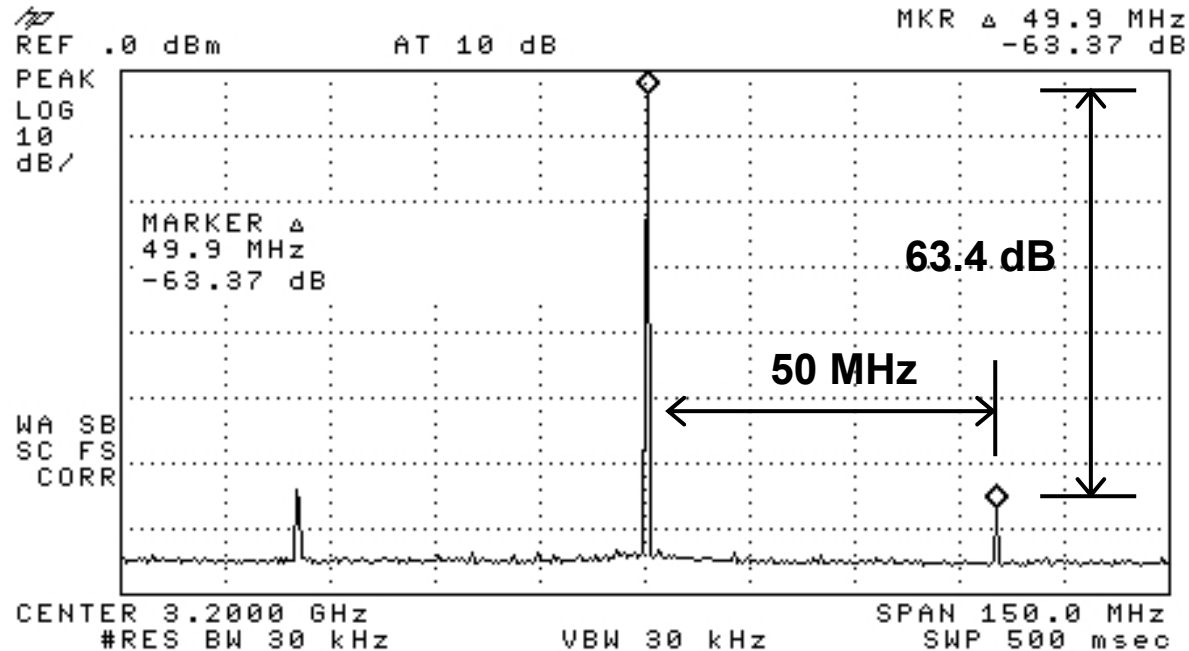
- **Random jitter: 91 fs (rms)**
 - From integrated phase noise (1 kHz to 20 MHz)

Measured Phase Noise (close-loop tuned PILO)



- **Random jitter: 134 fs (rms)**
 - From integrated phase noise (1 kHz to 40 MHz)

Measured Reference Spurs and Est. Deterministic Jitter



- Reference Spur: -63.4 dBc

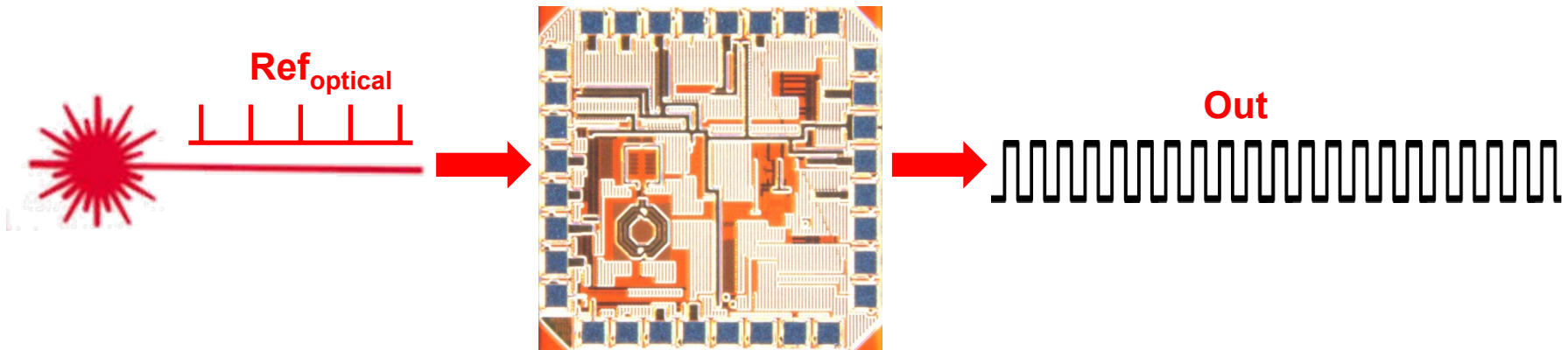
- From Fourier analysis: $\Delta \approx T_{out} \times 10^{Spur(dBc)/20}$

→ Estimated deterministic jitter ≈ 211 fs (peak-to-peak)

Performance Summary

Process	0.13 μm CMOS
Core Area	0.4 mm²
Core Power	28.6 mW
Output Frequency	3.2 GHz (up to 4 GHz)
Reference Frequency	50 MHz
Reference Spur	-63.4 dBc
Deterministic Jitter	211 fs (peak-to-peak), estimated from measured reference spurs
Random Jitter	134 fs (rms), from integrated phase noise (1 kHz to 40 MHz)

Future Research Area: Optical PILO



- RF output from an optical reference input
- Leverage Mode-Locked lasers
 - Train of very short optical pulses
 - Ultra-low jitter in the range of 10's fs to sub-fs

Conclusions

- **Clock multiplication by injection locking**
 - Lower jitter than typical PLLs
 - Achieved continuous tuning
- **Pulse Injection-Locked Oscillator (PILO)**
 - Injection by shorting minimizes deterministic jitter when tuned
- **PILO-based clock multiplier with highly-digital tuning**
 - 3.2 GHz from 50 MHz reference
 - Random jitter: 134 fs (rms)
 - Deterministic jitter: 211 fs (peak-to-peak)
 - Avoids analog non-idealities
 - Enables low bandwidth without leakage or large area